

# TAS5828M Hybrid-Pro アルゴリズムを実装した、50W 高効率のステレオ、デジタル入力、閉ループ Class-D アンプ

## 1 特長

- 柔軟なオーディオ I/O:
  - 32、44.1、48、88.2、96、192kHz のサンプル・レートをサポート
  - I<sup>2</sup>S、LJ、RJ、TDM、SDOUT によるオーディオ・モニタ、サブチャンネル、またはエコー・キャンセル
  - 3 線式のデジタル・オーディオ・インターフェイスをサポート (MCLK 不要)
- 高効率 Class-D 変調
  - 90% を超える電力効率、90mΩ の R<sub>DS(on)</sub>
- 複数の出力構成をサポート
  - 2.0 モードで 2× 50W (4Ω、23V、THD+N = 1%)
  - 2.0 モードで 2× 40W (6Ω、24V、THD+N=1%)
  - 1.0 モードで 1× 100W (2Ω、23V、THD+N = 1%)
  - 1.0 モードで 1× 80W (3Ω、24V、THD+N=1%)
- 優れたオーディオ性能:
  - THD+N ≤ 0.03% (1W、1kHz、PVDD = 12V)
  - SNR ≥ 110dB (A-weighted)、ICN ≤ 40μVRMS
- 柔軟な処理機能
  - 3 バンドの高度な DRC +2 BQ + AGL + 2 BQ
  - チャンネルごとに 12 の BQ、レベル・メーター
  - 96kHz、192kHz のプロセッサ・サンプリング
  - ミキサ、ボリューム、動的 EQ、出力クロス・オーバー
  - PVDD センシングと Hybrid-Pro アルゴリズム・オーディオ信号トラッキング
- 柔軟な電源構成
  - PVDD: 4.5V ~ 26.4V
  - DVDD および I/O: 1.8V または 3.3V
- 優れた自己保護機能を内蔵
  - 過電流エラー (OCE)
  - サイクル単位の電流制限
  - 過熱警告 (OTW)
  - 過熱エラー (OTE)
  - 低電圧 / 過電圧誤動作防止 (UVLO/OVLO)
  - PVDD 電圧降下検出
- システム統合が簡単
  - I<sup>2</sup>C ソフトウェアまたはハードウェア制御モード
  - 閉ループ・デバイスと比べて少ない受動部品数

## 2 アプリケーション

- バッテリー駆動スピーカー
- ワイヤレス、Bluetooth スピーカー
- サウンドバーとサブウーファー
- 熱または効率を重視するオーディオ・システム

## 3 概要

TAS5828M は高性能のステレオ、閉ループの Class-D アンプで、最高 192kHz アーキテクチャのオーディオ・プロセッサが内蔵されています。

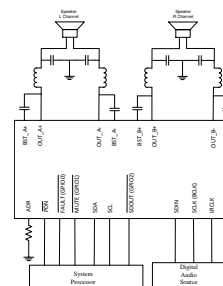
ソフトウェア制御モードについては、TAS5828M は従来の BQ、3 バンド DRC、AGL だけでなく、Hybrid-Pro と呼ぶ独自のアルゴリズムも実装しています。Hybrid-Pro アルゴリズムは、予測されるオーディオ電力の需要を検出し、Hybrid-Pro フィードバック・ピン (HPFB) により、前段の DC-DC コンバータに PWM 形式の制御信号を出力します。TAS5828M は、エンベロープ・トラッキングを予測できるように最大 4ms のオーディオ信号遅延バッファをサポートしているため、DC-DC 電圧の調整に起因するオーディオ・クリッピングを防止する上で非常に有効です。

ハードウェア制御モードの設定については、TAS5828M はスイッチング周波数、アナログ・ゲイン、BTL/PBTL モード、ピン設定によるサイクル単位の電流制限スレッショルドをサポートしています。このモードは、エンド・システムのソフトウェア・ドライバの統合に手間がかからないように特に設計されています。

### 製品情報

部品番号	パッケージ <sup>(1)</sup>	本体サイズ (公称)
TAS5828M	TSSOP (32) DAD	11.00mm × 6.20mm

- (1) 利用可能なすべてのパッケージについては、このデータシートの末尾にある注文情報を参照してください。



### 簡略回路



## Table of Contents

<b>1 特長</b> .....	1	8.6 Register Maps.....	48
<b>2 アプリケーション</b> .....	1	<b>9 Application and Implementation</b> .....	76
<b>3 概要</b> .....	1	9.1 Application Information.....	76
<b>4 Revision History</b> .....	2	9.2 Typical Applications.....	78
<b>5 Pin Configuration and Functions</b> .....	3	<b>10 Power Supply Recommendations</b> .....	82
<b>6 Specifications</b> .....	7	10.1 DVDD Supply.....	82
6.1 Absolute Maximum Ratings.....	7	10.2 PVDD Supply.....	82
6.2 ESD Ratings.....	7	<b>11 Layout</b> .....	84
6.3 Recommended Operating Conditions.....	7	11.1 Layout Guidelines.....	84
6.4 Thermal Information.....	7	11.2 Layout Example.....	86
6.5 Electrical Characteristics.....	8	<b>12 Device and Documentation Support</b> .....	88
6.6 Timing Requirements.....	12	12.1 Device Support.....	88
6.7 Typical Characteristics.....	13	12.2 Receiving Notification of Documentation Updates..	88
<b>7 Parameter Measurement Information</b> .....	27	12.3 サポート・リソース.....	88
<b>8 Detailed Description</b> .....	28	12.4 Trademarks.....	89
8.1 Overview.....	28	12.5 静電気放電に関する注意事項.....	89
8.2 Functional Block Diagram.....	28	12.6 用語集.....	89
8.3 Feature Description.....	28	<b>13 Mechanical, Packaging, and Orderable Information</b> .....	89
8.4 Device Functional Modes.....	35		
8.5 Programming and Control.....	40		

## 4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision * (June 2021) to Revision A (December 2021)	Page
• ドキュメントのステータスを事前情報から量産データに変更.....	1

## 5 Pin Configuration and Functions

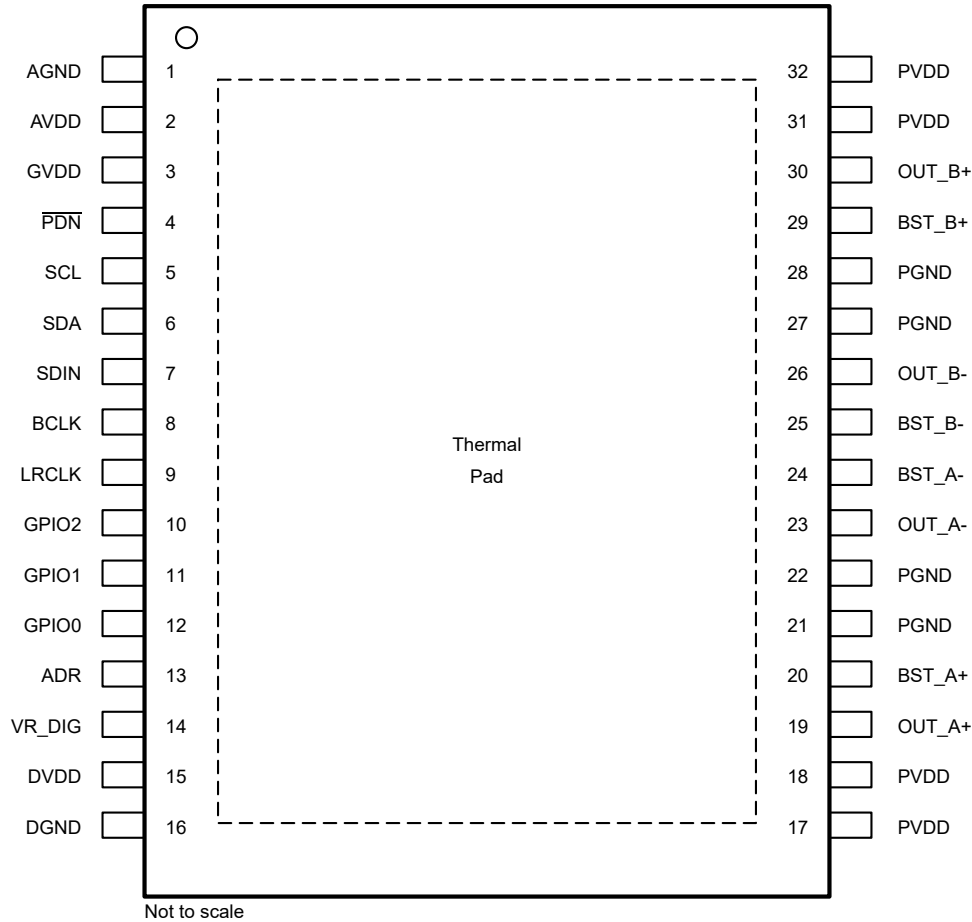


图 5-1. DAD (TSSOP) Package, 32-Pin PadUp, Software Mode, Top View

表 5-1. Pin Functions - Software Mode

PIN		TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.		
AGND	1	G	Analog ground.
AVDD	2	P	Internally regulated 5-V analog supply voltage. This pin must not be used to drive external devices.
GVDD	3	P	Gate drive internal regulator output. This pin must not be used to drive external devices.
PDN	4	DI	Power down, active-low. $\overline{\text{PDN}}$ place the amplifier in Shutdown, turn off all internal regulators.
SCL	5	DI	I <sup>2</sup> C serial control clock input.
SDA	6	DI/O	I <sup>2</sup> C serial control data interface input/output.
SDIN	7	DI	Data line to the serial data port.
BCLK	8	DI	Bit clock for the digital signal that is active on the input data line of the serial data port.
LRCLK	9	DI	Word select clock for the digital signal that is active on the serial port's input data line. In I <sup>2</sup> S, LJ and RJ, this corresponds to the left channel and right channel boundary. In TDM mode, this corresponds to the frame sync boundary.
GPIO2	10	DI/O	General-purpose input/output, function of this pin can be programmed by register (Register Address 0x60h and 0x62h). Can be configured to be open drain output or push-pull output.
GPIO1	11	DI/O	General-purpose input/output, function of this pin can be programmed by register (Register Address 0x60h and 0x61h). Can be configured to be open drain output or push-pull output.
GPIO0	12	DI/O	General-purpose input/output, function of this pin can be programmed by register (Register Address 0x60h and 0x63h). Can be configured to be open drain output or push-pull output.
ADR	13	AI	A table of resistor value (Pull down to GND) decides the device I <sup>2</sup> C address. See 表 8-7.

表 5-1. Pin Functions - Software Mode (continued)

PIN		TYPE <sup>(1)</sup>	DESCRIPTION
NAME	NO.		
VR_DIG	14	P	Internally regulated 1.5-V digital supply voltage. This pin must not be used to drive external devices.
DVDD	15	P	3.3-V or 1.8-V digital power supply.
DGND	16	G	Digital ground.
PVDD	17	P	PVDD voltage input.
	18	P	
	31	P	
	32	P	
PGND	21	G	Ground reference for power device circuitry. Connect this pin to system ground.
	22	G	
	27	G	
	28	G	
OUT_A+	19	O	Positive pin for differential speaker amplifier output A.
BST_A+	20	P	Connection point for the OUT_A+ bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_A+.
OUT_A-	23	O	Negative pin for differential speaker amplifier output A.
BST_A-	24	P	Connection point for the OUT_A- bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_A-.
BST_B-	25	P	Connection point for the OUT_B- bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_B-.
OUT_B-	26	O	Negative pin for differential speaker amplifier output B.
BST_B+	29	P	Connection point for the OUT_B+ bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_B+.
OUT_B+	30	O	Positive pin for differential speaker amplifier output B.
PowerPAD™		P	Ground, connect to grounded heat sink for best system performance.

(1) AI = Analog input, AO = Analog output, DI = Digital Input, DO = Digital Output, DI/O = Digital Bi-directional (input and output), P = Power, G = Ground (0 V)

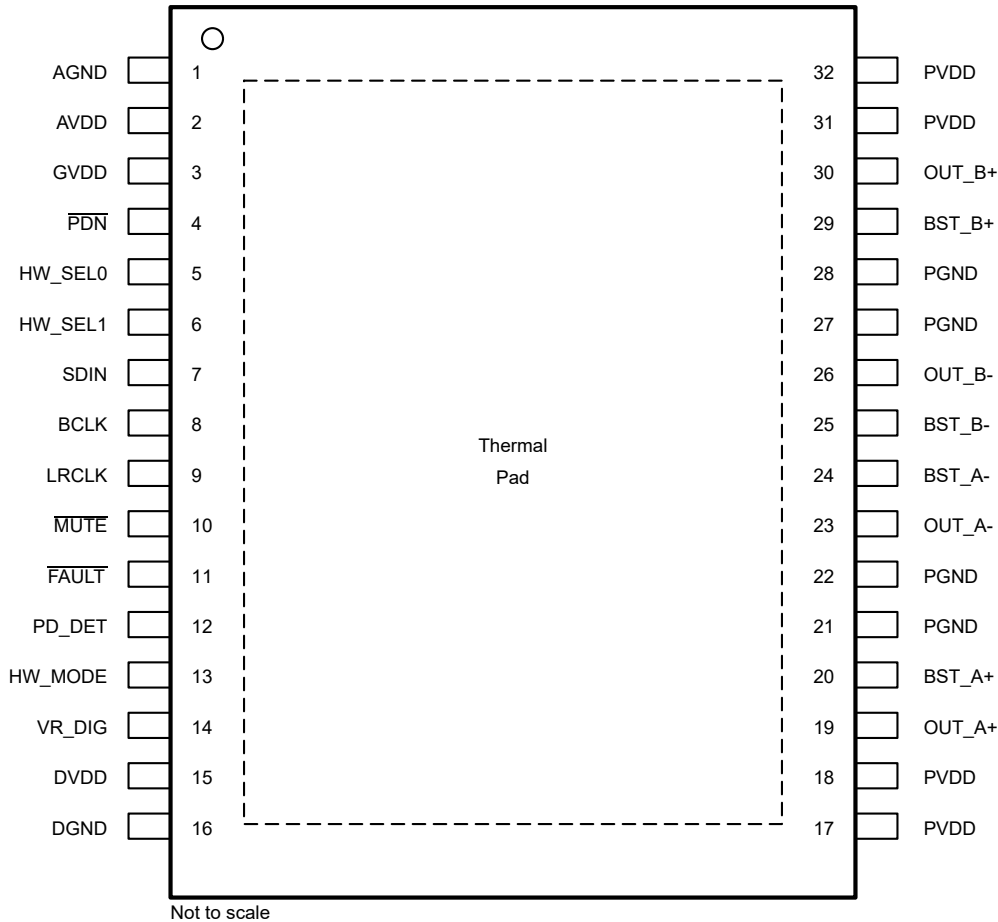


图 5-2. DAD (TSSOP) Package, 32-Pin PadUp, Hardware Mode, Top View

表 5-2. Pin Functions - Hardware Mode

PIN		TYPE <sup>1</sup>	DESCRIPTION
NAME	NO.		
AGND	1	G	Analog ground.
AVDD	2	P	Internally regulated 5-V analog supply voltage. This pin must not be used to drive external devices.
GVDD	3	P	Gate drive internal regulator output. This pin must not be used to drive external devices.
P̄DN	4	DI	Power down, active-low. P̄DN place the amplifier in Shutdown, turn off all internal regulators.
HW_SEL0	5	DI	Analog gain and BTL/PBTL mode selection in Hardware Mode . Pull up to DVDD or Pull down to ground with different resistor. See 表 8-6.
HW_SEL1	6	DI	PWM Switching Frequency and Spread Spectrum Enable/Disable selection in Hardware Mode. Pull up to DVDD or Pull down to ground with different resistor. See 表 8-5.
SDIN	7	DI	Data line to the serial data port.
BCLK	8	DI	Bit clock for the digital signal that is active on the input data line of the serial data port.
LRCLK	9	DI	Word select clock for the digital signal that is active on the serial port's input data line. In I <sup>2</sup> S, LJ and RJ, this corresponds to the left channel and right channel boundary. In TDM mode, this corresponds to the frame sync boundary.
MUTE	10	DI	Speaker amplifier Mute. Which must be pulled low (connect to DGND) to MUTE the device and pulled high (connected to DVDD) to exit MUTE state. In Mute state, device output keep in Hi-Z state.
FAULT	11	DO	Fault terminal, which is pulled LOW when an internal fault occurs.
PD_DET	12	DO	PVDD Drop detection, which is pulled LOW when the PVDD drop below 8V.
HW_MODE	13	AI	Connect to DVDD directly to ensure device enter into Hardware Control Mode.
VR_DIG	14	P	Internally regulated 1.5-V digital supply voltage. This pin must not be used to drive external devices.
DVDD	15	P	3.3-V or 1.8-V digital power supply.

表 5-2. Pin Functions - Hardware Mode (continued)

PIN		TYPE <sup>1</sup>	DESCRIPTION
NAME	NO.		
DGND	16	G	Digital ground.
PVDD	17	P	PVDD voltage input.
	18	P	
	31	P	
	32	P	
PGND	21	G	Ground reference for power device circuitry. Connect this pin to system ground.
	22	G	
	27	G	
	28	G	
OUT_A+	19	O	Positive pin for differential speaker amplifier output A.
BST_A+	20	P	Connection point for the OUT_A+ bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_A+.
OUT_A-	23	O	Negative pin for differential speaker amplifier output A.
BST_A-	24	P	Connection point for the OUT_A- bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_A-.
BST_B-	25	P	Connection point for the OUT_B- bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_B-.
OUT_B-	26	O	Negative pin for differential speaker amplifier output B.
BST_B+	29	P	Connection point for the OUT_B+ bootstrap capacitor which is used to create a power supply for the high-side gate drive for OUT_B+.
OUT_B+	30	O	Positive pin for differential speaker amplifier output B.
PowerPAD™		P	Ground, connect to grounded heat sink for best system performance.

1. AI = Analog input, AO = Analog output, DI = Digital Input, DO = Digital Output, DI/O = Digital Bi-directional (input and output), P = Power, G = Ground (0 V)

## 6 Specifications

### 6.1 Absolute Maximum Ratings

Free-air room temperature 25°C (unless otherwise noted) <sup>(1)</sup>

		MIN	MAX	UNIT
DVDD	Low-voltage digital supply	-0.3	3.9	V
PVDD	PVDD supply	-0.3	30	V
V <sub>I(DigIn)</sub>	DVDD referenced digital inputs <sup>(2)</sup>	-0.5	V <sub>DVDD</sub> + 0.5	V
V <sub>I(SPK_OUTxx)</sub>	Voltage at speaker output pins	-0.3	32	V
T <sub>A</sub>	Ambient operating temperature	-40	85	°C
T <sub>J</sub>	Operating junction temperature	-40	150	°C
T <sub>stg</sub>	Storage temperature	-40	125	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) DVDD referenced digital pins include: ADR/FAULT, LRCLK, SCLK, SDIN, SDOUT, SCL, SDA, PDN

### 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub>	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	V
		Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002. <sup>(2)</sup>	±500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V <sub>(POWER)</sub>	Power supply inputs	PVDD	4.5		26.4	V
		DVDD	1.62		3.63	V
R <sub>SPK</sub>	Minimum Speaker Load	4.5V-24V Operating PVDD Range, BTL Mode	3.2			Ω
		4.5V-24V Operating PVDD Range, PBTTL Mode	1.6			Ω
V <sub>IH(DigIn)</sub>	Input logic high for DVDD referenced digital inputs		0.9 × V <sub>DVDD</sub>		DVDD	V
V <sub>IL(DigIn)</sub>	Input logic low for DVDD referenced digital inputs				0.1 × V <sub>DVDD</sub>	V
L <sub>OUT</sub>	Minimum inductor value in LC filter under short-circuit condition		1			μH

### 6.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>		TAS5828M - TSSOP32 (DAD) - 32 PINS	UNIT
		JEDEC STANDARD 4-LAYER PCB	
R <sub>θJA(top)</sub>	Junction-to-case (top) thermal resistance	1.2	°C/W
ψ <sub>JT</sub>	Junction-to-top characterization parameter	1.2	°C/W
ψ <sub>JB</sub>	Junction-to-board characterization parameter	21	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

## 6.5 Electrical Characteristics

Free-air room temperature 25°C, 1SPW Mode, LC filter=10uH+0.68uF, Fsw=384kHz, Class D Bandwidth=80kHz, (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>Digital I/O</b>						
IIH	Input logic high current level for DVDD referenced digital input pins	$V_{IN(Digin)} = V_{DVDD}$			10	uA
IIL	Input logic low current level for DVDD referenced digital input pins	$V_{IN(Digin)} = 0\text{ V}$			-10	uA
$V_{IH(Digin)}$	Input logic high threshold for DVDD referenced digital inputs		70%			$V_{DVDD}$
$V_{IL(Digin)}$	Input logic low threshold for DVDD referenced digital inputs				30%	$V_{DVDD}$
$V_{OH(Digin)}$	Output logic high voltage level	$I_{OH} = 4\text{ mA}$	80%			$V_{DVDD}$
$V_{OL(Digin)}$	Output logic low voltage level	$I_{OH} = -4\text{ mA}$			20%	$V_{DVDD}$
<b>I<sup>2</sup>C CONTROL PORT</b>						
$C_{L(I2C)}$	Allowable load capacitance for each I <sup>2</sup> C Line				400	pF
$f_{SCL(fast)}$	Support SCL frequency	No wait states, fast mode			400	kHz
$f_{SCL(slow)}$	Support SCL frequency	No wait states, slow mode			100	kHz
<b>SERIAL AUDIO PORT</b>						
$t_{DLY}$	Required LRCLK/FS to SCLK rising edge delay		5			ns
$D_{SCLK}$	Allowable SCLK duty cycle		40%		60%	
$f_s$	Supported input sample rates		32		192	kHz
$f_{SCLK}$	Supported SCLK frequencies		32		64	$f_s$
$f_{SCLK}$	SCLK frequency				24.576	MHz
<b>AMPLIFIER OPERATING MODE AND DC PRAMETERS</b>						
$I_{CC}$	Quiescent supply current of DVDD	$\overline{PDN} = 2\text{ V}$ , DVDD = 3.3 V, Play mode, General Audio Process flow with full DSP running		23		mA
$I_{CC}$	Quiescent supply current of DVDD	$\overline{PDN} = 2\text{ V}$ , DVDD = 3.3 V, Sleep mode		1		mA
$I_{CC}$	Quiescent supply current of DVDD	$\overline{PDN} = 2\text{ V}$ , DVDD = 3.3 V, Deep Sleep mode		1		mA
$I_{CC}$	Quiescent supply current of DVDD	$\overline{PDN} = 0.8\text{ V}$ , DVDD = 3.3 V, Shutdown mode		16		uA
$I_{CC}$	Quiescent supply current of PVDD	$\overline{PDN} = 2\text{ V}$ , PVDD = 18 V, No Load, LC filter = 10 $\mu$ H + 0.68 $\mu$ F, FSW = 384 kHz, 1SPW Modulation, Play Mode		39		mA
$I_{CC}$	Quiescent supply current of PVDD	$\overline{PDN} = 2\text{ V}$ , PVDD = 18 V, No Load, LC filter = 10 $\mu$ H + 0.68 $\mu$ F, FSW = 384 kHz, Output Hiz Mode		11		mA
$I_{CC}$	Quiescent supply current of PVDD	$\overline{PDN} = 2\text{ V}$ , PVDD = 18 V, No Load, LC filter = 10 $\mu$ H + 0.68 $\mu$ F, FSW = 384 kHz, Sleep Mode		7.5		mA
$I_{CC}$	Quiescent supply current of PVDD	$\overline{PDN} = 2\text{ V}$ , PVDD = 18 V, No Load, LC filter = 10 $\mu$ H + 0.68 $\mu$ F, FSW = 384 kHz, Deep Sleep Mode		10		uA
$I_{CC}$	Quiescent supply current of PVDD	$\overline{PDN} = 2\text{ V}$ , PVDD = 18 V, No Load, LC filter = 10 $\mu$ H + 0.68 $\mu$ F, FSW = 384 kHz, Shutdown Mode		10		uA
$A_{V(SP\_AMP)}$	Programmable Gain	Value represents the "peak voltage" disregarding clipping due to lower PVDD Measured at 0 dB input(1FS)	13.75		29.4	dBV
$\Delta A_{V(SP\_AMP)}$	Amplifier gain error	Gain = 26.4dBV		0.5		dB



## 6.5 Electrical Characteristics (continued)

Free-air room temperature 25°C, 1SPW Mode, LC filter=10uH+0.68uF, Fsw=384kHz, Class D Bandwidth=80kHz, (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
f <sub>SPK_AMP</sub>	Switching frequency of the speaker amplifier.	Software Mode	384			kHz		
			480			kHz		
			768			kHz		
	Hardware Mode	480			kHz			
		768			kHz			
R <sub>DS(on)</sub>	Drain-to-source on resistance of the individual output MOSFETs	FET + Metallization. V <sub>PVDD</sub> =24V, I <sub>(OUT)</sub> =500mA, T <sub>J</sub> =25°C			90	mΩ		
<b>PROTECTION</b>								
OCE <sub>THRES</sub>	Over-Current Error Threshold (Speaker current)	Speaker Output Current (Post LC filter), Speaker current, LC Filter=10uH+0.68uF, BTL Mode			7.5	8	8.5	A
UVE <sub>THRES(PVDD)</sub>	PVDD under voltage error threshold				3.7	4	4.2	V
OVE <sub>THRES(PVDD)</sub>	PVDD over voltage error threshold				27	28.1	29.2	V
DCE <sub>THRES</sub>	Output DC Error protection threshold	Class D Amplifier's output DC voltage cross speaker load to trigger Output DC Fault protection				1.7		V
T <sub>DCDET</sub>	Output DC Detect time	Class D Amplifier's output remain at or above DCE <sub>THRES</sub>				570		ms
OTE <sub>THRES</sub>	Over temperature error threshold					165		°C
OTE <sub>Hysteresis</sub>	Over temperature error hysteresis					10		°C
OTW <sub>THRES</sub>	Over temperature warning level	Read by register 0x73 bit0				112		°C
OTW <sub>THRES</sub>	Over temperature warning level	Read by register 0x73 bit1				122		°C
OTW <sub>THRES</sub>	Over temperature warning level	Read by register 0x73 bit2				134		°C
OTW <sub>THRES</sub>	Over temperature warning level	Read by register 0x73 bit3				146		°C

## 6.5 Electrical Characteristics (continued)

Free-air room temperature 25°C, 1SPW Mode, LC filter=10uH+0.68uF, Fsw=384kHz, Class D Bandwidth=80kHz, (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
<b>AUDIO PERFORMANCE (STEREO BTL)</b>						
V <sub>OS</sub>	Amplifier offset voltage	Measured differentially with zero input data, programmable gain configured with 29.4dBV analog gain, V <sub>PVDD</sub> range:12V~24V		-5	5	mV
P <sub>O(SPK)</sub>	Output Power (Per Channel)	V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 4 Ω, f = 1 KHz, THD+N = 10%			43	W
		V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 4 Ω, f = 1 KHz, THD+N = 1%			35	W
		V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 6 Ω, f = 1 KHz, THD+N = 10%			31	W
		V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 6 Ω, f = 1 KHz, THD+N = 1%			25	W
		V <sub>PVDD</sub> = 21 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 4 Ω, f = 1 KHz, THD+N = 10%			55	W
		V <sub>PVDD</sub> = 21 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 4 Ω, f = 1 KHz, THD+N = 1%			44	W
		V <sub>PVDD</sub> = 24 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 6 Ω, f = 1 KHz, THD+N = 10%			54	W
		V <sub>PVDD</sub> = 24 V, LC Filter=10uH+0.68uF, R <sub>SPK</sub> = 6 Ω, f = 1 KHz, THD+N = 1%			43	W
THD+N <sub>SPK</sub>	Total harmonic distortion and noise (P <sub>O</sub> = 1 W, f = 1 KHz)	V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, Load=4Ω			0.08	%
		V <sub>PVDD</sub> = 24 V, LC Filter=10uH+0.68uF, Load=6Ω			0.06	%
ICN <sub>(SPK)</sub>	Idle channel noise(Aweighted, AES17)	V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, Load=4 Ω, Fsw=768kHz, BD Modulation			40	μVrms
		V <sub>PVDD</sub> = 18 V, LC Filter=10uH+0.68uF, Load=4 Ω, Fsw=384kHz, 1SPW Modulation			35	μVrms
		V <sub>PVDD</sub> = 24 V, LC Filter=10uH+0.68uF, Load=6 Ω, Fsw=768kHz, BD Modulation			35	μVrms
		V <sub>PVDD</sub> = 24 V, LC Filter=10uH+0.68uF, Load=6 Ω, Fsw=384kHz, 1SPW Modulation			35	μVrms
DR	Dynamic range	A-Weighted, -60 dBFS method. V <sub>PVDD</sub> = 24 V, Load=6Ω Analog Gain = 29.4dBV			111	dB
SNR	Signal-to-noise ratio	A-Weighted, referenced to 1% THD+N Output Level, V <sub>PVDD</sub> =24V, load=6Ω			111	dB
		A-Weighted, referenced to 1% THD+N Output Level, V <sub>PVDD</sub> =18V, Load=4Ω			106	dB
PSRR	Power supply rejection ratio	Injected Noise = 1 KHz, 1 Vrms, V <sub>PVDD</sub> = 24 V, input audio signal = digital zero			72	dB
X-talk <sub>SPK</sub>	Cross-talk (worst case between left-to-right and right-to-left coupling)	f = 1 KHz, based on Inductor (DFEG7030D-4R7) from Murata			100	dB

## 6.5 Electrical Characteristics (continued)

Free-air room temperature 25°C, 1SPW Mode, LC filter=10uH+0.68uF, Fsw=384kHz, Class D Bandwidth=80kHz, (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
<b>AUDIO PERFORMANCE (MONO PBTL)</b>						
V <sub>OS</sub>	Amplifier offset voltage	Measured differentially with zero input data, programmable gain configured with 29.4dBV Analog gain, V <sub>PVDD</sub> = 12V-24V range, 1SPW mode		-5	5	mV
P <sub>O(SPK)</sub>	Output Power	V <sub>PVDD</sub> = 24 V, R <sub>SPK</sub> = 3 Ω, f = 1KHz, THD+N = 1%		84		W
		V <sub>PVDD</sub> = 24 V, R <sub>SPK</sub> = 3 Ω, f = 1KHz, THD+N = 10%		104		W
		V <sub>PVDD</sub> = 18 V, R <sub>SPK</sub> = 2 Ω, f = 1KHz, THD+N = 1%		67		W
		V <sub>PVDD</sub> = 18 V, R <sub>SPK</sub> = 2 Ω, f = 1KHz, THD+N = 10%		80		W
THD+N <sub>SPK</sub>	Total harmonic distortion and noise (P <sub>O</sub> = 1 W, f = 1 KHz)	V <sub>PVDD</sub> = 18 V, LC-filter=10uH+0.68uF, R <sub>SPK</sub> = 2 Ω		0.07		%
		V <sub>PVDD</sub> = 24 V, LC-filter=10uH+0.68uF, R <sub>SPK</sub> = 3 Ω		0.05		%
DR	Dynamic range	A-Weighted, -60 dBFS method, V <sub>PVDD</sub> =24V, R <sub>SPK</sub> = 3 Ω.		111		dB
SNR	Signal-to-noise ratio	A-Weighted, referenced to 1% THD+N Output Level, V <sub>PVDD</sub> =24V, R <sub>SPK</sub> = 3 Ω		108		dB
		A-Weighted, referenced to 1% THD+N Output Level, V <sub>PVDD</sub> =18V, R <sub>SPK</sub> = 2 Ω		106		dB
PSRR	Power supply rejection ratio	Injected Noise = 1 KHz, 1 V <sub>rms</sub> , V <sub>PVDD</sub> = 18 V, input audio signal = digital zero		72		dB

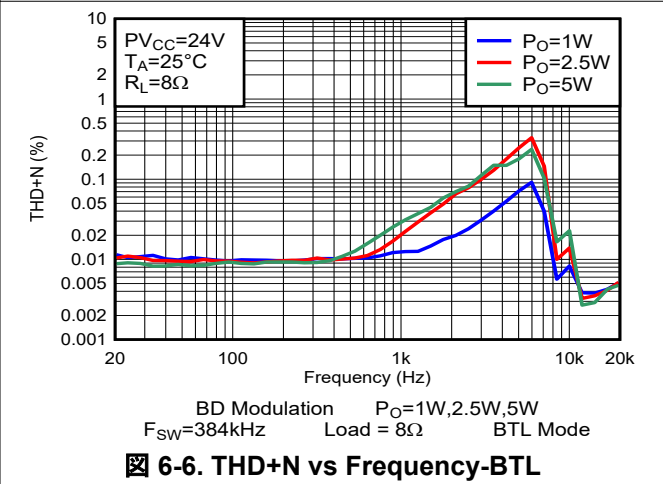
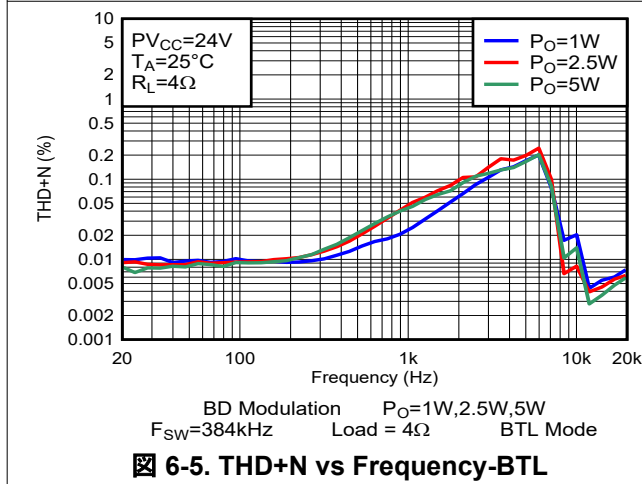
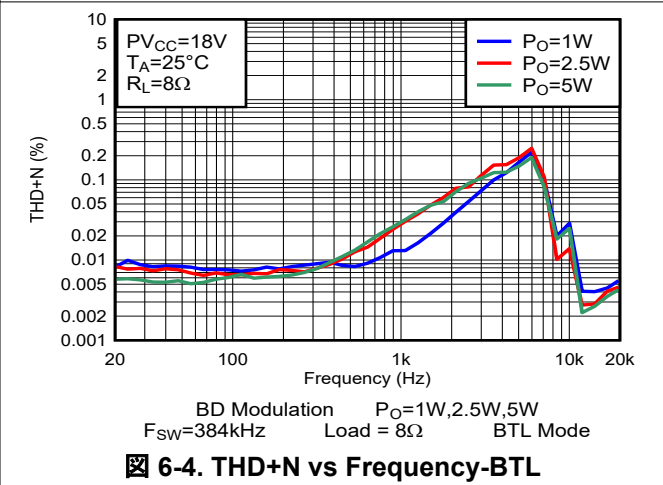
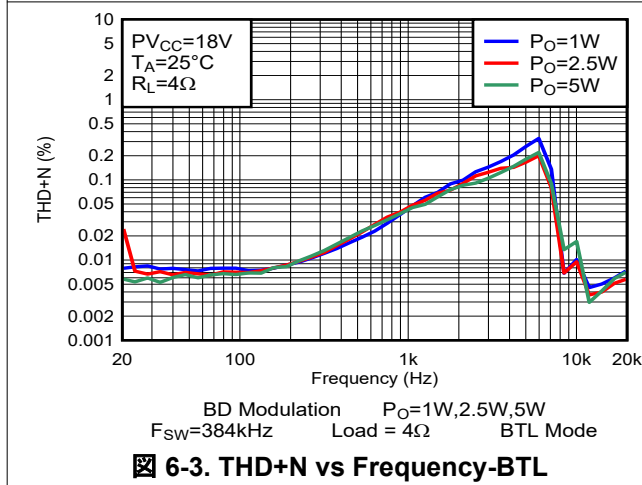
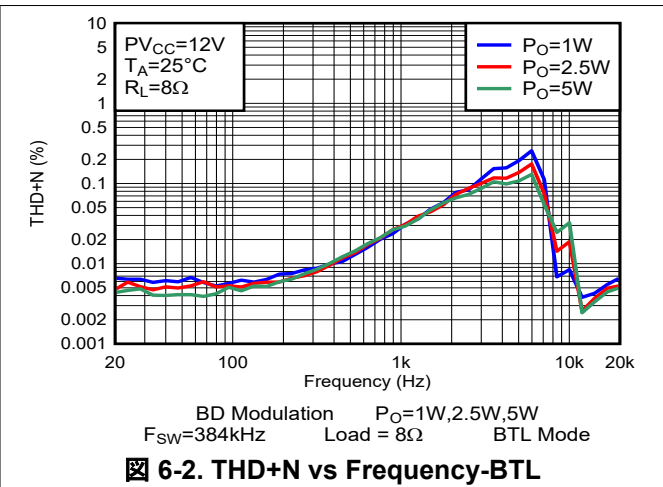
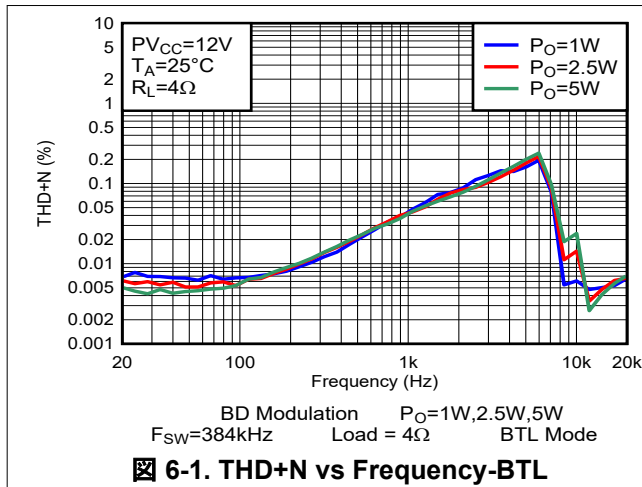
## 6.6 Timing Requirements

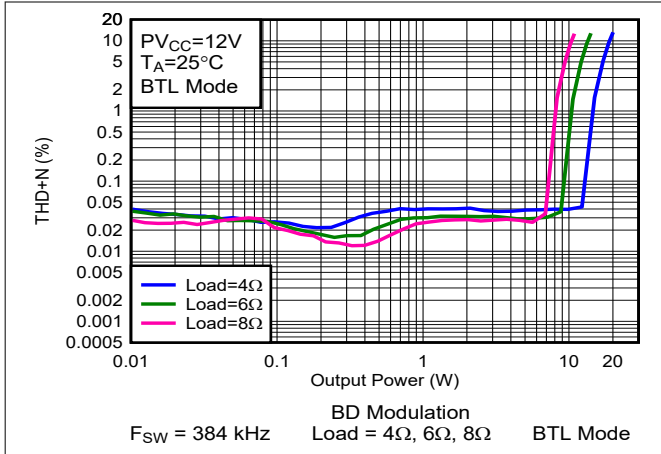
		MIN	NOM	MAX	UNIT
<b>Serial Audio Port Timing - Target Mode</b>					
$f_{SCLK}$	SCLK frequency	1.024			MHz
$t_{SCLK}$	SCLK period	40			ns
$t_{SCLKL}$	SCLK pulse width, low	16			ns
$t_{SCLKH}$	SCLK pulse width, high	16			ns
$t_{SL}$	SCLK rising to LRCLK/FS edge	8			ns
$t_{LS}$	LRCK/FS Edge to SCLK rising edge	8			ns
$t_{SU}$	Data setup time, before SCLK rising edge	8			ns
$t_{DH}$	Data hold time, after SCLK rising edge	8			ns
$t_{DFS}$	Data delay time from SCLK falling edge			15	ns
<b>I<sup>2</sup>C Bus Timing – Standard</b>					
$f_{SCL}$	SCL clock frequency			100	kHz
$t_{BUF}$	Bus free time between a STOP and START condition	4.7			μs
$t_{LOW}$	Low period of the SCL clock	4.7			μs
$t_{HI}$	High period of the SCL clock	4			μs
$t_{RS-SU}$	Setup time for (repeated) START condition	4.7			μs
$t_{S-HD}$	Hold time for (repeated) START condition	4			μs
$t_{D-SU}$	Data setup time	250			ns
$t_{D-HD}$	Data hold time	0		3450	ns
$t_{SCL-R}$	Rise time of SCL signal	$20 + 0.1C_B$		1000	ns
$t_{SCL-R1}$	Rise time of SCL signal after a repeated START condition and after an acknowledge bit	$20 + 0.1C_B$		1000	ns
$t_{SCL-F}$	Fall time of SCL signal	$20 + 0.1C_B$		1000	ns
$t_{SDA-R}$	Rise time of SDA signal	$20 + 0.1C_B$		1000	ns
$t_{SDA-F}$	Fall time of SDA signal	$20 + 0.1C_B$		1000	ns
$t_{P-SU}$	Setup time for STOP condition	4			μs
$C_b$	Capacitive load for each bus line			400	pf
<b>I<sup>2</sup>C Bus Timing – Fast</b>					
$f_{SCL}$	SCL clock frequency			400	kHz
$t_{BUF}$	Bus free time between a STOP and START condition	1.3			μs
$t_{LOW}$	Low period of the SCL clock	1.3			μs
$t_{HI}$	High period of the SCL clock	600			ns
$t_{RS-SU}$	Setup time for (repeated)START condition	600			ns
$t_{RS-HD}$	Hold time for (repeated)START condition	600			ns
$t_{D-SU}$	Data setup time	100			ns
$t_{D-HD}$	Data hold time	0		900	ns
$t_{SCL-R}$	Rise time of SCL signal	$20 + 0.1C_B$		300	ns
$t_{SCL-R1}$	Rise time of SCL signal after a repeated START condition and after an acknowledge bit	$20 + 0.1C_B$		300	ns
$t_{SCL-F}$	Fall time of SCL signal	$20 + 0.1C_B$		300	ns
$t_{SDA-R}$	Rise time of SDA signal	$20 + 0.1C_B$		300	ns
$t_{SDA-F}$	Fall time of SDA signal	$20 + 0.1C_B$		300	ns
$t_{P-SU}$	Setup time for STOP condition	600			ns
$t_{SP}$	Pulse width of spike suppressed			50	ns
$C_b$	Capacitive load for each bus line			400	pf

## 6.7 Typical Characteristics

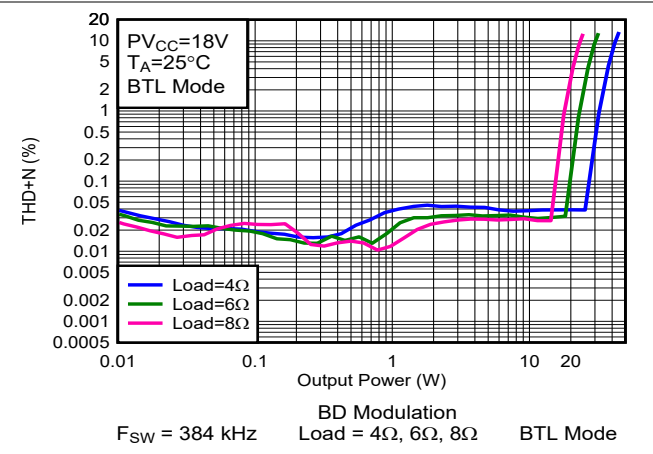
### 6.7.1 Bridge Tied Load (BTL) Configuration Curves with BD Modulation

Free-air room temperature 25°C (unless otherwise noted). Measurements were made using Audio Precision System 2722 with Analog Analyzer filter set to 20-kHz brickwall filter. All measurements taken with audio frequency set to 1 kHz and device PWM frequency set to 384kHz, 80 kHz Class D Amplifier Loop Bandwidth, LC filter with 10µH / 0.68 µF, unless otherwise noted.

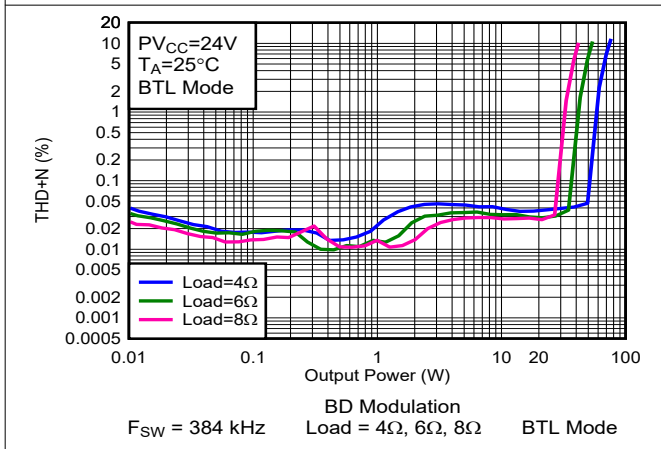




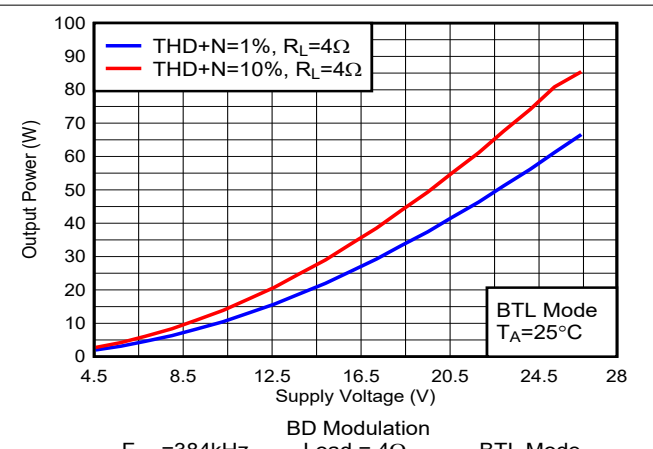
**6-7. THD+N vs Output Power-BTL**



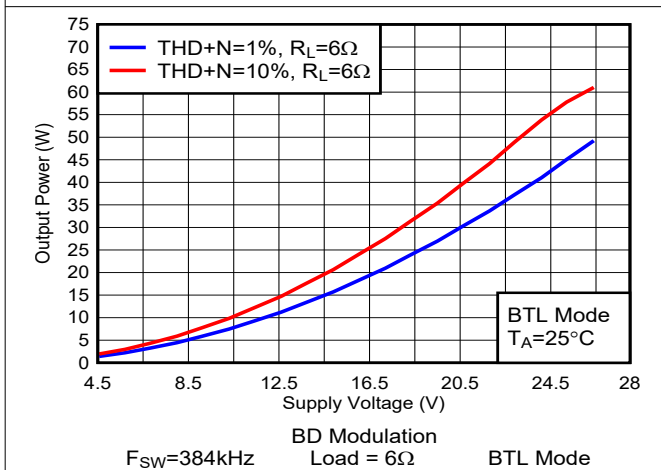
**6-8. THD+N vs Output Power-BTL**



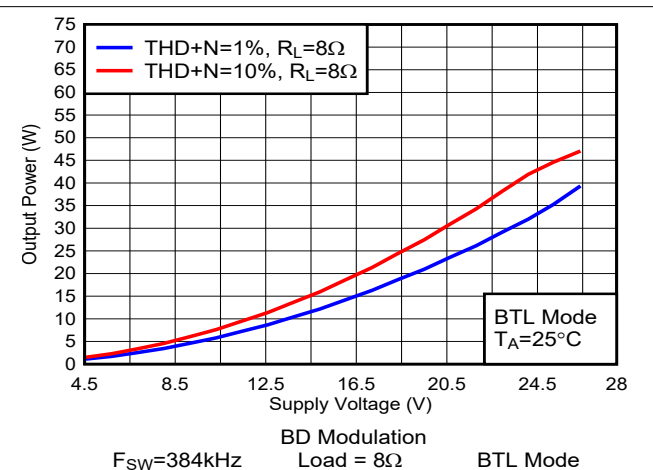
**6-9. THD+N vs Output Power-BTL**



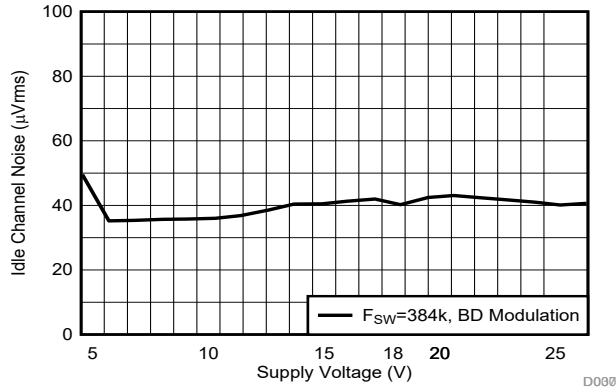
**6-10. Output Power vs Supply Voltage**



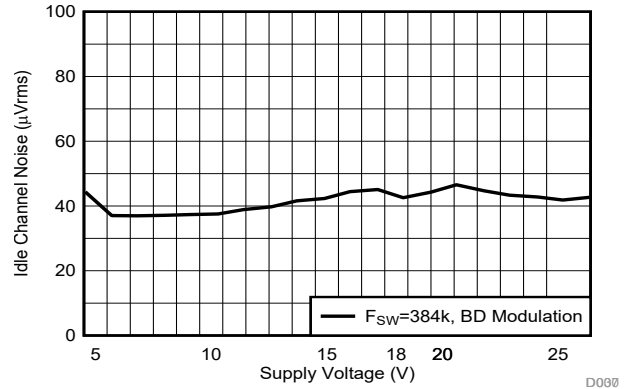
**6-11. Output Power vs Supply Voltage**



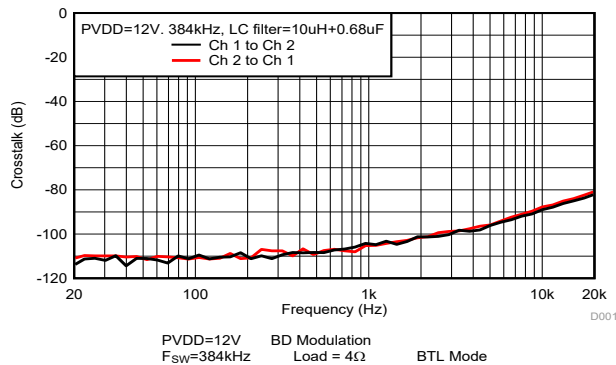
**6-12. Output Power vs Supply Voltage**



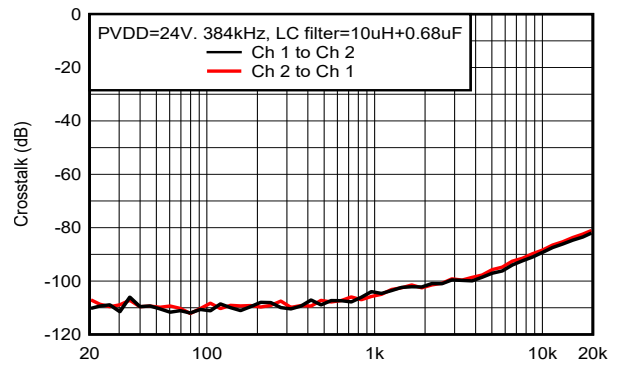
**6-13. Idle Channel Noise vs Supply Voltage**



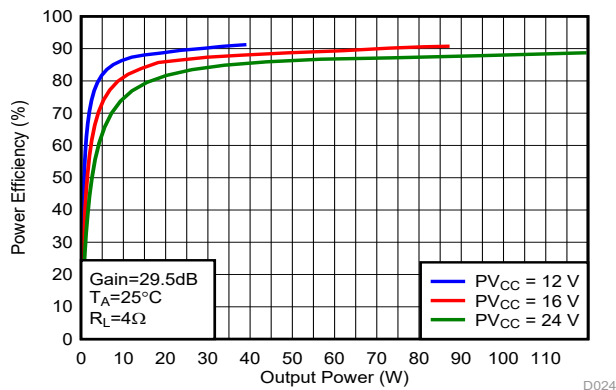
**6-14. Idle Channel Noise vs Supply Voltage**



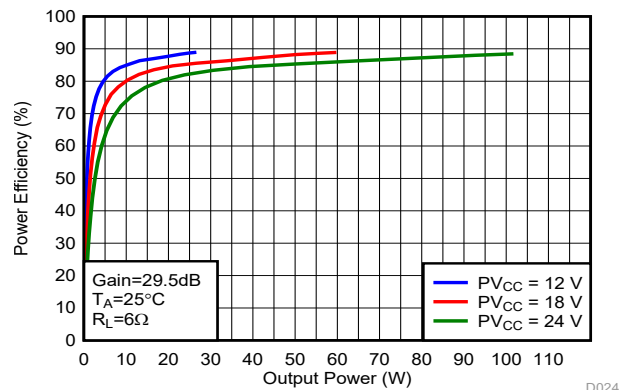
**6-15. Crosstalk**



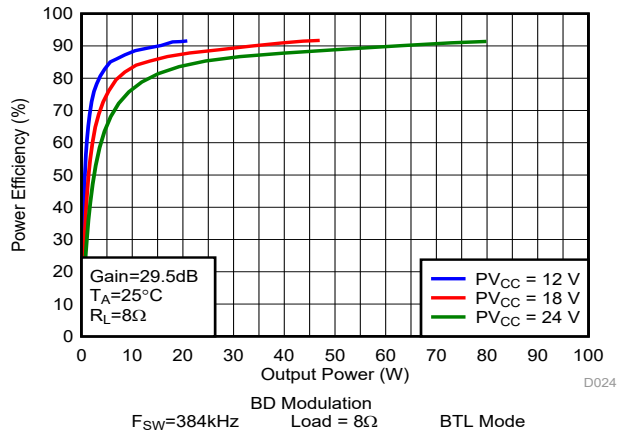
**6-16. Crosstalk**



**6-17. Efficiency vs Output Power**



**6-18. Efficiency vs Output Power**

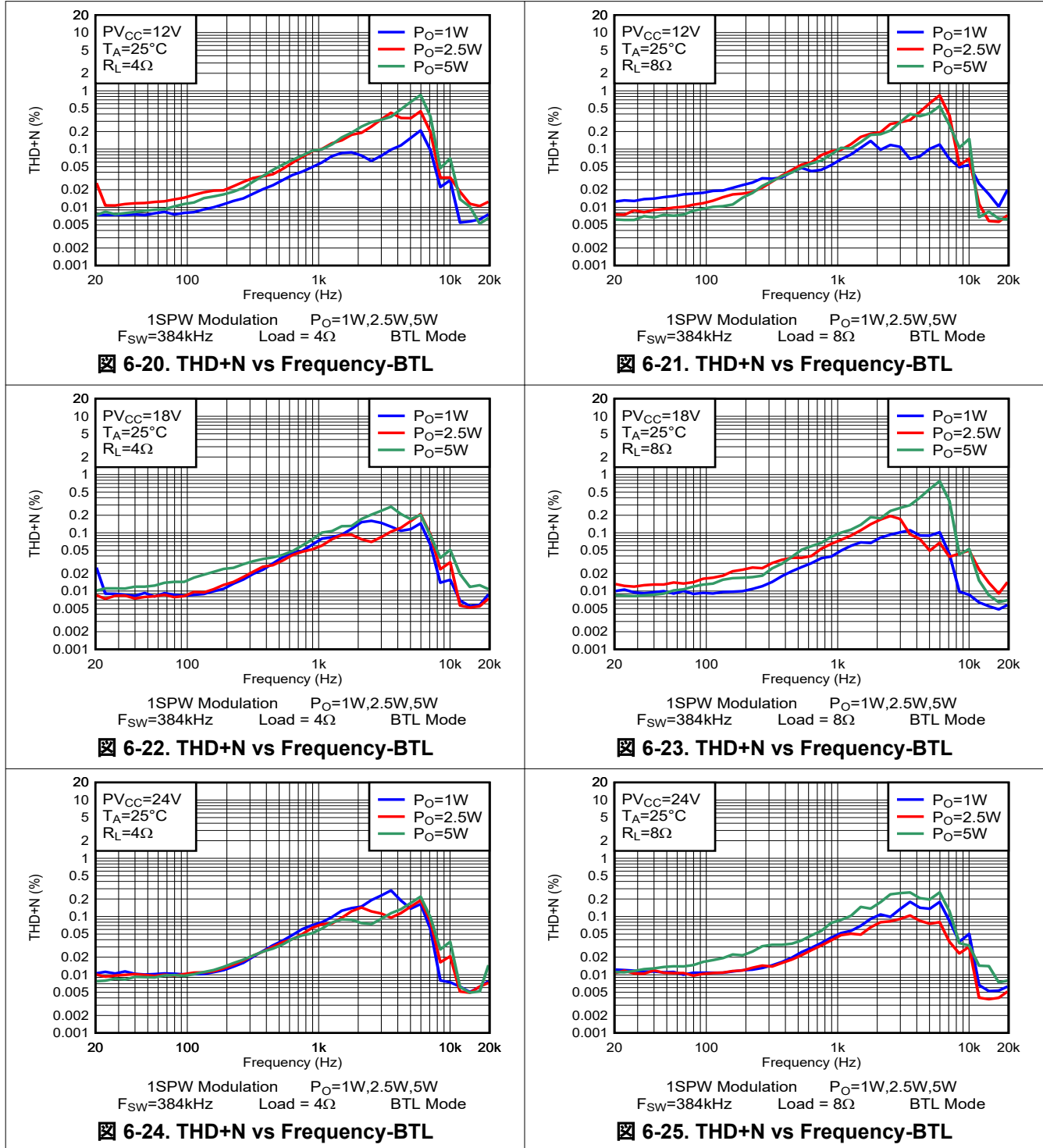


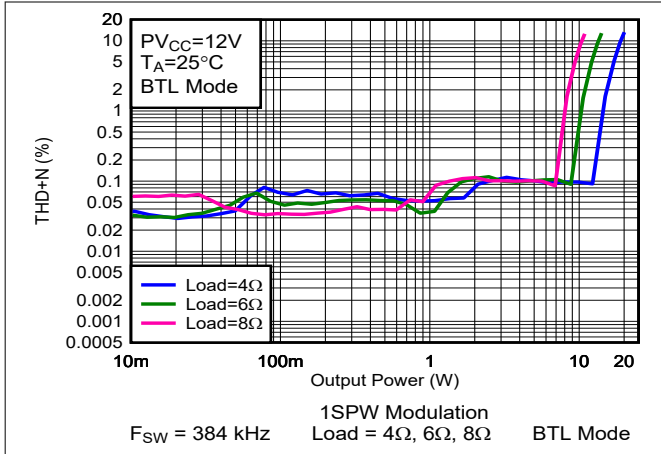
**6-19. Efficiency vs Output Power**



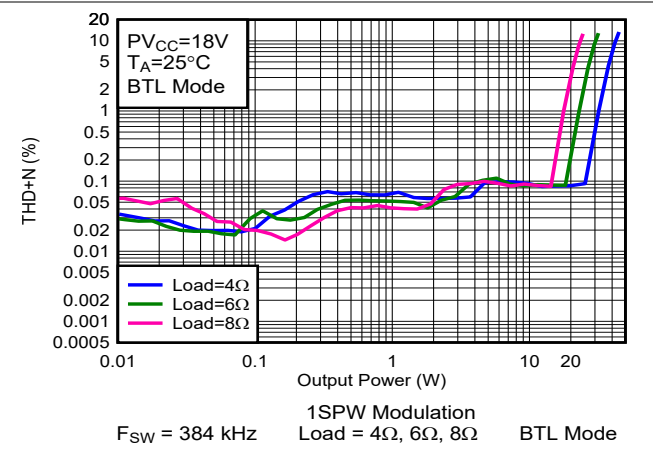
### 6.7.2 Bridge Tied Load (BTL) Configuration Curves with 1SPW Modulation

Free-air room temperature 25°C (unless otherwise noted). Measurements were made using Audio Precision System 2722 with Analog Analyzer filter set to 20-kHz brickwall filter. All measurements taken with audio frequency set to 1 kHz and device PWM frequency set to 384 kHz, 80 kHz Class D Loop Bandwidth, the LC filter used was 10µH / 0.68 µF, unless otherwise noted.

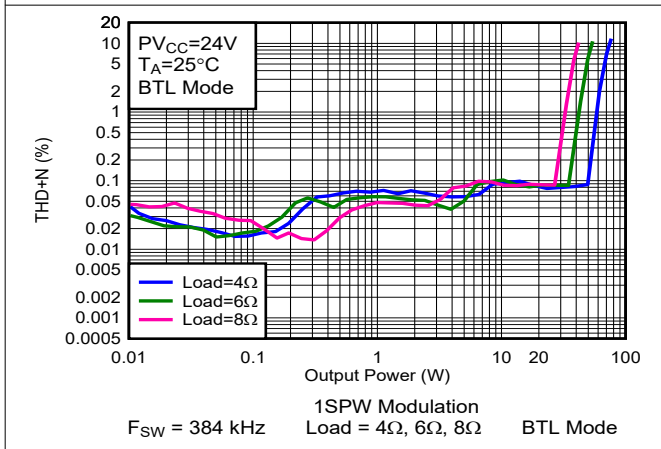




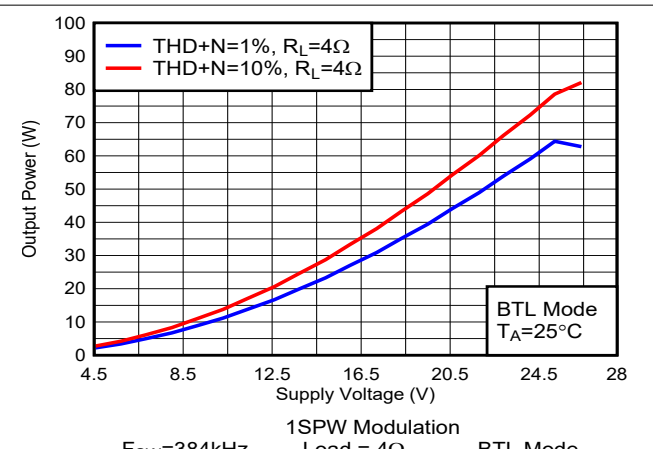
**6-26. THD+N vs Output Power-BTL**



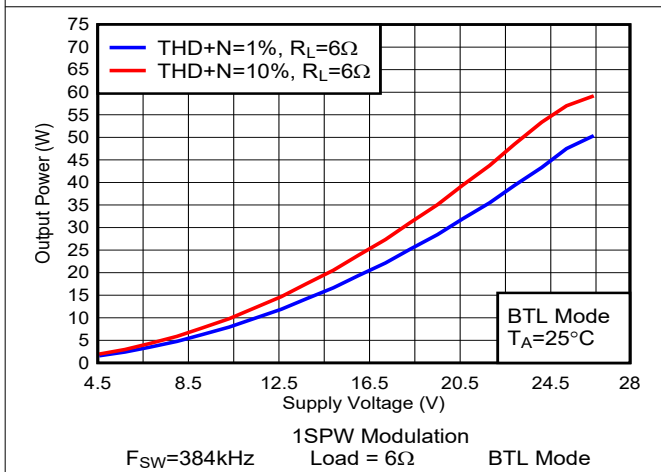
**6-27. THD+N vs Output Power-BTL**



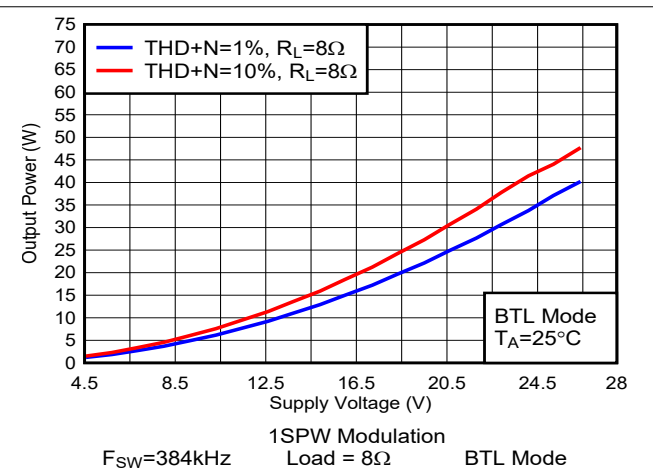
**6-28. THD+N vs Output Power-BTL**



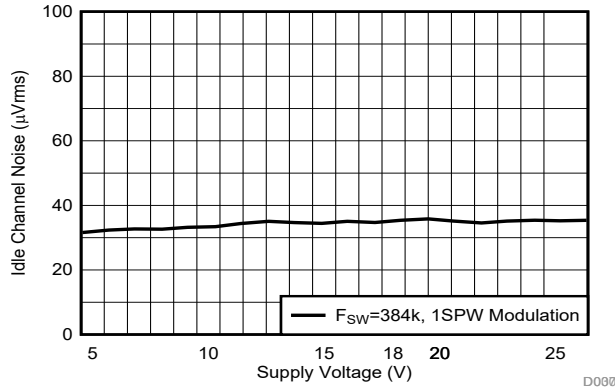
**6-29. Output Power vs Supply Voltage**



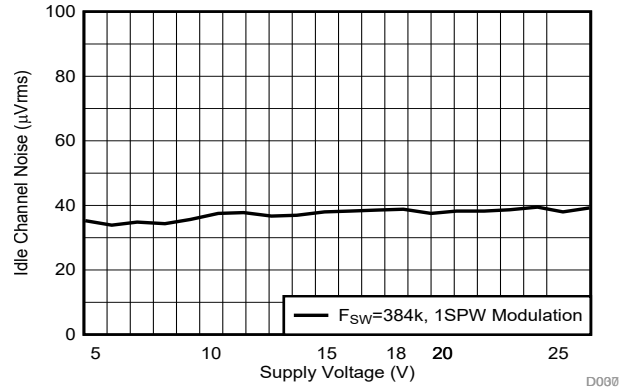
**6-30. Output Power vs Supply Voltage**



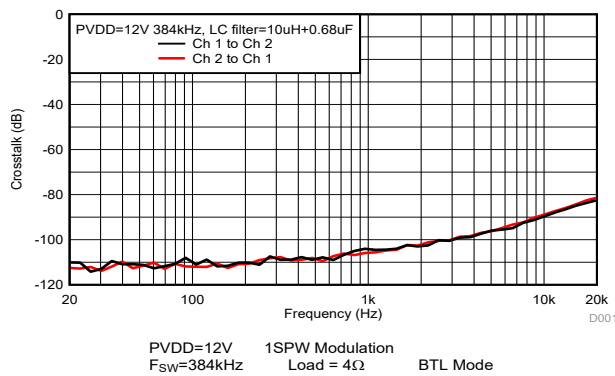
**6-31. Output Power vs Supply Voltage**



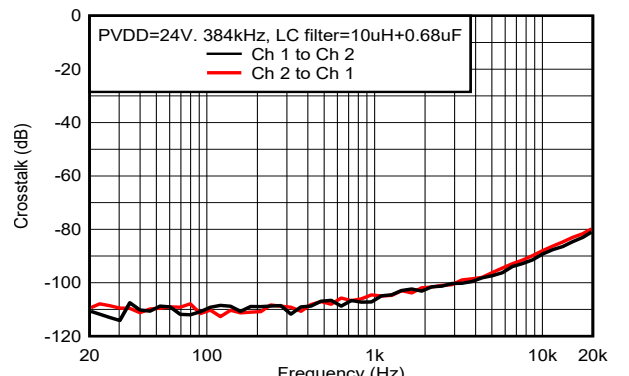
6-32. Idle Channel Noise vs Supply Voltage



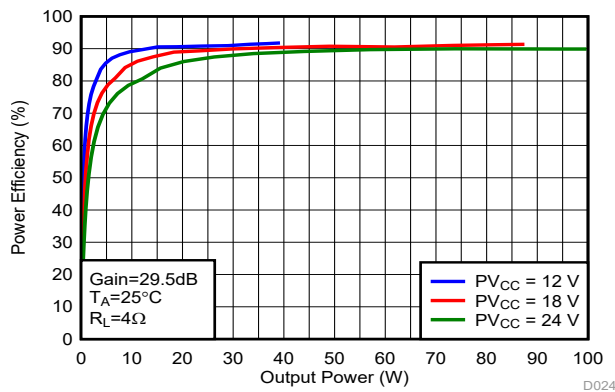
6-33. Idle Channel Noise vs Supply Voltage



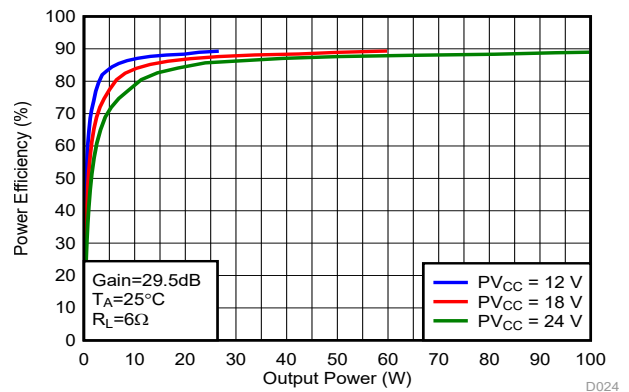
6-34. Crosstalk



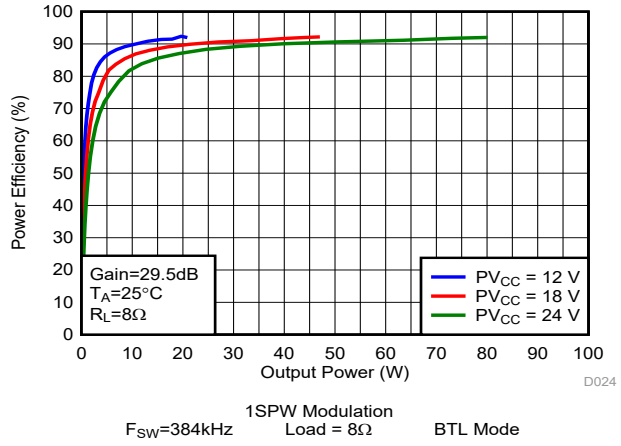
6-35. Crosstalk - old



6-36. Efficiency vs Output Power



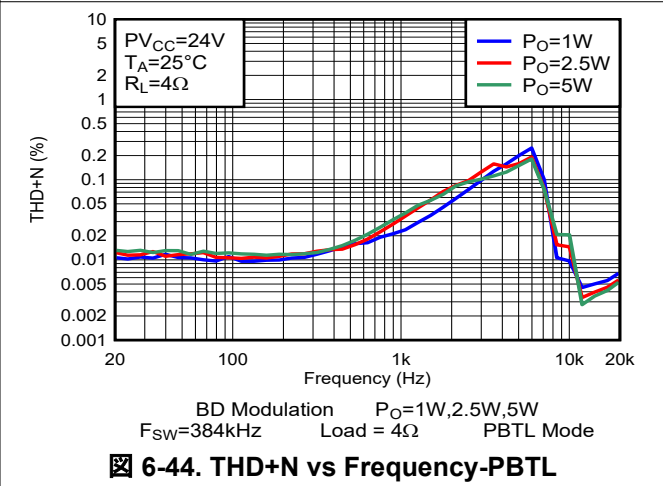
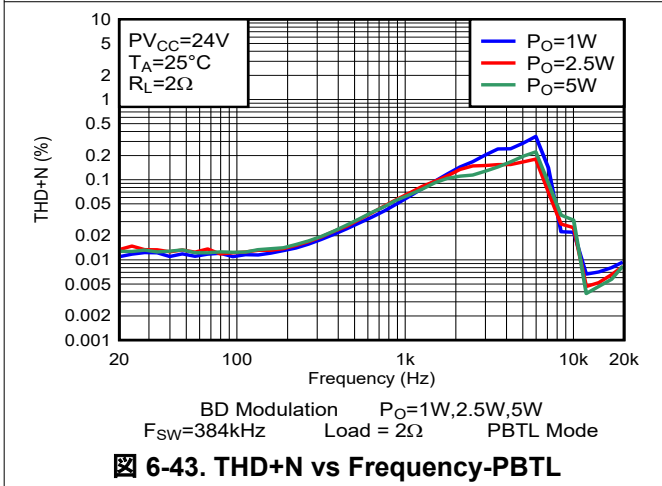
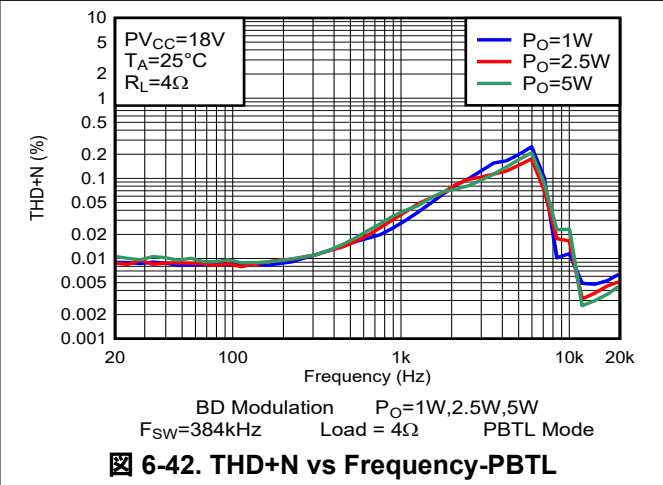
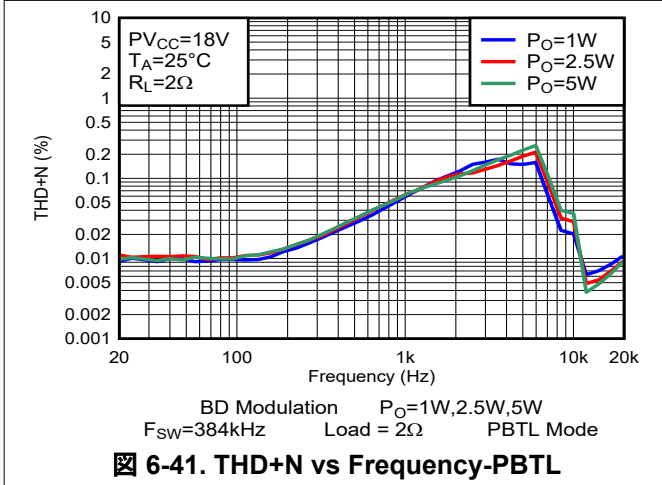
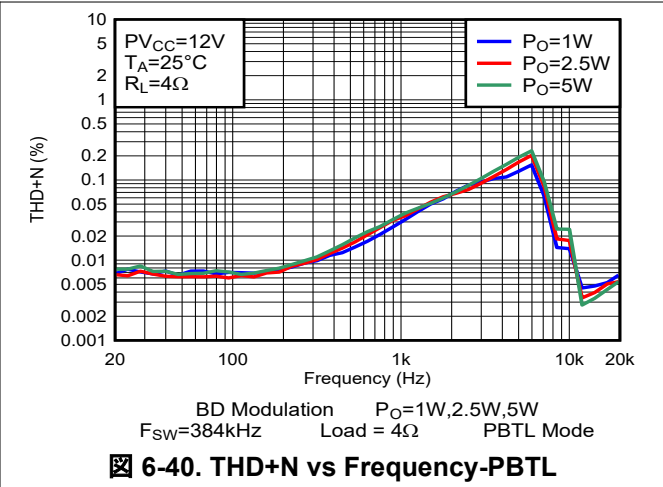
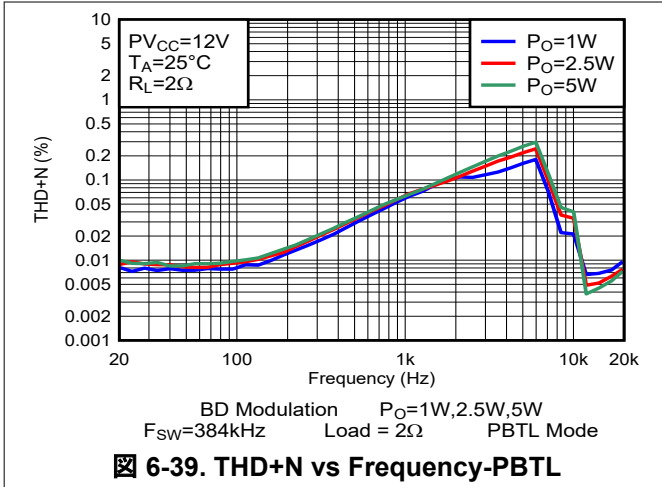
6-37. Efficiency vs Output Power

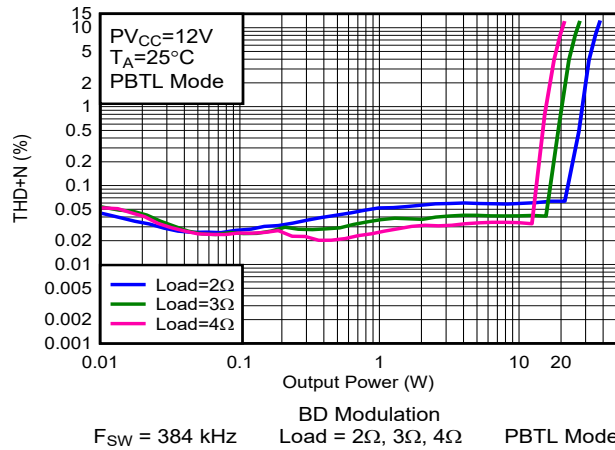


**6-38. Efficiency vs Output Power**

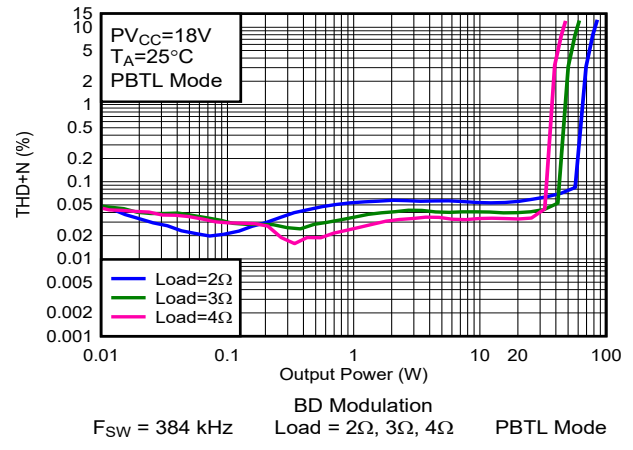
### 6.7.3 Parallel Bridge Tied Load (PBTL) Configuration With BD Modulation

Free-air room temperature 25°C (unless otherwise noted). Measurements were made using Audio Precision System 2722 with Analog Analyzer filter set to 20-kHz brickwall filter. All measurements taken with audio frequency set to 1 kHz and device PWM frequency set to 384 kHz, 80 kHz Class D Amplifier Loop Bandwidth, LC filter with 10  $\mu$ H / 0.68  $\mu$ F (Post-Filter PBTL, the merging of the two output channels after the inductor portion of the output filter, see details in [セクション 9.2.4](#)), unless otherwise noted.

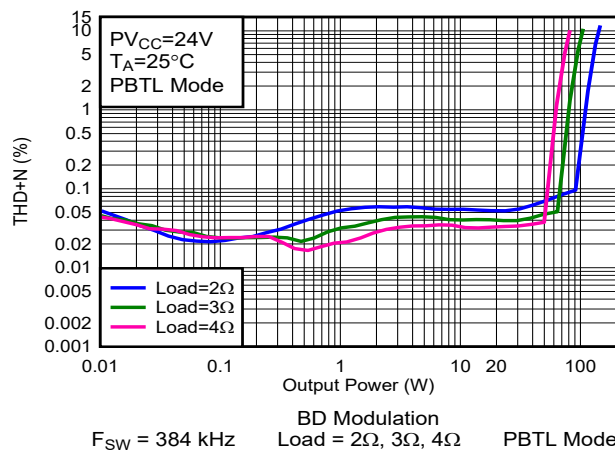




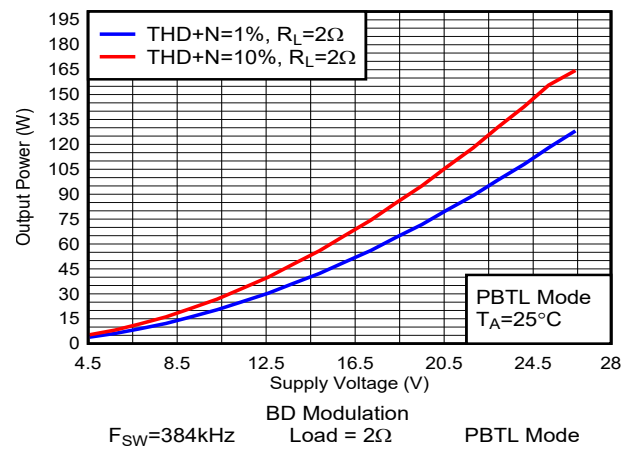
6-45. THD+N vs Output Power-PBTL



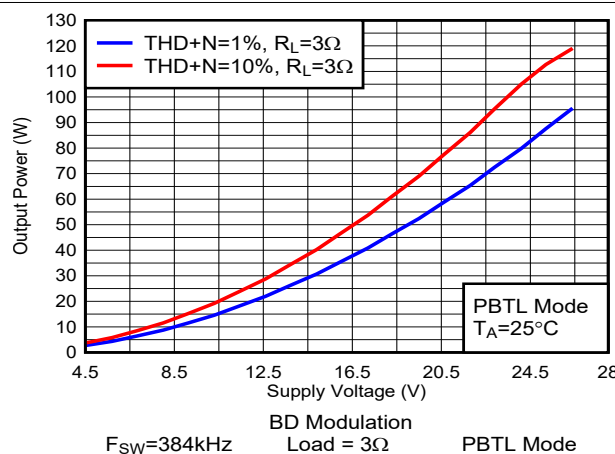
6-46. THD+N vs Output Power-PBTL



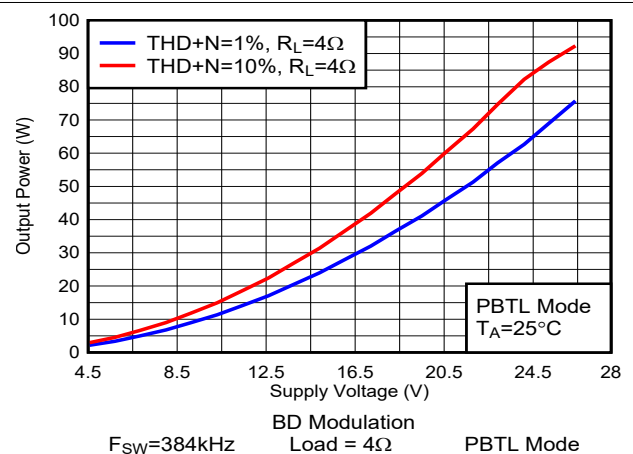
6-47. THD+N vs Output Power-PBTL



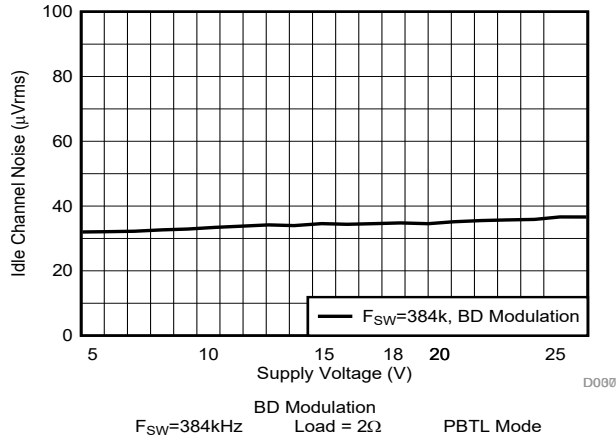
6-48. Output Power vs Supply Voltage



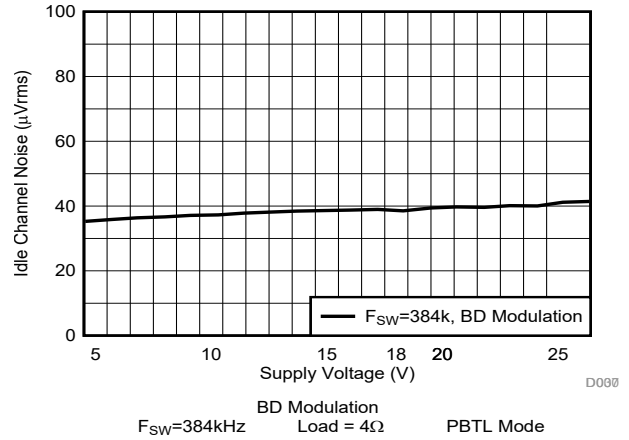
6-49. Output Power vs Supply Voltage



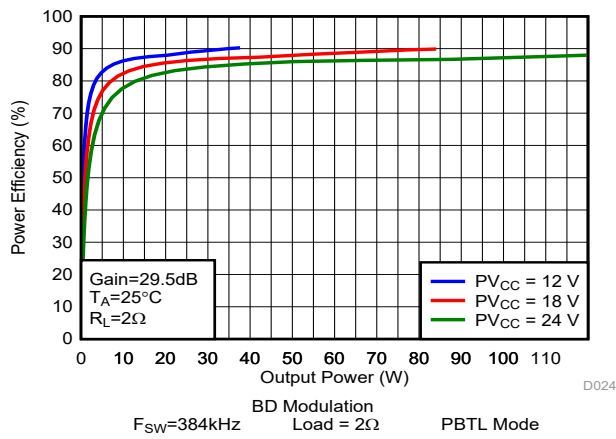
6-50. Output Power vs Supply Voltage



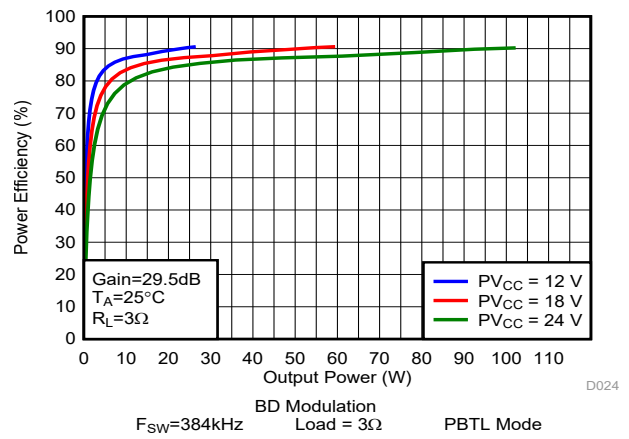
6-51. Idle Channel Noise vs Supply Voltage



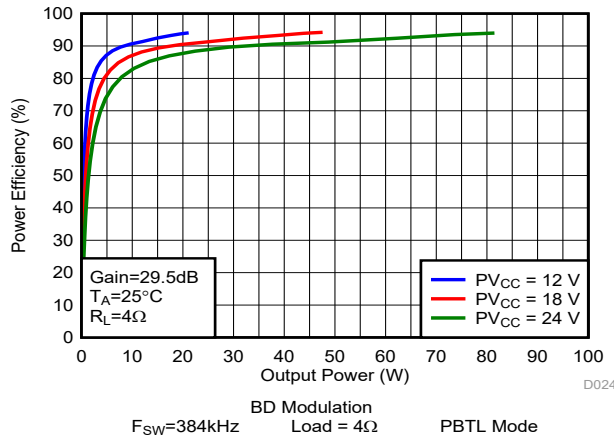
6-52. Idle Channel Noise vs Supply Voltage



6-53. Efficiency vs Output Power



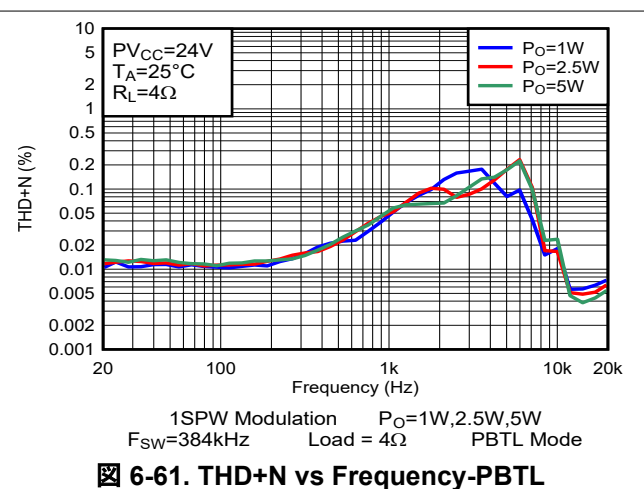
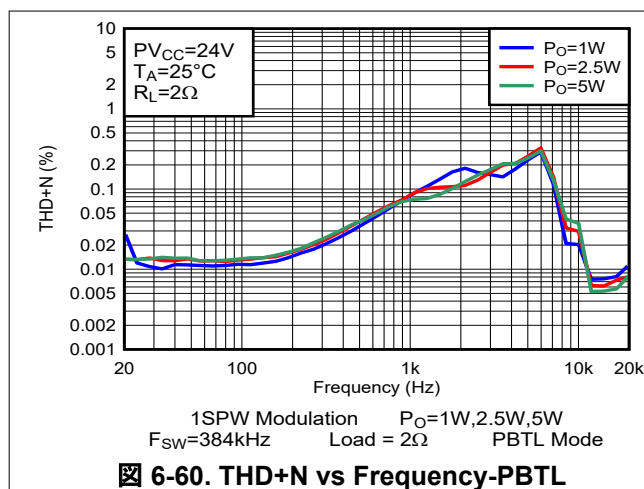
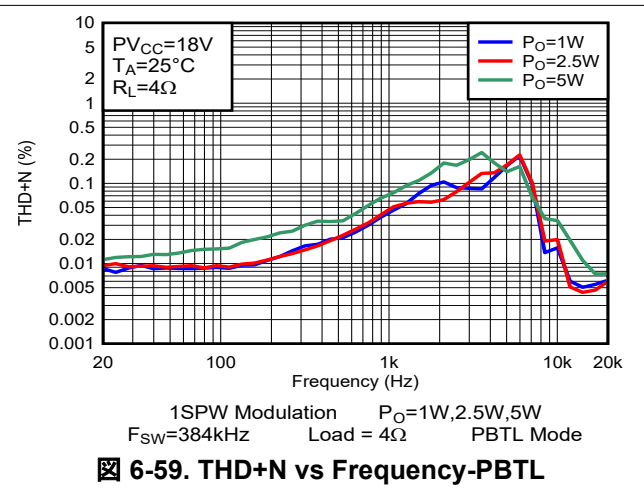
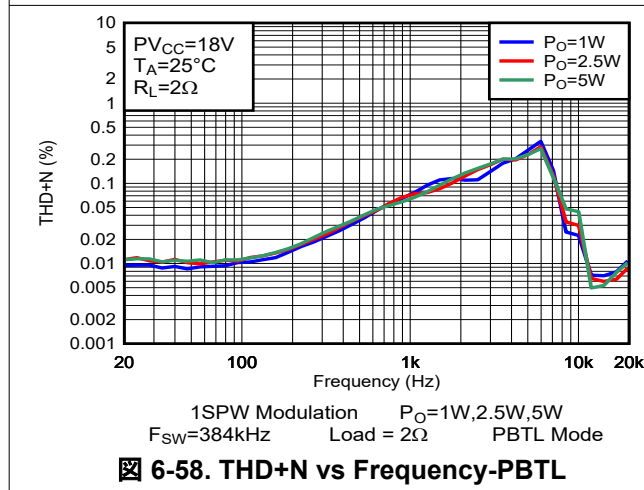
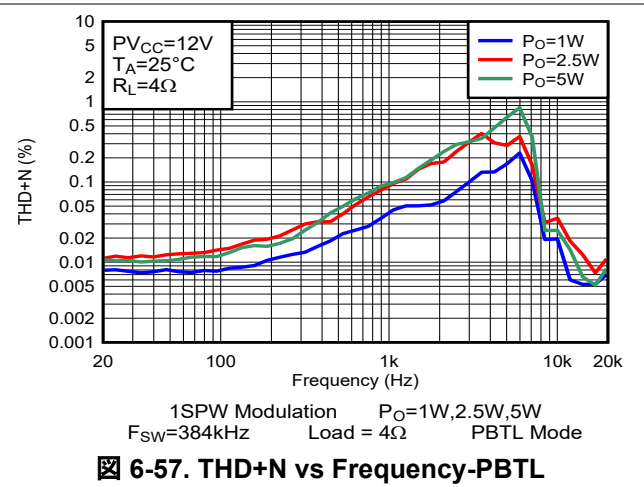
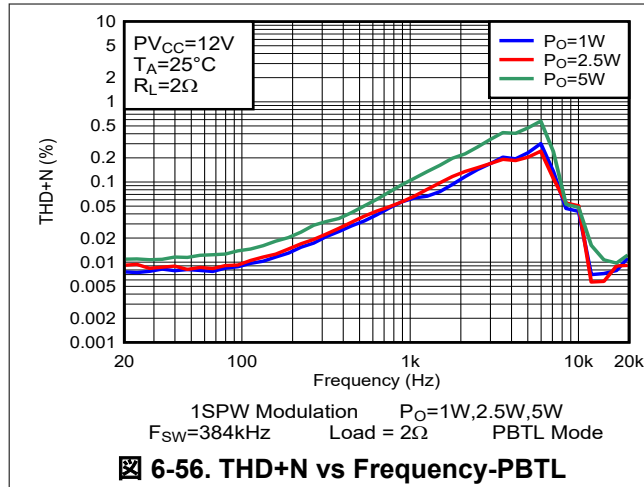
6-54. Efficiency vs Output Power



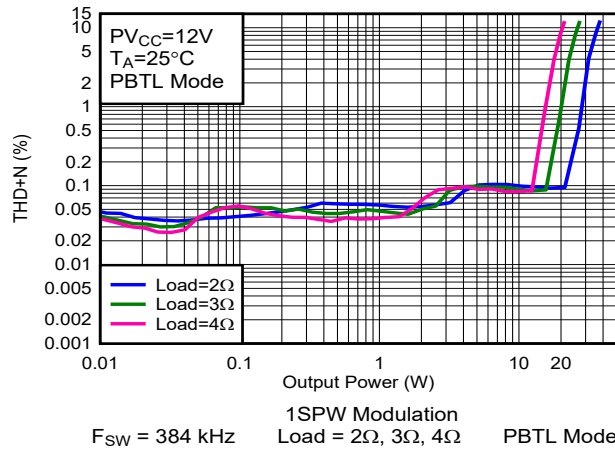
6-55. Efficiency vs Output Power

### 6.7.4 Parallel Bridge Tied Load (PBTL) Configuration With 1SPW Modulation

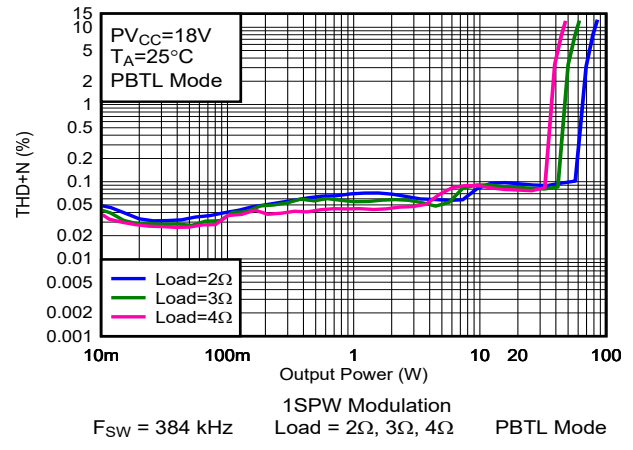
Free-air room temperature 25°C (unless otherwise noted). Measurements were made using Audio Precision System 2722 with Analog Analyzer filter set to 20-kHz brickwall filter. All measurements taken with audio frequency set to 1 kHz and device PWM frequency set to 384 kHz, 80 kHz Class D Amplifier Loop Bandwidth, the LC filter used was 10  $\mu$ H / 0.68  $\mu$ F (Post-Filter PBTL, the merging of the two output channels after the inductor portion of the output filter, see connect method in [セクション 9.2.4](#)), unless otherwise noted.



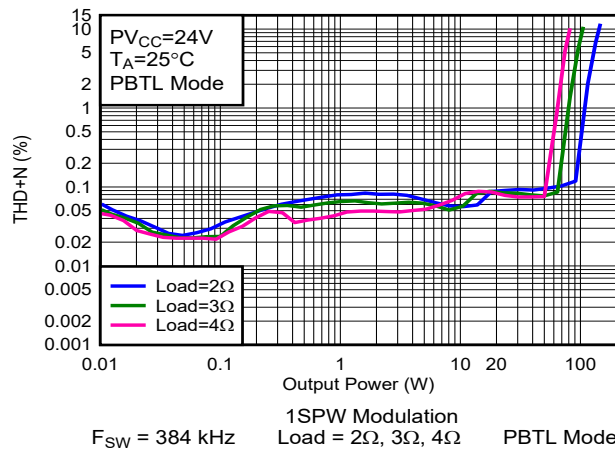




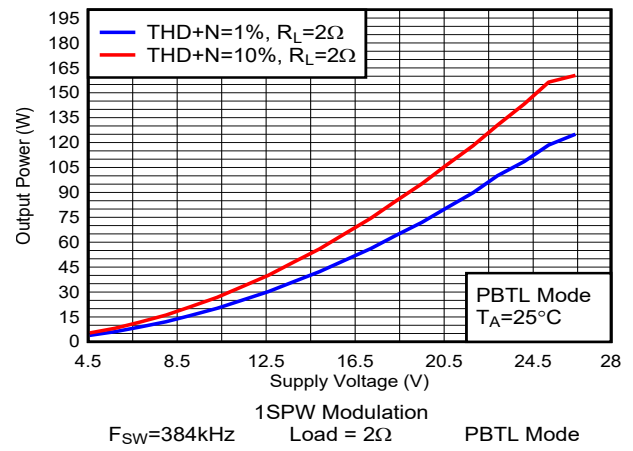
6-62. THD+N vs Output Power-PBTL



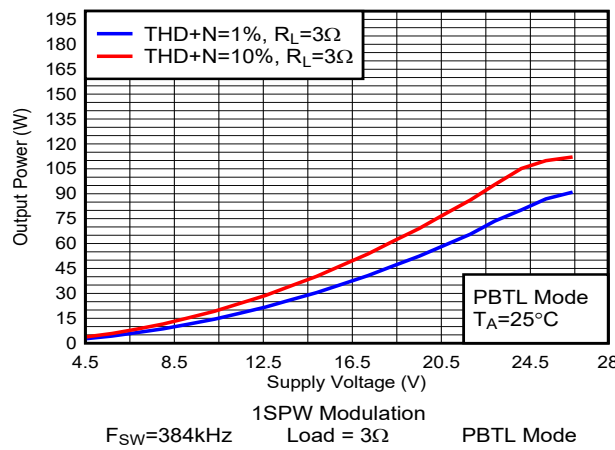
6-63. THD+N vs Output Power-PBTL



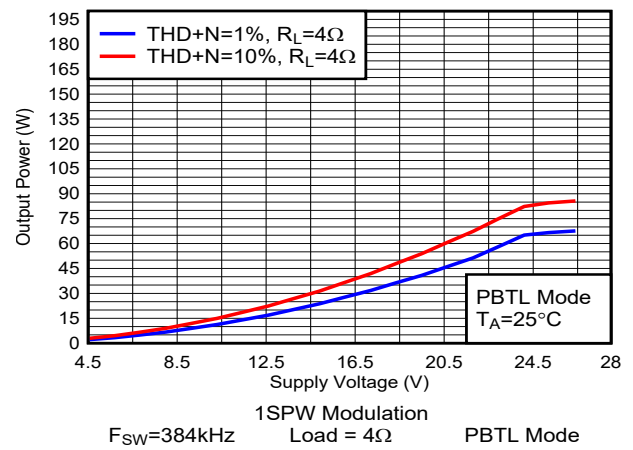
6-64. THD+N vs Output Power-PBTL



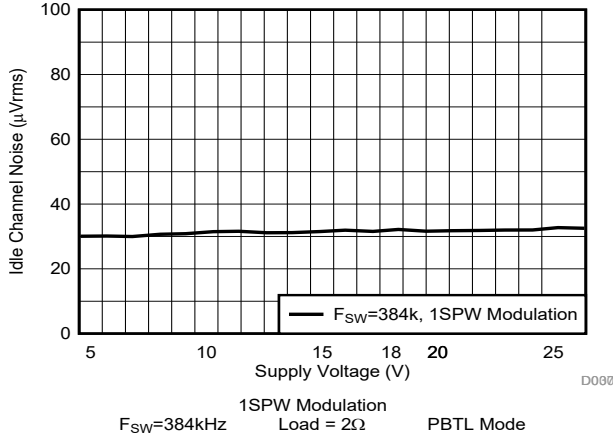
6-65. Output Power vs Supply Voltage



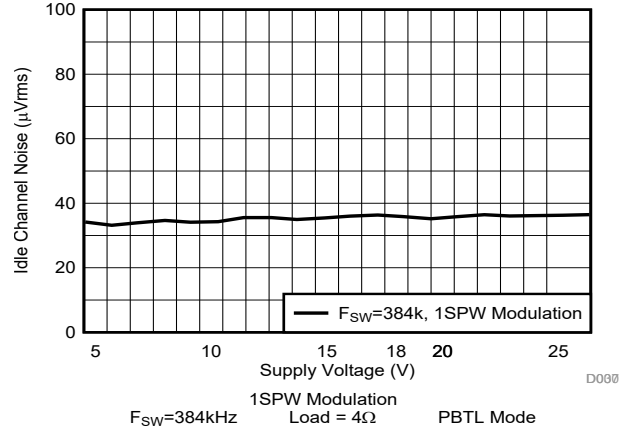
6-66. Output Power vs Supply Voltage



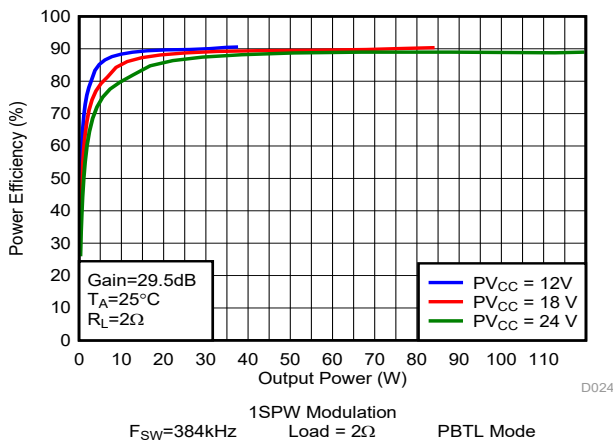
6-67. Output Power vs Supply Voltage



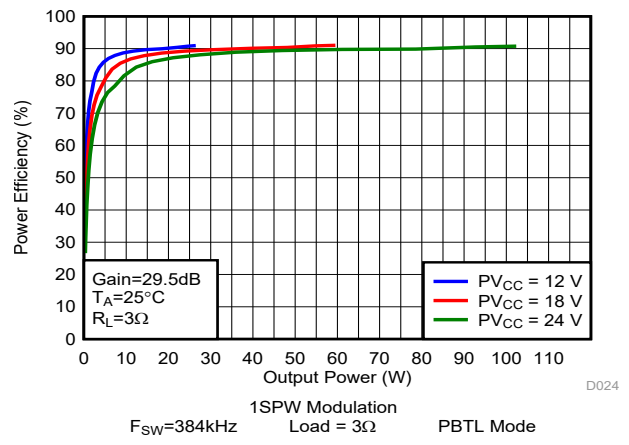
**6-68. Idle Channel Noise vs Supply Voltage**



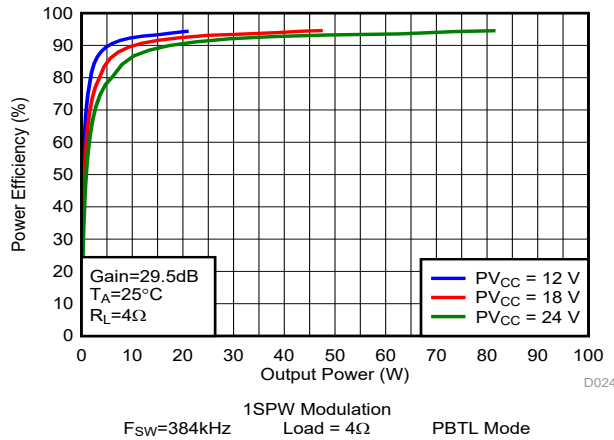
**6-69. Idle Channel Noise vs Supply Voltage**



**6-70. Efficiency vs Output Power**

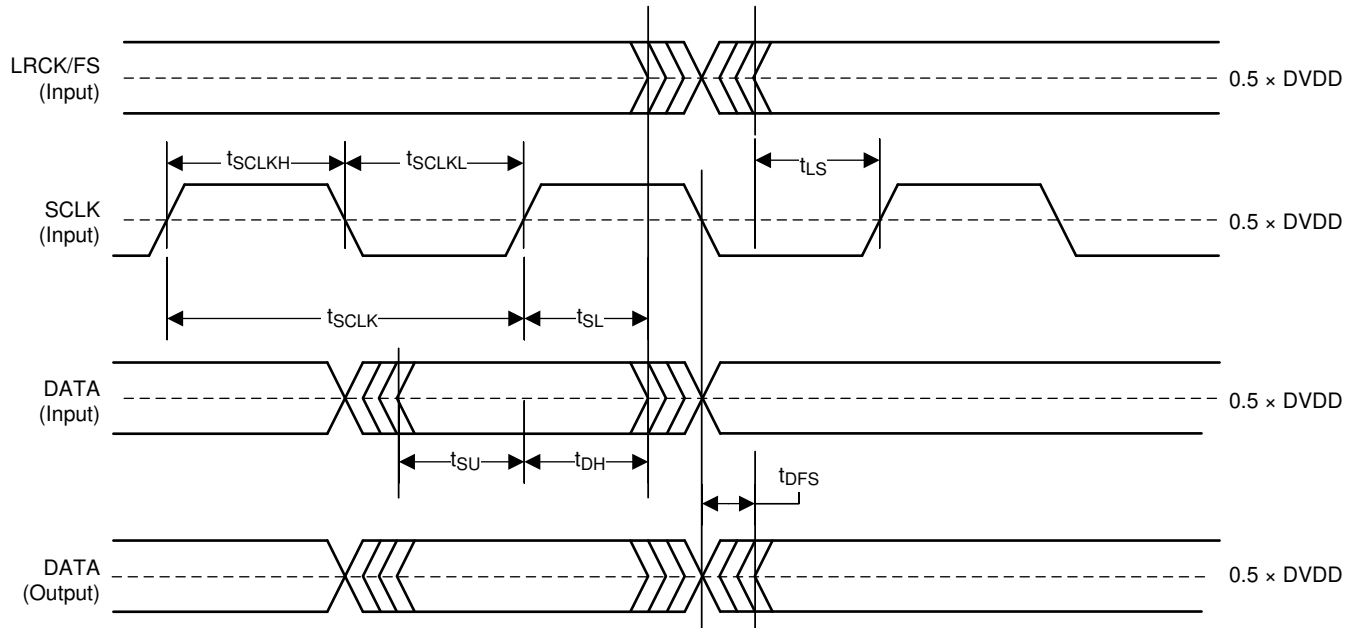


**6-71. Efficiency vs Output Power**

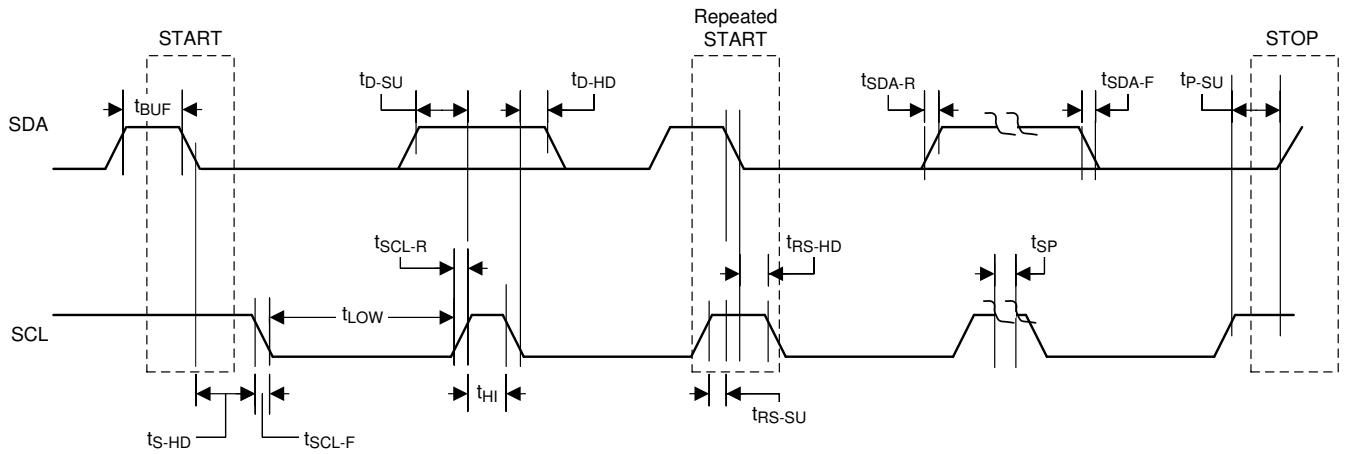


**6-72. Efficiency vs Output Power**

## 7 Parameter Measurement Information



7-1. Serial Audio Port Timing in Target Mode



7-2. I<sup>2</sup>C Communication Port Timing Diagram

## 8 Detailed Description

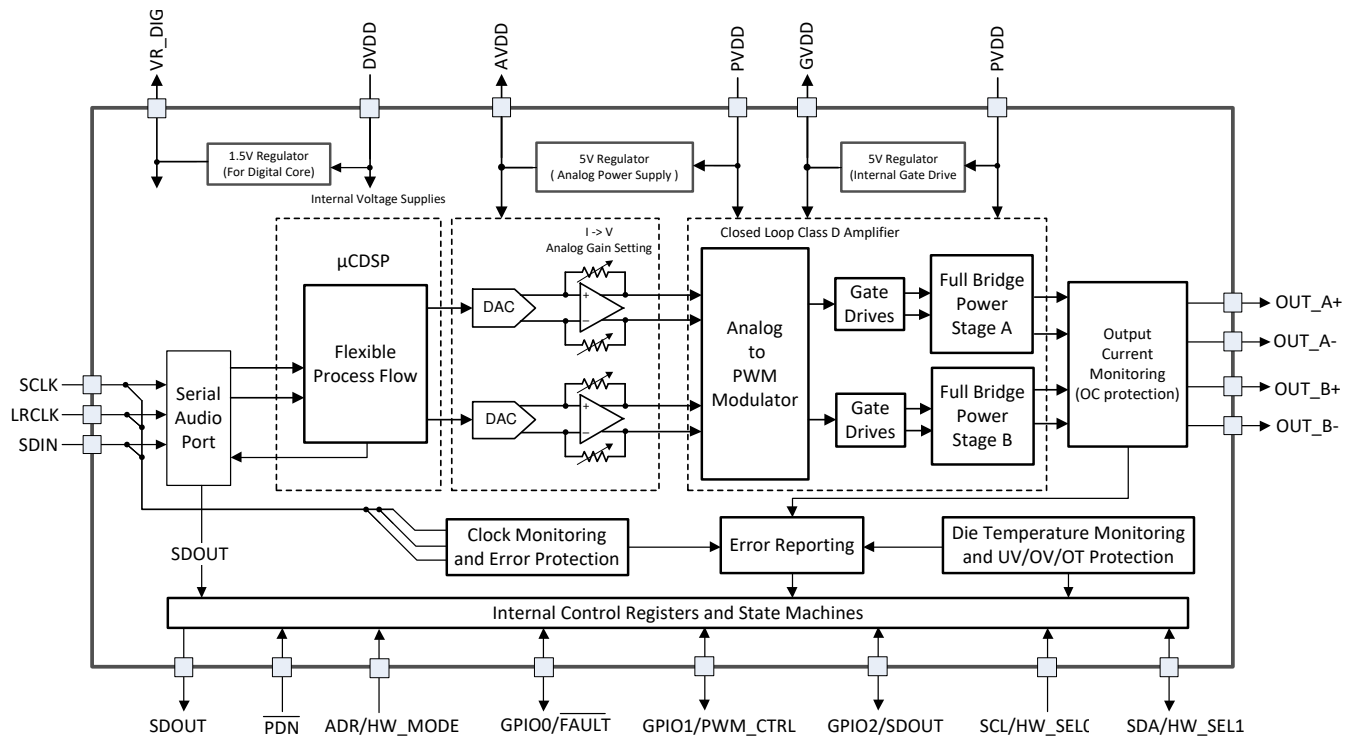
### 8.1 Overview

The TAS5828M device combines 4 main building blocks into a single cohesive device that maximizes sound quality, flexibility, and ease of use. The 4 main building blocks are listed as follows:

- A stereo digital to PWM modulator.
- An Audio DSP subsystem.
- A flexible close-loop amplifier capable of operating in stereo or mono, at several different switching frequencies, and with a variety of output voltages and loads.
- An I<sup>2</sup>C control port for communication with the device

The device requires only two power supplies for proper operation. A DVDD supply is required to power the low voltage digital circuitry. Another supply, called PVDD, is required to provide power to the output stage of the audio amplifier. Two internal LDOs convert PVDD to 5 V for GVDD and AVDD and to 1.5 V for DVDD respectively.

### 8.2 Functional Block Diagram



### 8.3 Feature Description

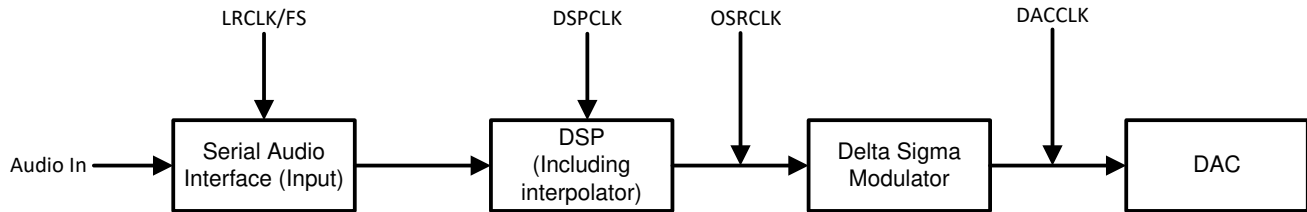
#### 8.3.1 Power Supplies

For system design, TAS5828M needs a 3.3-V or 1.8-V supply in addition to the (typical) 12 V or 24 V power-stage supply. Two internal voltage regulators provide suitable voltage levels for the gate drive circuitry and internal circuitry. The external pins are provided only as a connection point for off-chip bypass capacitors to filter the supply. Connecting external circuitry to these regulator outputs may result in reduced performance and damage to the device. Additionally, all circuitry requiring a floating voltage supply, that is, the high-side gate drive, is accommodated by built-in bootstrap circuitry requiring only a few external capacitors. To provide good electrical and acoustical characteristics, the PWM signal path for the output stage is designed as identical, independent half-bridges. For this reason, each half-bridge has separate bootstrap pins (BST\_x). The gate drive voltages (GVDD) are derived from the PVDD voltage. Special attention should be paid to placing all decoupling capacitors as close to their associated pins as possible. In general, inductance between the power-supply pins and decoupling capacitors must be avoided. For a properly functioning bootstrap circuit, a small ceramic

capacitor must be connected from each bootstrap pin (BST\_x) to the power-stage output pin (OUT\_x). When the power-stage output is low, the bootstrap capacitor is charged through an internal diode connected between the gate-drive regulator output pin (GVDD) and the bootstrap pin. When the power-stage output is high, the bootstrap capacitor potential is shifted above the output potential and thus provides a suitable voltage supply for the high-side gate driver.

### 8.3.2 Device Clocking

The TAS5828M devices have flexible systems for clocking. Internally, the device requires a number of clocks, mostly at related clock rates to function correctly. All of these clocks can be derived from the Serial Audio Interface.



**图 8-1. Audio Flow with Respective Clocks**

图 8-1 shows the basic data flow and clock Distribution.

The Serial Audio Interface typically has 3 connection pins which are listed as follows:

- SCLK (Bit Clock)
- LRCLK/FS (Left/Right Word Clock or Frame Sync)
- SDIN (Input Data)

The device has an internal PLL that is used to take SCLK and create the higher rate clocks required by the DSP and the DAC clock.

The TAS5828M device has an audio sampling rate detection circuit that automatically senses which frequency the sampling rate is operating. Common audio sampling frequencies of 32 kHz, 44.1kHz – 48 kHz, 88.2 kHz – 96 kHz, 176.4 kHz – 192 kHz are supported. The sampling frequency detector sets the clock for DAC and DSP automatically.

If the input LRCLK/SCLK stopped during music playing, the TAS5828M DSP switches to sleep state and waiting for the clock recovery (Class D output switches to Hiz automatically ), once LRCLK/SCLK recovered, TAS5828M auto recovers to the play mode. There is no need to reload the DSP code.

### 8.3.3 Serial Audio Port – Clock Rates

The serial audio interface port is a 3-wire serial port with the signals LRCLK/FS , SCLK , and SDIN. SCLK is the serial audio bit clock, used to clock the serial data present on SDIN into the serial shift register of the audio interface. Serial data is clocked into the TAS5828M device with SCLK. The LRCLK/FS pin is the serial audio left/ right word clock or frame sync when the device is operated in TDM Mode.

**表 8-1. Audio Data Formats, Bit Depths and Clock Rates**

FORMAT	DATA BITS	MAXIMUM LRCLK/FS FREQUENCY (kHz)	SCLK RATE (fs)
I <sup>2</sup> S/LJ/RJ	32, 24, 20, 16	32 to 192	64, 32
TDM	32, 24, 20, 16	32	128
		44.1,48	128,256,512
		96	128,256
		192	128

When Clock halt, non-supported SCLK to LRCLK(FS) ratio is detected, the device reports Clock Error in Register 113 (Register Address 0x71).

### 8.3.4 Clock Halt Auto-recovery

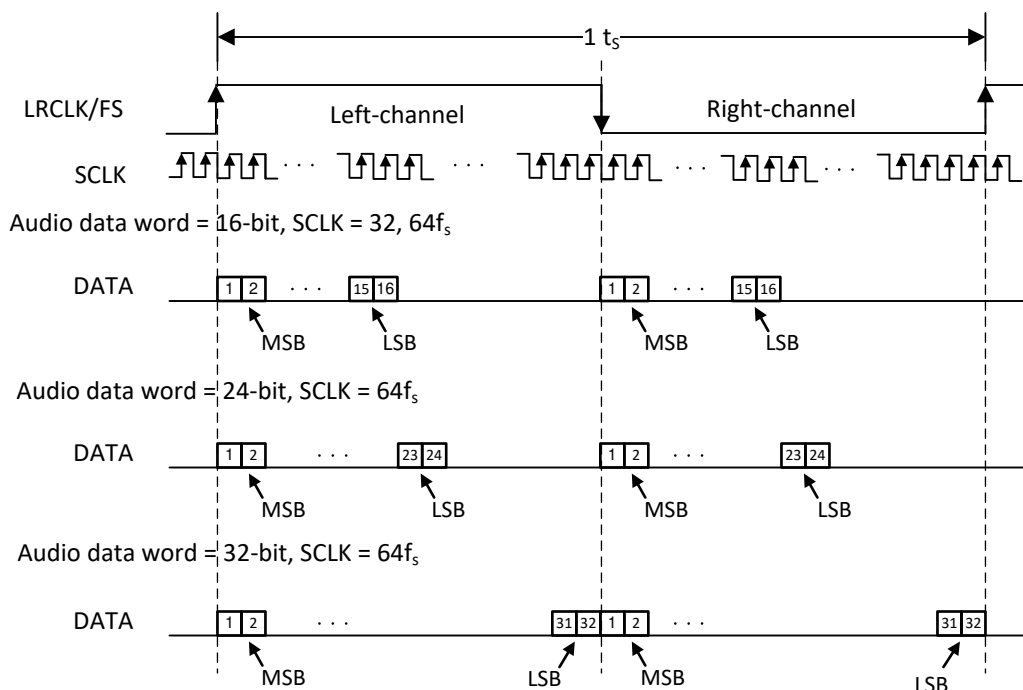
As some of host processor will Halt the I<sup>2</sup>S clock when there is no audio playing. When Clock halt, the device puts all channels into the Hi-Z state and reports Clock Error in Register 113 (Register Address 0x71). After audio clocks recovery, the device automatically returns to the previous state.

### 8.3.5 Sample Rate on the Fly Change

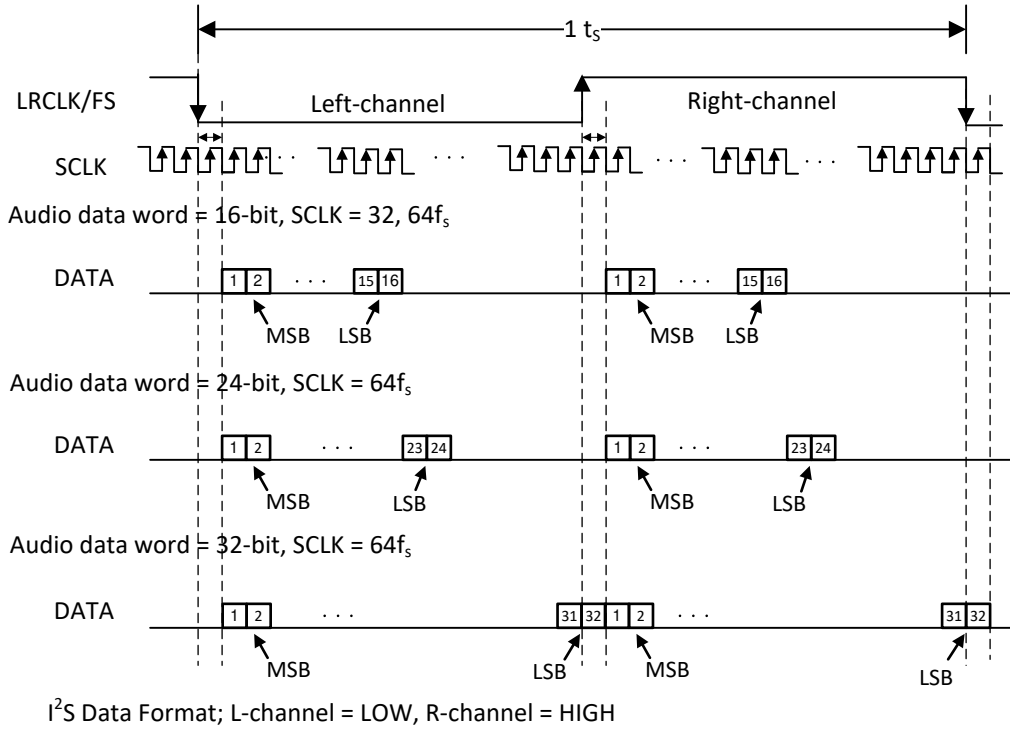
TAS5828M supports LRCLK(FS) rate on the fly change. For example, change LCRLK from 32kHz to 48kHz or 96kHz or 192kHz, Host processor needs to put the LRCLK(FS)/SCLK to Halt state at least 100us before changing to the new sample rate.

### 8.3.6 Serial Audio Port - Data Formats and Bit Depths

The device supports industry-standard audio data formats, including standard I<sup>2</sup>S, left-justified, right-justified and TDM/DSP data. Data formats are selected via Register (Register Address 0x33h -D[5:4]). If the high width of LRCLK/Fs in TDM/DSP mode is less than 8 cycles of SCK, the register (Register Address 0x33h -D[3:2]) should set to 01. All formats require binary two's complement, MSB-first audio data; up to 32-bit audio data is accepted. All the data formats, word length and clock rate supported by this device are shown in Table 1. The data formats are detailed in [Figure 8-2](#) through [Figure 8-6](#). The word length are selected via Register (Register Address 0x33h -D[1:0]). The offsets of data are selected via Register (Register Address 0x33h -D[7]) and Register (Register Address 0x34h -D[7:0]). Default setting is I<sup>2</sup>S and 24 bit word length.

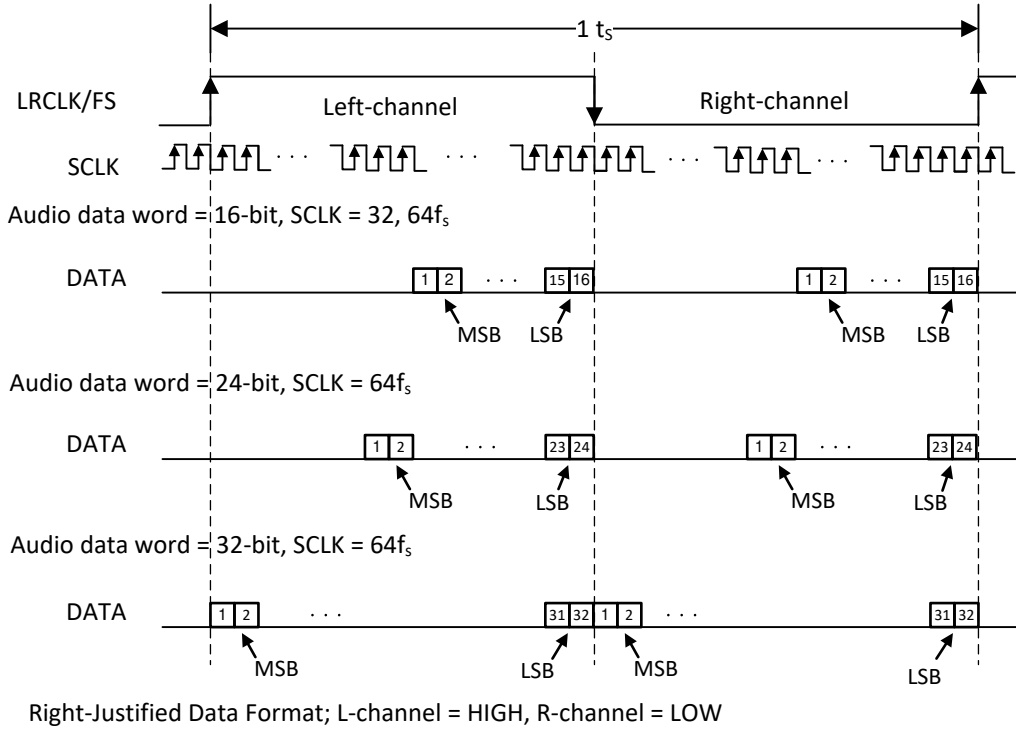


**Figure 8-2. Left Justified Audio Data Format**



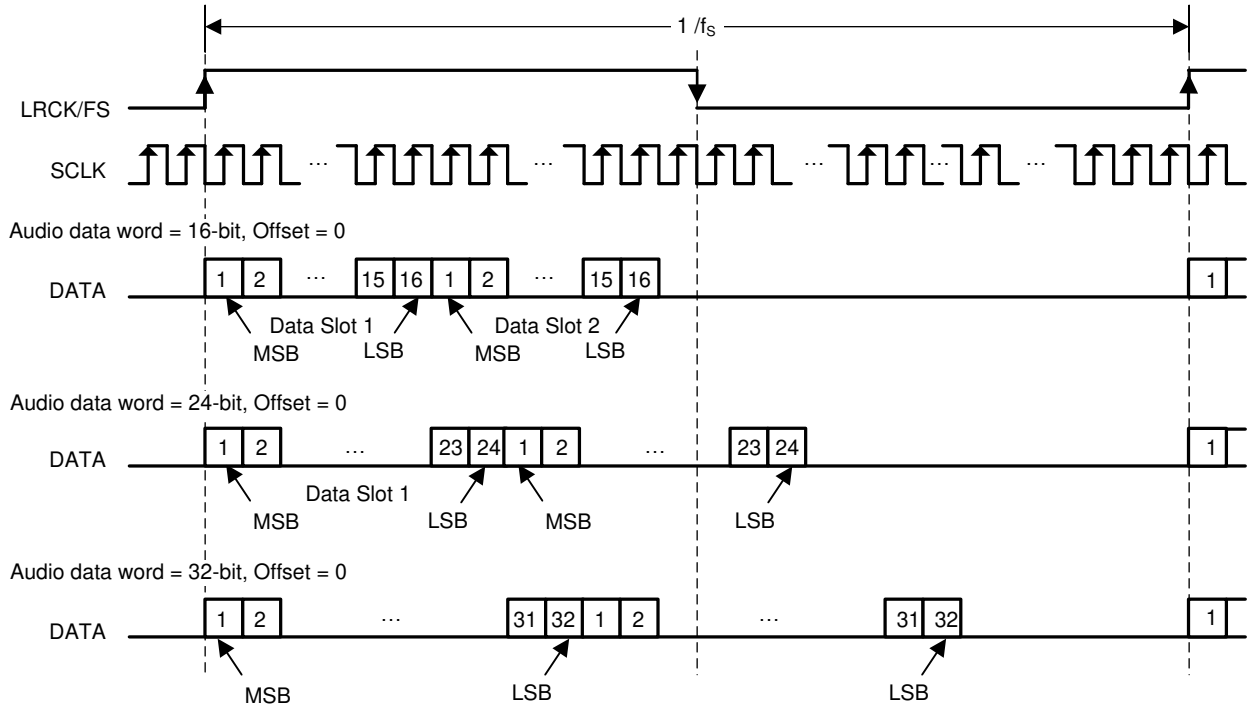
I<sup>2</sup>S Data Format; L-channel = LOW, R-channel = HIGH

**8-3. I<sup>2</sup>S Audio Data Format**



Right Justified Data Format; L-channel = HIGH, R-channel = LOW

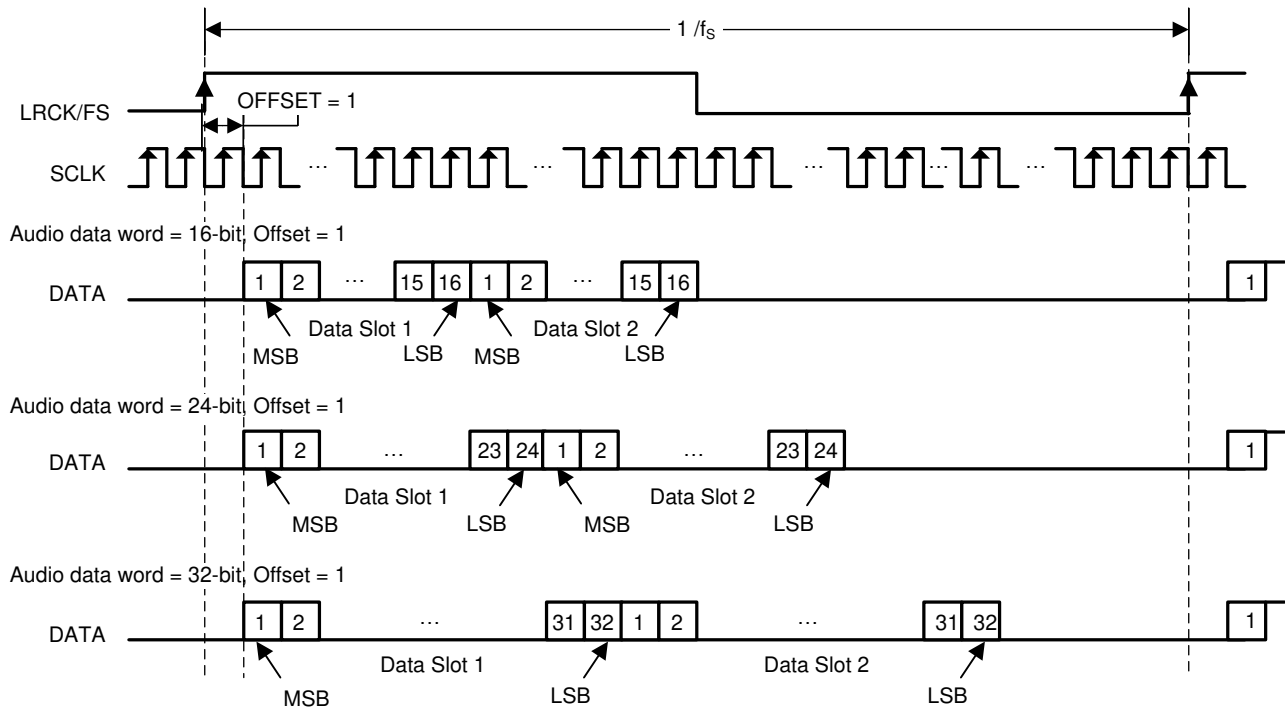
**8-4. Right Justified Audio Data Format**



TDM Data Format with OFFSET = 0

In TDM Modes, Duty Cycle of LRCK/FS should be 1x SCLK at minimum. Rising edge is considered frame start.

**8-5. TDM 1 Audio Data Format**



TDM Data Format with OFFSET = 1

In TDM Modes, Duty Cycle of LRCK/FS should be 1x SCLK at minimum. Rising edge is considered frame start.

**8-6. TDM 2 Audio Data Format**



### 8.3.7 Digital Audio Processing

TAS5828M digital audio processing includes three main functions: basic audio tuning blocks, Hybrid-Pro algorithm and advanced features.

Basic audio tuning blocks are SRC (sample rate converter), stereo channel Input Mixer, 15 BQs for each channel, pop click free Volume, multi-bands DRC, and AGL. Detailed introduction of each block can be found with [TAS5825M Process Flows](#).

Hybrid-Pro can be used in conjunction with [Hybrid Modulation](#), which is an innovative Class-D internal PWM modulation scheme to improve efficiency even more without compromising THD+N performance. Hybrid-Pro goes beyond Hybrid PWM modulation from system efficiency perspective, by tracking audio signal envelope with advanced look-ahead DSP structure, controlling the external PVDD supply voltage rail, and maintaining just enough margin to provide high dynamic range without clipping distortion to save as much power as possible. Refer [TAS5828M User Guide](#) for more configurable options:

- Optional 8 steps 384 kHz PWM format or 16 steps 192 kHz PWM format Hybrid-Pro control waveform for external DC-DC converter.
- Configurable max 4 ms look-ahead audio signal delay buffer, which provides capability to fit various applications systems' DC-DC bandwidth and power supply coupling capacitance.
- Max 512 samples audio signal peak hold to optimize power supply voltage rail transition from large audio input to small level, which is useful to avoid clipping distortion.
- Hybrid-Pro Margin automatically adjusts audio signal trigger level and each step level. Fine tune it to achieve the balance between efficiency and envelope tracking speed.

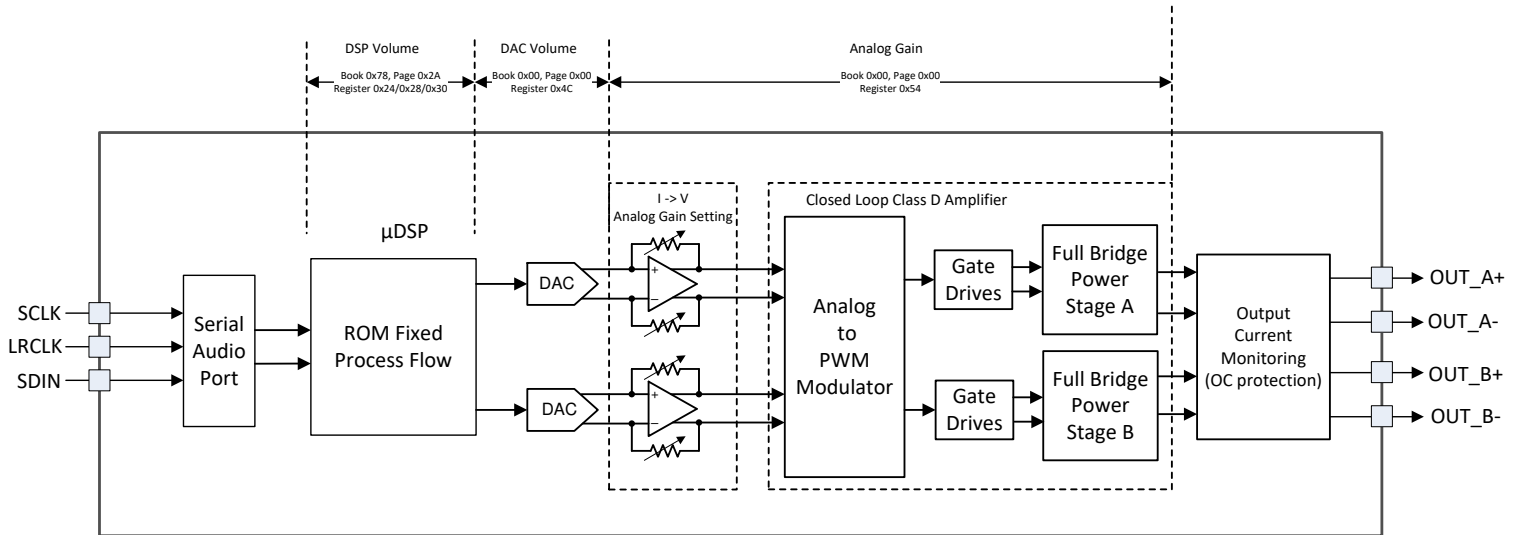
Advanced features include PVDD Sensing (Dynamic Headroom Tracking), Thermal Foldback and Hybrid PWM modulation. They are implemented based on integrated 8-bit PVDD sense ADC and 4 level temperature sensor. Refer to application note: [TAS5825M Advanced Features](#).

### 8.3.8 Class D Audio Amplifier

Following the digital clipper, the interpolated audio data is next sent to the Closed Loop Class-D amplifier, whose first stage is Digital to PWM Conversion (DPC) block. In this block, the stereo audio data is translated into two pairs of complimentary pulse width modulated (PWM) signals which are used to drive the outputs of the speaker amplifier. Feedback loops around the DPC ensure constant gain across supply voltages, reduce distortion, and increase immunity to power supply injected noise and distortion. The analog gain is also applied in the Class-D amplifier section of the device. The gain structures are discussed in detail below for both [图 8-7](#) and [表 8-2](#). The switching rate of the amplifier is configurable by register (Register Address 0x02h -D[6:4])

#### 8.3.8.1 Speaker Amplifier Gain Select

A combination of digital gain and analog gain is used to provide the overall gain of the speaker amplifier. As seen in [图 8-7](#), the audio path of the TAS5828M consists of a digital audio input port, a digital audio path, a digital to PWM converter (DPC), a gate driver stage, a Class D power stage, and a feedback loop which feeds the output information back into the DPC block to correct for distortion sensed on the output pins. The total amplifier gain is comprised of digital gain, shown in the digital audio path and the analog gain from the input of the analog modulator to the output of the speaker amplifier power stage.



**8-7. Speaker Amplifier Gain**

As shown in 8-7, the first gain stage for the speaker amplifier is present in the digital audio path. It consists of the volume control and the digital boost block. The volume control is set to 0 dB by default, it does not change. For all settings of the register 0x54, AGAIN[4:0], the digital boost block remains at 0 dB. These gain settings ensure that the output signal is not clipping at different PVDD levels. 0dBFS output is 29.5-V peak output voltage

**表 8-2. Analog Gain Setting**

AGAIN <4:0>	GAIN (dBFS)	AMPLIFIER OUTPUT PEAK VOLTAGE (V <sub>p</sub> /FS)	AMPLIFIER OUTPUT PEAK VOLTAGE (dBV <sub>p</sub> /FS)
00000	0	29.5	29.4
00001	-0.5	27.85	28.9
00010	-1.0	26.29	28.4
00011	-1.5	24.82	27.9
.....	.....	.....	.....
11111	-15.5	4.95	13.9

**8.3.8.2 Class D Loop Bandwidth and Switching Frequency Setting**

TAS5828M closed loop structure provides Loop bandwidth setting option (Setting by register 83 -Register address 0x53h-D[6-5]) to co-work with different switching frequency (Setting by register 2 -Register address 0x02h-D[6-4] ). 表 8-3 shows recommended settings for the Loop Bandwidth and Switching Frequency selection. Same Fsw, Better THD+N performance with higher BW.

**表 8-3. Loop Bandwidth and Switching Frequency Setting**

Modulation Scheme	Fsw	BW (Loop Band Width)	Notes
Hybrid, 1SPW	384kHz	80kHz	Principle: Fsw (Switching Frequency) ≥ 4.2 × Loop Bandwidth
	480kHz	80kHz, 100kHz	
	576kHz	80kHz, 100kHz, 120kHz	
	768kHz	80kHz, 100kHz, 120kHz, 175kHz	
BD	384kHz	80kHz, 100kHz, 120kHz	Principle: Fsw (Switching Frequency) ≥ 3 × Loop Bandwidth
	480kHz	80kHz, 100kHz, 120kHz	
	576kHz	80kHz, 100kHz, 120kHz, 175kHz	
	768kHz	80kHz, 100kHz, 120kHz, 175kHz	

## 8.4 Device Functional Modes

### 8.4.1 Software Control

The TAS5828M device is configured via an I<sup>2</sup>C communication port.

The I2C Communication Protocol is detailed in the [I<sup>2</sup>C Communication Port section](#). The I<sup>2</sup>C timing requirements are described in the [Timing Requirements - I<sup>2</sup>C Bus Timing](#).

### 8.4.2 Speaker Amplifier Operating Modes

The TAS5828M device can be configured as two different amplifier configurations through Register 0x02h -D[2]:

- BTL Mode
- PBTL Mode

#### 8.4.2.1 BTL Mode

In BTL mode, the TAS5828M amplifies two independent signals, which represent the left and right portions of a stereo signal. The amplified left signal is presented on differential output pair shown as OUT\_A+ and OUT\_A-, the amplified right signal is presented on differential output pair shown as OUT\_B+ and OUT\_B-.

#### 8.4.2.2 PBTL Mode

The PBTL mode of operation is used to describe operation in which the two outputs of the device are placed in parallel with one another to increase the power sourcing capabilities of the device. On the output side of the TAS5828M device, the summation of the devices can be done before the filter in a configuration called Pre-Filter Parallel Bridge Tied Load (PBTL). However, the two outputs can be required to merge together after the inductor portion of the output filter. Doing so does require two additional inductors, but allows smaller, less expensive inductors to be used because the current is divided between the two inductors. The process is called Post-Filter PBTL. On the input side of the TAS5828M device, the input signal to the PBTL amplifier is left frame of I2S or TDM data.

### 8.4.3 Low EMI Modes

TAS5828M employs several modes to minimize EMI during playing audio, and they can be used based on different applications.

#### 8.4.3.1 Spread Spectrum

Spread spectrum is used in some inductor free or inductor less case to minimize EMI noise. The TAS5828M supports Spread Spectrum with triangle mode.

User need configure register SS\_CTRL0 (0x6B) to Enable triangle mode and enable spread spectrum, select spread spectrum frequency and range with SS\_CTRL1 (0x6C). For 768kHz F<sub>SW</sub> which configured by DEVICE\_CTRL1 (0x02), the spread spectrum frequency and range are described in [表 8-4](#).

**表 8-4. Triangle Mode Spread Spectrum Frequency and Range Selection**

SS_TRI_CTRL[3:0]	0	1	2	3	4	5	6	7
Triangle Freq	24k				48k			
Spread Spectrum Range	5%	10%	20%	25%	5%	10%	20%	25%

User Application example: Central Switching Frequency is 768kHz, Triangle Frequency is 48kHz.

Register 0x02 = 0x41 // 768kHz Fsw, BTL Mode, 1SPW mode.

Register 0x6b = 0x03 // Enable Spread Spectrum

Register 0x6c = 0x03 // SS\_CTRL[3:0]=0011, Triangle Frequency = 48kHz, Spread Spectrum Range should be 10% (729kHz~807kHz)

### 8.4.3.2 Channel to Channel Phase Shift

This device supports channel to channel 180-degree PWM phase shift to minimize the EMI. Bit 0 of Register 0x53 can be used to disable or enable the phase shift.

### 8.4.3.3 Multi-Devices PWM Phase Synchronization

TAS5828M support up to 4 phases selection for the multi devices application system. For example, when a system integrated 4 TAS5828M devices, user can select phase0/1/2/3 for each device by register PHASE\_CTRL(0x6A), which means there is a 45 degree phase shift between each device to minimize the EMI.

There are two methods for Multi-Device PWM phase synchronization. Phase Synchronization With I<sup>2</sup>S Clock In Startup Phase or Phase Synchronization With GPIO.

#### 8.4.3.3.1 Phase Synchronization With I<sup>2</sup>S Clock In Startup Phase

1. Step 1, Halt I<sup>2</sup>S clock.
2. Step 2, Configure each device phase selection and enable the phase synchronization. For example: Register 0x6A=0x03 for device 0; Register 0x6A=0x07 for device 1; Register 0x6A=0x0B for device 2; Register 0x6A=0x0F for device 3.
3. Step 3, Configure each device into HIZ mode.
4. Step 4, Provide I<sup>2</sup>S to each device. Phase synchronization for all 4 devices is automatically done by internal sequence.
5. Step 5, Initialize the DSP code (This step can be skipped if only need to do the Phase Synchronization).
6. Step 6, Device to Device PWM phase shift should be fixed with 45 degree.

#### 8.4.3.3.2 Phase Synchronization With GPIO

1. Step 1, Connect GPIOx pin of each device to the SOC GPIO pin on PCB.
2. Step 2, Configure each device GPIOx as phase sync input usage by registers GPIO\_CTRL (0x60) and GPIO\_INPUT\_SEL (0x64).
3. Step 3, Select different phase for each device and enable phase synchronization by register PHASE\_CTRL (0x6A).
4. Step 4, Configure each device into PLAY mode by register DEVICE\_CTRL2 (0x03) and monitor the POWER\_STATE register (0x68) until device changed to HIZ state.
5. Step 5, Give a 0 to 1 toggle on SOC GPIO. Then all 4 devices nter into PLAY mode, and device-to-device PWM phase shift should be fixed with 45 degree.
6. Step 6, Phase Synchronization has been finished. Configure the GPIOx pin to other function based on the application.

#### 8.4.4 Thermal Foldback

The Thermal Foldback (TFB) is designed to protect TAS5828M from excessive die temperature increases, in case the device operates beyond the recommended temperature/power limit, or with a weaker thermal system design than recommended. It allows the TAS5828M to play as loud as possible without triggering unexpected thermal shutdown. When the die temperature triggers the over-temperature warning (OTW) level (TAS5828M has four different temperature threshold, each threshold is indicated in I<sup>2</sup>C register 0x73 bits 0,1,2 and 3 ), an internal AGL (Automatic Gain Limiter) reduces the digital gain gradually, lower value of OTW, smaller attenuation added, with the OTW warning goes higher, more attenuation added. Once the die temperature drops below the OTW, the device's digital gain gradually returns to the former setting. Both the attenuation gain and adjustable rate are programmable. The TFB gain regulation speed (attack rate and release rate) settings are the same as a regular AGL, which is also configurable with TAS5828M App in PurePath™ Console3.

#### 8.4.5 Device State Control

Except Shutdown Mode, TAS5828M has other 4 states for different power dissipation which listed in the *Electrical Characteristics Table*.

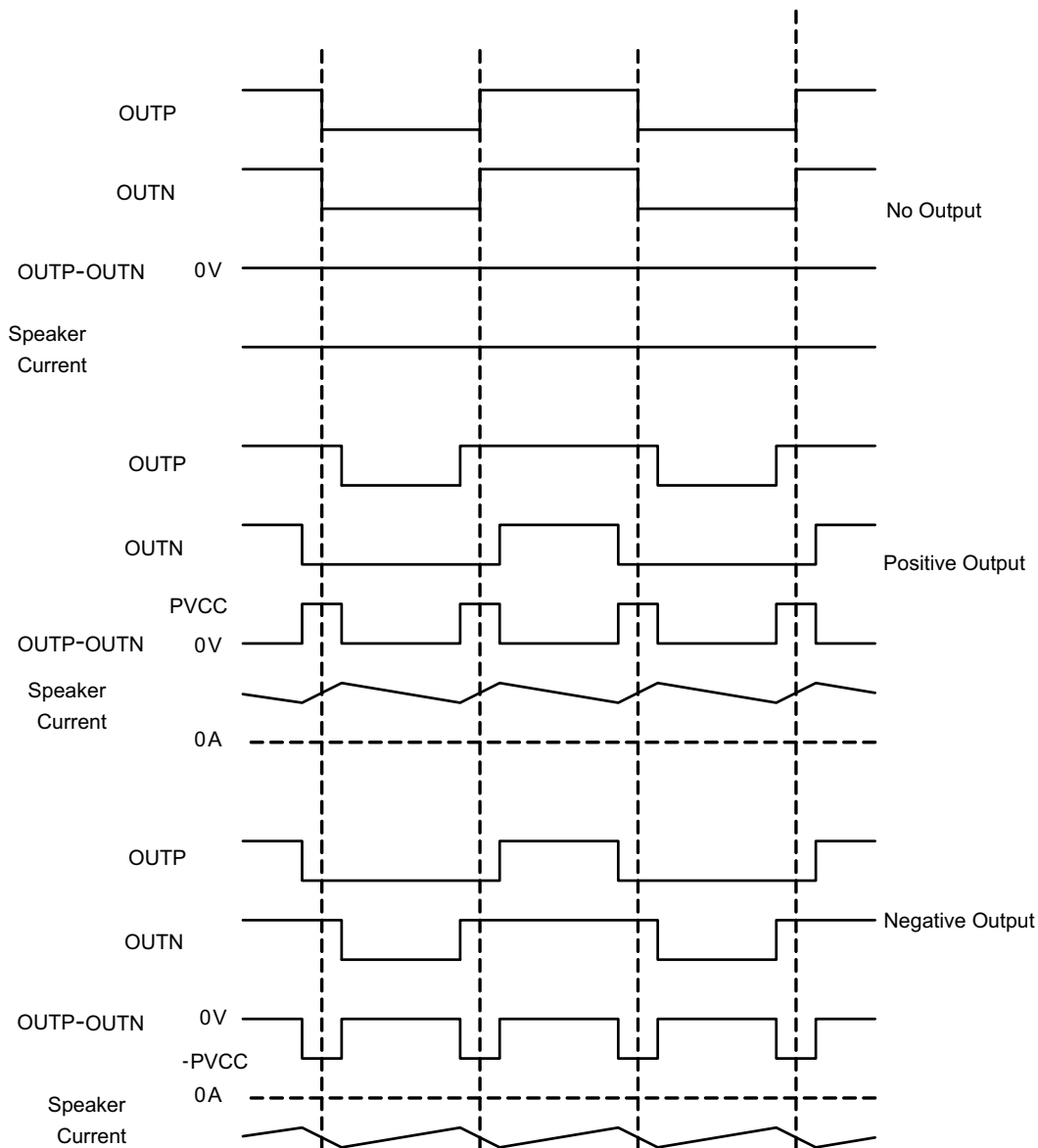
- Deep Sleep Mode. Register 0x03h -D[1:0]=00, Device stays in Deep Sleep Mode. In this mode, I<sup>2</sup>C block keep works. This mode can be used to extend the battery life time in some portable speaker application case, once the host processor stopped playing audio for a long time, TAS5828M can be set to Deep Sleep Mode to minimize power dissipation until host processor start playing audio again. Device returns back to Play Mode by setting Register 0x03h -D[1:0] to 11. Compare with Shutdown Mode (Pull  $\overline{\text{PDN}}$  Low), enter or exit Deep Sleep Mode, DSP keeps active.
- Sleep Mode. Register 0x03h -D[1:0]=01, Device stays in Sleep Mode. In this mode, I<sup>2</sup>C block, Digital core, DSP Memory , 5 V Analog LDO keep works. Compare with Shutdown Mode (Pull  $\overline{\text{PDN}}$  Low), enter or exit Sleep Mode, DSP keeps active.
- Output Hiz Mode. Register 0x03h -D[1:0]=10, Device stays in Hiz Mode. In this mode, Only output driver set to be Hiz state, all other block work normally.
- Play Mode. Register 0x03h -D[1:0]=11, Device stays in Play Mode.

### 8.4.6 Device Modulation

TAS5828M has 3 modulation schemes: BD modulation, 1SPW modulation and Hybrid modulation. Select modulation schemes for TAS5828M with Register 0x02 [1:0]-DAMP\_MOD.

#### 8.4.6.1 BD Modulation

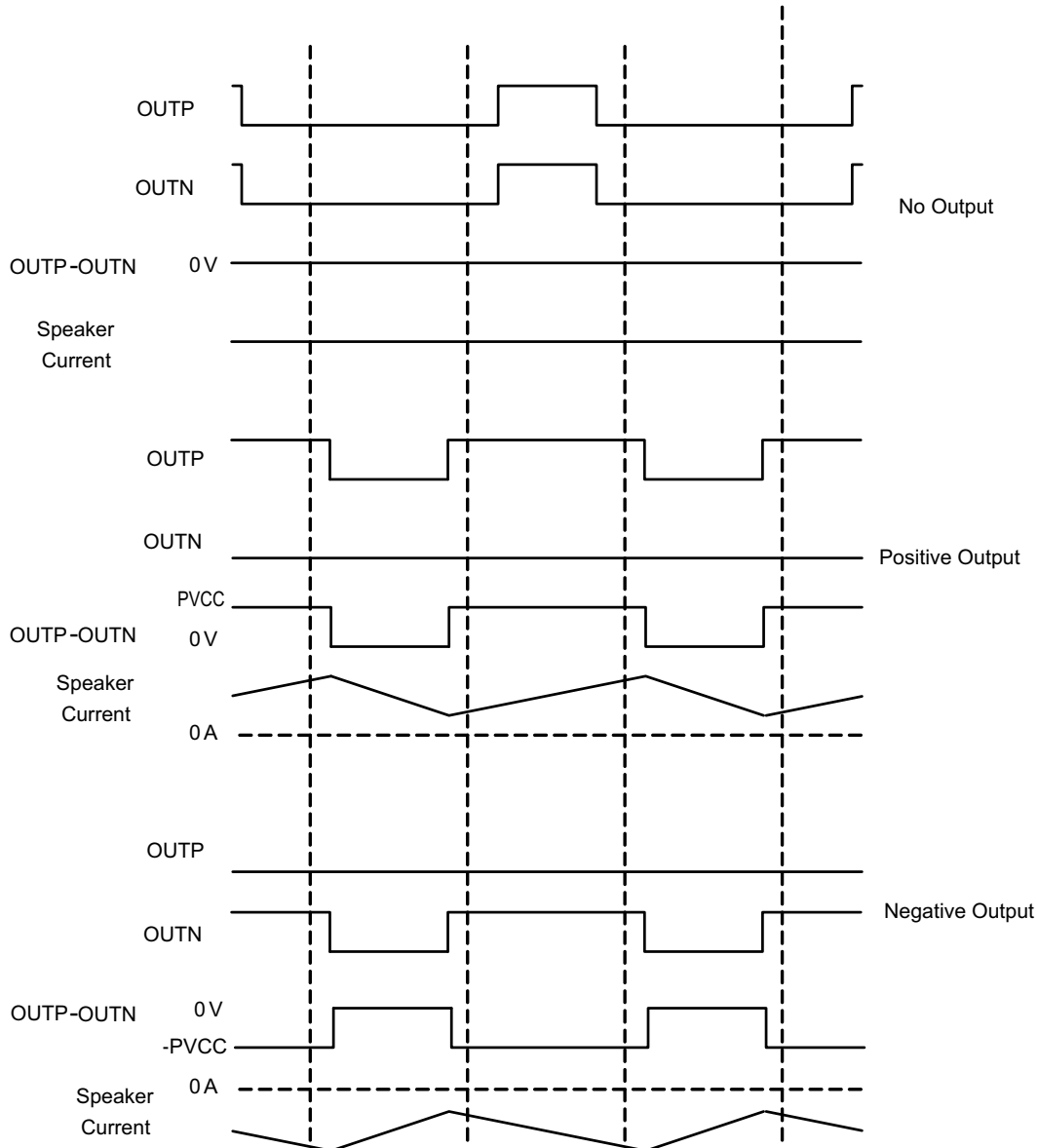
This is a modulation scheme that allows operation without the classic LC reconstruction filter when the amp is driving an inductive load with short speaker wires. Each output is switching from 0 volts to the supply voltage. The OUTPx and OUTNx are in phase with each other with no input so that there is little or no current in the speaker. The duty cycle of OUTPx is greater than 50% and OUTNx is less than 50% for positive output voltages. The duty cycle of OUTPx is less than 50% and OUTNx is greater than 50% for negative output voltages. The voltage across the load sits at 0 V throughout most of the switching period, reducing the switching current, which reduces any  $I^2R$  losses in the load.



**8-8. BD Mode Modulation**

### 8.4.6.2 1SPW Modulation

The 1SPW mode alters the normal modulation scheme in order to achieve higher efficiency with a slight penalty in THD degradation and more attention required in the output filter selection. In Low Idle Current mode the outputs operate at ~17% modulation during idle conditions. When an audio signal is applied, one output decreases and one increases. The decreasing output signal rails to GND. At this point all the audio modulation takes place through the rising output. The result is that only one output is switching during a majority of the audio cycle. Efficiency is improved in this mode due to the reduction of switching losses.



 **8-9. 1SPW Mode Modulation**

### 8.4.6.3 Hybrid Modulation

Hybrid Modulation is designed for minimized power loss without compromising the THD+N performance, and is optimized for battery-powered applications. With Hybrid modulation, TAS5828M detects the input signal level and adjust PWM duty cycle dynamically based on PVDD. Hybrid modulation achieves ultra low idle current and maintains the same audio performance level as the BD Modulation.

### Note

As Hybrid Modulation need the internal DSP to detect the input signal level and adjust PWM duty cycle dynamically. To use the Hybrid Modulation, users need to select the corresponding process flows which support Hybrid Modulation in TAS5828M PPC3 App. Look into TAS5828M PPC3 App for more information about TAS5828M flexible audio process flows.

## 8.5 Programming and Control

### 8.5.1 I<sup>2</sup>C Serial Communication Bus

The device has a bidirectional serial control interface that is compatible with I<sup>2</sup>C bus protocol and supports 100 and 400-kHz data transfer rates for random and sequential write and read operations as a target device. Because the TAS5828M register map and DSP memory spans multi pages, the user should change from page to page before writing individual register or DSP memory. Changing from page to page is accomplished via register 0 on each page. This register value selects the page address, from 0 to 255. All registers listed in TAS5828M Datasheet belongs to Page 0

### 8.5.2 Hardware Control Mode

For the system which does not require the advanced flexibility of the I<sup>2</sup>C registers control or does not have an available I<sup>2</sup>C host controller, the TAS5828M can be used in Hardware Control Mode. Then the device operates in Hardware mode default configurations and any change is accomplished via the Hardware control pins. The audio performance between Hardware and Software Control mode with same configuration is identical, however more features are accessible under Software Control Mode through registers.

Several I/O's on the TAS5828M need to be taken into consideration during schematic design for desired startup settings. The method going into Hardware Control Mode is to pull high HW\_MODE pin13 to DVDD.

The TAS5828M default Hardware configuration with optimized audio, thermal and BOM is BTL mode, 768-kHz switching frequency, 1 SPW mode, 175 kHz Class D amplifier loop bandwidth, 29.5 V<sub>p</sub>/FS analog gain, CBC threshold with 80% of OCP threshold. It requires the HW\_SEL0 pin 5 and HW\_SEL1 pin 6 directly tied low GND.

**表 8-5. Hardware Control - HW\_SEL0 Pin5**

Pin Configuration	Analog Gain	H-Bridge Output Configuration
0 Ω to GND	29.5 V <sub>p</sub> /FS	BTL
1 kΩ to GND	20.9 V <sub>p</sub> /FS	BTL
4.7 kΩ to GND	14.7 V <sub>p</sub> /FS	BTL
15 kΩ to GND	7.4 V <sub>p</sub> /FS	BTL
33 kΩ to DVDD	7.4 V <sub>p</sub> /FS	PBTL
6.8 kΩ to DVDD	14.7 V <sub>p</sub> /FS	PBTL
1.5 kΩ to DVDD	20.9 V <sub>p</sub> /FS	PBTL
0 Ω to DVDD	29.5 V <sub>p</sub> /FS	PBTL

**表 8-6. Hardware Control - HW\_SEL1 Pin6**

Pin Configuration	F <sub>SW</sub> &Class D Loop Bandwidth	Cycle By Cycle Current Limit Threshold	Spread Spectrum	Modulation
0 Ω to GND	768 kHz F <sub>SW</sub> , 175 kHz BW	CBC Threshold = 80% OCP	Disable	1SPW
1 kΩ to GND	768 kHz F <sub>SW</sub> , 175 kHz BW	CBC Disable	Disable	1SPW
4.7 kΩ to GND	768 kHz F <sub>SW</sub> , 175 kHz BW	CBC Threshold = 40% OCP	Disable	1SPW
15 kΩ to GND	768 kHz F <sub>SW</sub> , 175 kHz BW	CBC Threshold = 60% OCP	Disable	1SPW
33 kΩ to DVDD	480 kHz F <sub>SW</sub> , 100 kHz BW	CBC Disable	Enable	BD
6.8 kΩ to DVDD	480 kHz F <sub>SW</sub> , 100 kHz BW	CBC Threshold = 80% OCP	Enable	BD



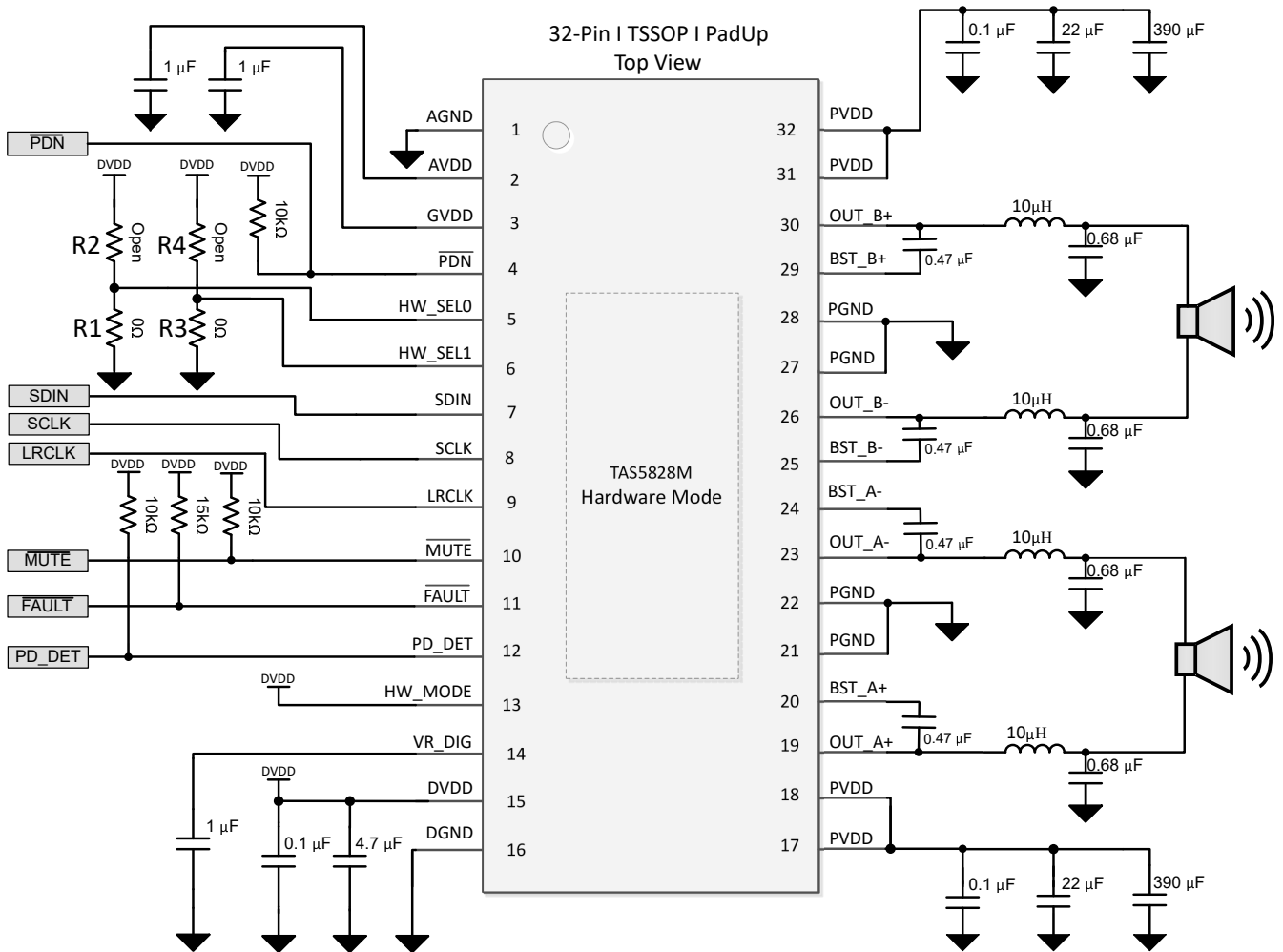
表 8-6. Hardware Control - HW\_SEL1 Pin6 (continued)

Pin Configuration	F <sub>sw</sub> &Class D Loop Bandwidth	Cycle By Cycle Current Limit Threshold	Spread Spectrum	Modulation
1.5 kΩ to DVDD	480 kHz F <sub>sw</sub> , 100 kHz BW	CBC Threshold = 40% OCP	Enable	BD
0 Ω to DVDD	480 kHz F <sub>sw</sub> , 100 kHz BW	CBC Threshold = 60% OCP	Enable	BD

**Example 1:**

BTL Mode, FSW = 768 kHz, 1 SPW Modulation, 175 kHz Loop Bandwidth, CBC Threshold = 80% OCP, Analog Gain = 29.5 Vp/FS, Spread spectrum disable.

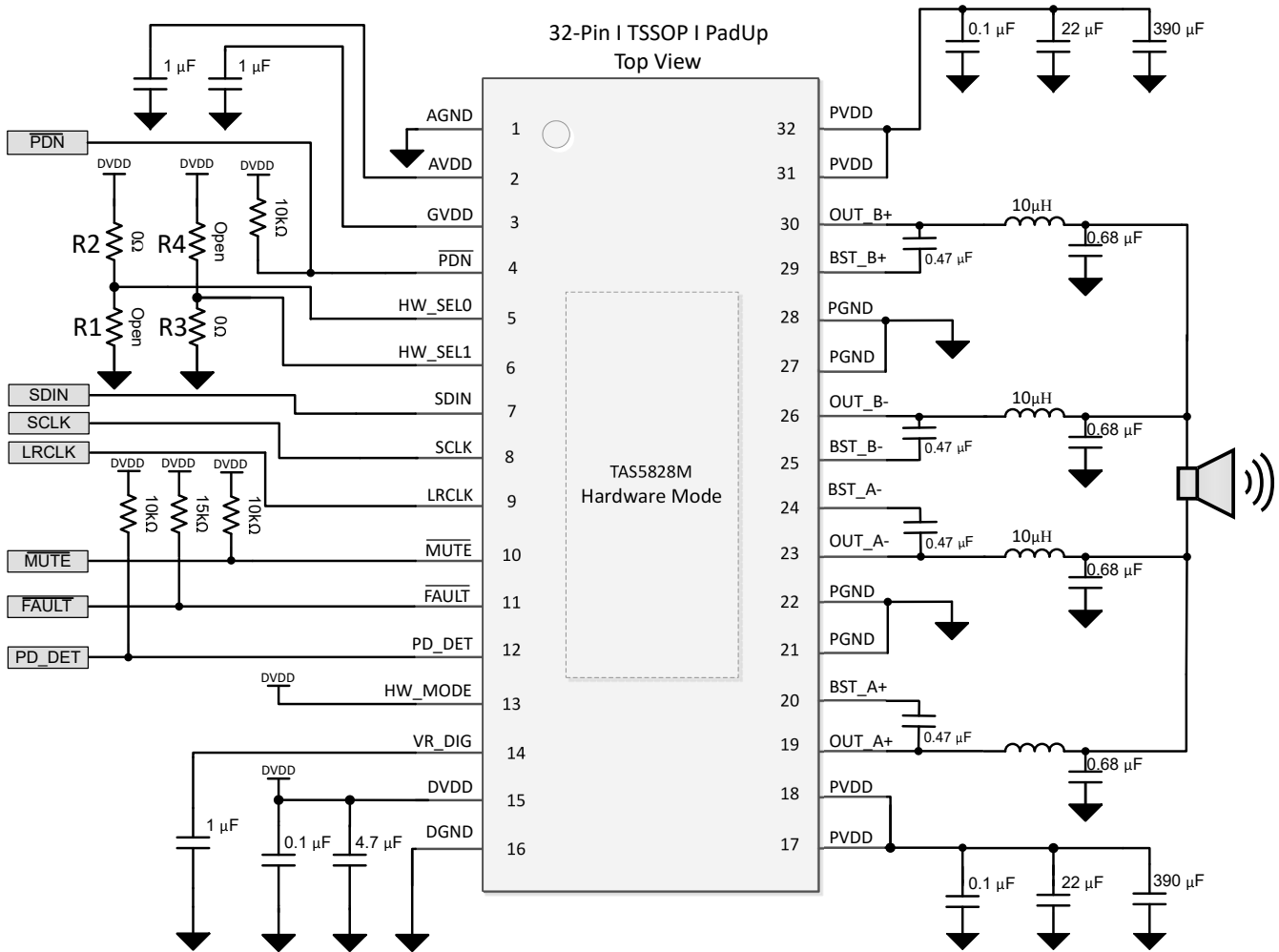
图 8-10. Typical Hardware Control Mode Application Schematic-BTL Mode



**Example 2:**

PBTL Mode, FSW = 768 kHz, 1 SPW Modulation, 175 kHz Loop Bandwidth, CBC Threshold = 80% OCP, Analog Gain = 29.5 V<sub>p</sub>/FS, Spread spectrum disable.

**8-11. Typical Hardware Control Mode Application Schematic-PBTL Mode**



**8.5.3 I<sup>2</sup>C Target Address**

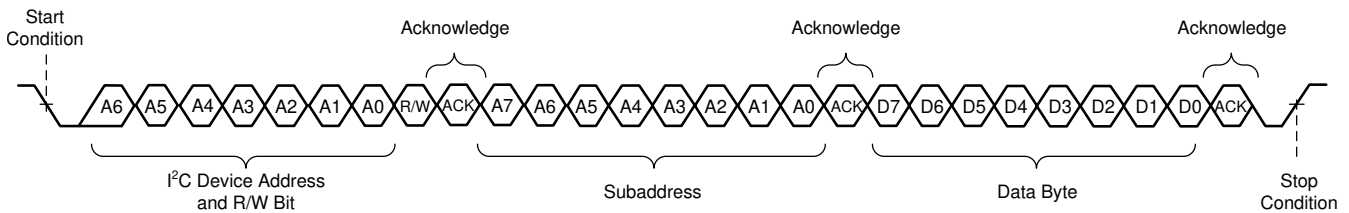
The TAS5828M device has 7 bits for the target address. The user-defined address through ADR pin is listed in [表 8-7](#).

**表 8-7. I<sup>2</sup>C Target Address Configuration**

ADR PIN Configuration	MSBs				User Define			LSB
0 Ω to GND	1	1	0	0	0	0	0	R/ $\bar{W}$
1kΩ to GND	1	1	0	0	0	0	1	R/ $\bar{W}$
4.7kΩ to GND	1	1	0	0	0	1	0	R/ $\bar{W}$
15kΩ to GND	1	1	0	0	0	1	1	R/ $\bar{W}$
33kΩ to DVDD	1	1	0	0	1	0	0	R/ $\bar{W}$
6.8kΩ to DVDD	1	1	0	0	1	0	1	R/ $\bar{W}$

### 8.5.3.1 Random Write

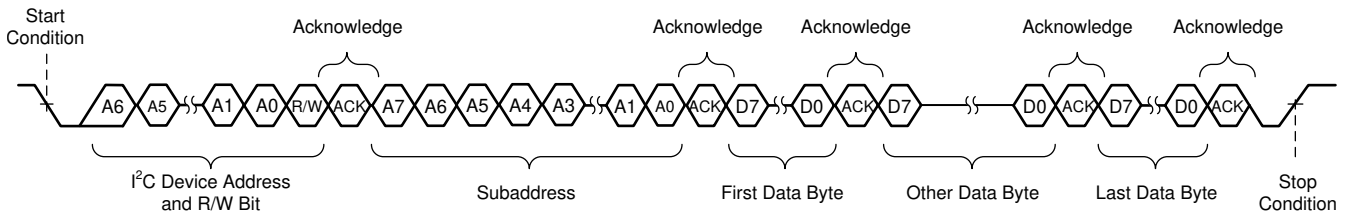
As shown in [Figure 8-12](#), a single-byte data-write transfer begins with the controller device transmitting a start condition followed by the I<sup>2</sup>C device address and the read/write bit. The read/write bit determines the direction of the data transfer. For a write data transfer, the read/write bit is a 0. After receiving the correct I<sup>2</sup>C device address and the read/write bit, the device responds with an acknowledge bit. Next, the controller transmits the address byte corresponding to the internal memory address being accessed. After receiving the address byte, the device again responds with an acknowledge bit. Next, the controller device transmits the data byte to be written to the memory address being accessed. After receiving the data byte, the device again responds with an acknowledge bit. Finally, the controller device transmits a stop condition to complete the single-byte data-write transfer.



**Figure 8-12. Random Write Transfer**

### 8.5.3.2 Sequential Write

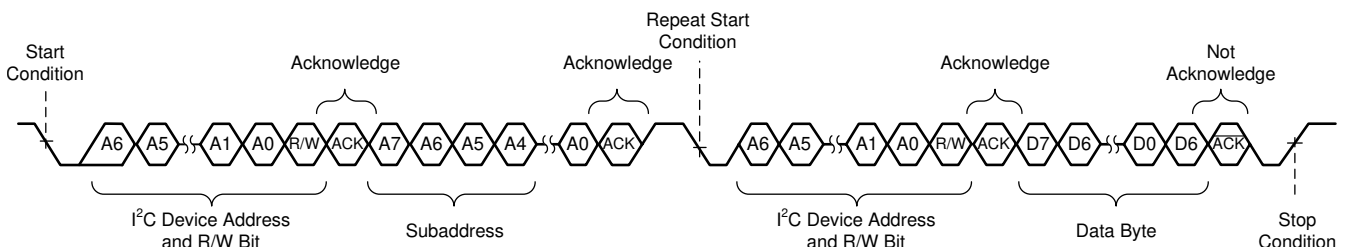
A sequential data-write transfer is identical to a single-byte data-write transfer except that multiple data bytes are transmitted by the controller to the device as shown in [Figure 8-13](#). After receiving each data byte, the device responds with an acknowledge bit and the I<sup>2</sup> subaddress is automatically incremented by one.



**Figure 8-13. Sequential Write Transfer**

### 8.5.3.3 Random Read

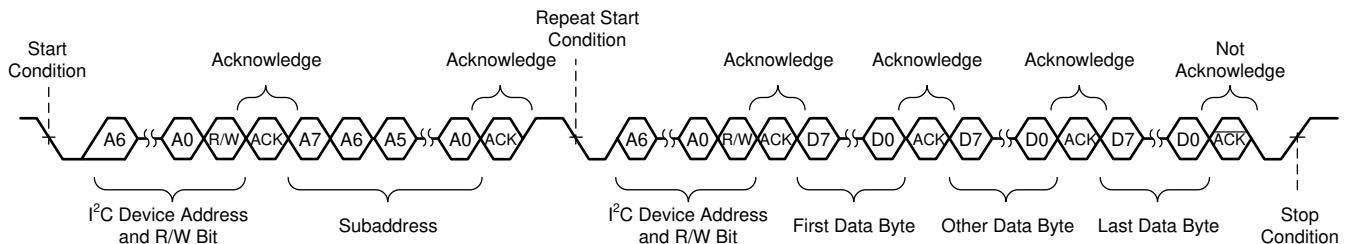
As shown in [Figure 8-14](#), a single-byte data-read transfer begins with the controller device transmitting a start condition followed by the I<sup>2</sup>C device address and the read/write bit. For the data-read transfer, both a write followed by a read are actually done. Initially, a write is done to transfer the address byte of the internal memory address to be read. As a result, the read/write bit is a 0. After receiving the address and the read/write bit, the device responds with an acknowledge bit. In addition, after sending the internal memory address byte, the controller device transmits another start condition followed by the address and the read/write bit again. This time the read/write bit is a 1, indicating a read transfer. After receiving the address and the read/write bit, the device again responds with an acknowledge bit. Next, the device transmits the data byte from the memory address being read. After receiving the data byte, the controller device transmits a not-acknowledge followed by a stop condition to complete the single-byte data-read transfer.



**Figure 8-14. Random Read Transfer**

### 8.5.3.4 Sequential Read

A sequential data-read transfer is identical to a single-byte data-read transfer except that multiple data bytes are transmitted by the device to the controller device as shown in [Figure 8-15](#). Except for the last data byte, the controller device responds with an acknowledge bit after receiving each data byte and automatically increments the I<sup>2</sup>C sub address by one. After receiving the last data byte, the controller device transmits a not-acknowledge followed by a stop condition to complete the transfer.



**Figure 8-15. Sequential Read Transfer**

### 8.5.3.5 DSP Memory Book, Page and BQ update

On Page 0x00 of each book, Register 0x7f is used to change the book. Register 0x00 of each page is used to change the page. To change a Page first write 0x00 to Register 0x00 to switch to Page 0 then write the book number to Register 0x7f on Page 0. To switch between pages in a book, simply write the page number to register 0x00.

All the Biquad Filters coefficients are addressed in book 0xAA. The five coefficients of every Biquad Filter should be written entirely and sequentially from the lowest address to the highest address. The address of all Biquad Filters can be found in Register Maps

All DSP/Audio Process Flow Related Register are listed in Application Note, [TAS5825M Process Flows](#)

### 8.5.3.6 Checksum

This device supports two different check sum schemes, a cyclic redundancy check (CRC) checksum and an Exclusive (XOR) checksum. Register reads do not change checksum, but writes to even nonexistent registers changes the checksum. Both checksums are 8-bit checksums and both are available together simultaneously. The checksums can be reset by writing a starting value (eg. 0x 00 00 00 00) to their respective 4-byte register locations.

#### 8.5.3.6.1 Cyclic Redundancy Check (CRC) Checksum

The 8-bit CRC checksum used is the 0x7 polynomial (CRC-8-CCITT 1.432.1; ATM HEC, ISDN HEC and cell delineation,  $(1 + x^1 + x^2 + x^8)$ ). A major advantage of the CRC checksum is that it is input order sensitive. The CRC supports all I<sup>2</sup>C transactions, excluding book and page switching. The CRC checksum is read from register 0x7E on page0 of any book (B\_x, Page\_0, Reg\_126). The CRC checksum can be reset by writing 0x00 to the same register locations where the CRC checksum is valid.

#### 8.5.3.6.2 Exclusive or (XOR) Checksum

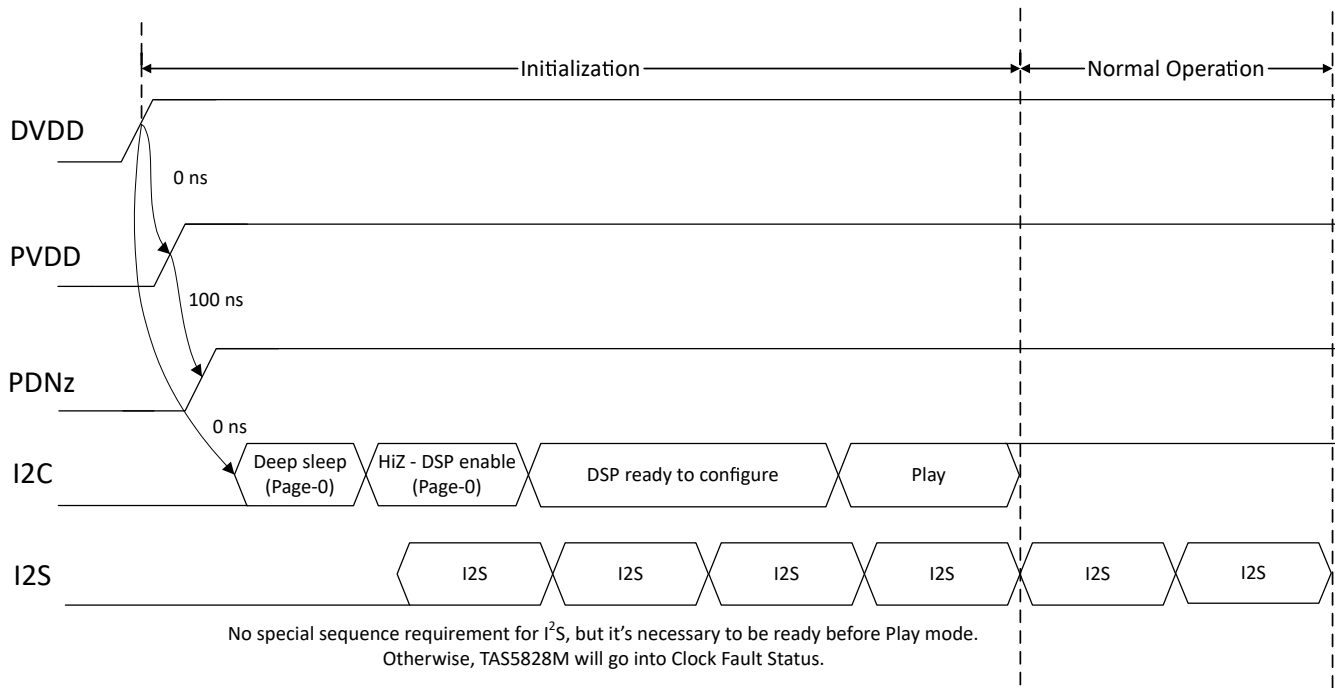
The Xor checksum is a simpler checksum scheme. It performs sequential XOR of each register byte write with the previous 8-bit checksum register value. XOR supports only Book 0x8C, and excludes page switching and all registers in Page 0x00 of Book 0x8C. XOR checksum is read from location register 0x7D on page 0x00 of book 0x8C (B\_140, Page\_0, Reg\_125). The XOR Checksum can be reset by writing 0x00 to the same register location where it is read.

### 8.5.4 Control via Software

- Startup Procedures
- Shutdown Procedures

#### 8.5.4.1 Startup Procedures

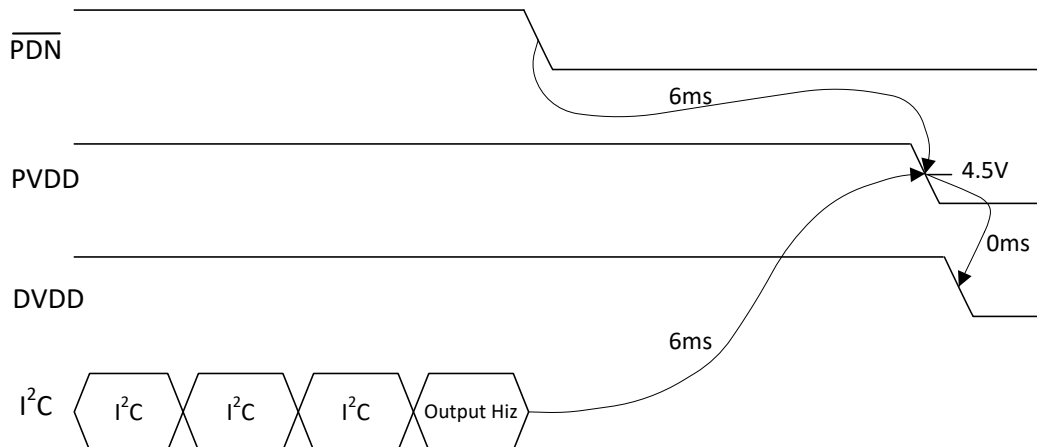
1. Configure ADR pin with proper setting for I<sup>2</sup>C device address or Hardware Mode with proper HW\_SEL0 and HW\_SEL1 settings.
2. Bring up power supplies (it does not matter if PVDD or DVDD comes up first).
3. Once power supplies are stable, wait at least 100 μs, bring up  $\overline{\text{PDN}}$  to High to enable internal LDO.
4. I<sup>2</sup>C control port to configure desired settings. This process includes Deep Sleep to HiZ, register map configurations, DSP coefficients, and set into Play mode. Hardware Mode does not need this step I<sup>2</sup>C writing.
5. Once I<sup>2</sup>S clocks are stable, TAS5828M is going to normal operation music playing.



**8-16. TAS5828M Startup Sequence**

### 8.5.4.2 Shutdown Procedures

1. The device is in normal operation.
2. Configure the Register 0x03h -D[1:0]=10 (Hiz) via the I<sup>2</sup>C control port or Pull  $\overline{\text{PDN}}$  low.
3. Wait at least 6ms (this time depends on the LRCLK rate ,digital volume and digital volume ramp down rate).
4. Bring down power supplies.
5. The device is now fully shutdown and powered off.



- Before PVDD/DVDD power down, Class D Output driver needs to be disabled by  $\overline{\text{PDN}}$  or by I<sup>2</sup>C.
- At least 6ms delay needed based on LRCLK (Fs) = 48kHz, Digital volume ramp down update every sample period, decreased by 0.5dB for each update, digital volume = 24dB. Change the value of register 0x4C and 0x4E or change the LRCLK rate, the delay changes.

### 8-17. Power-Down Sequence

## 8.5.5 Protection and Monitoring

### 8.5.5.1 Overcurrent Limit (Cycle-By-Cycle)

In stead of direct Overcurrent Shutdown to mute audio output, TAS5828M also provides CBC current limiting protection. The purpose is to reduce output current ahead of Overcurrent Shutdown level by insert pulse into PWM switching, and the threshold (list in [Electrical Characteristics - OCE<sub>THRES</sub>](#)) is configurable through Register 0x77h -D[4:3] Reg\_CBC\_Level\_Sel.

The overall effect on the audio is quite similar a voltage-clipping, which temporarily limits music signal peak power to maintain continues music playing without disruption on removal of the overload.

### 8.5.5.2 Overcurrent Shutdown (OCSD)

If there is severe short-circuit event, such as output short to PVDD or ground, the TAS5828M starts shutdown process less than 100ns once peak-current detector is over Overcurrent Threshold (list in [Electrical Characteristics - OCE<sub>THRES</sub>](#) ). The shutdown speed depends on a number of factors, such as the impedance of the short circuit, supply voltage, and switching frequency.

If an OCSD event occurs, the fault GPIO is pulled low and I<sup>2</sup>C fault register fault status is reported, then outputs transfer to high impedance Hiz status, signifying a fault. This is a latched error, and the user needs to restart output via I<sup>2</sup>C clear fault operation.

### 8.5.5.3 DC Detect Error

If the TAS5828M detects a DC offset in the output voltage cross speaker over DC error protection threshold DCR<sub>THRES</sub>, and this status period is over T<sub>DCDET</sub> (list in [Electrical Characteristics - Protection](#)), the FAULTZ line is pulled low and the OUTx outputs transition to high impedance, signifying a fault. This latched DC Protection error requires I<sup>2</sup>C clear fault operation to restart audio output.

#### 8.5.5.4 Overtemperature Shutdown (OTSD)

The TAS5828M device continuously monitors die temperature to ensure it does not exceed the over temperature threshold specified in [Electrical Characteristics -  \$OCE\_{THRES}\$](#) . If an OTE event occurs, the fault GPIO is pulled low and I<sup>2</sup>C fault status is reported, then audio output transfers to high impedance Hiz mode, signifying a fault. This is a latched error, and it requires I<sup>2</sup>C clear fault operation to restart audio playing.

#### 8.5.5.5 PVDD Overvoltage and Undervoltage Error

If the voltage presented on the PVDD supply rises over the  $OVE_{THRES(PVDD)}$  or drops below the  $UVE_{THRES(PVDD)}$  listed in [Electrical Characteristics - Protection](#), the fault GPIO is pulled to low and I<sup>2</sup>C fault status is reported, then audio output transfers to high impedance Hiz mode. These are self-clearing error, which means that once PVDD level is back to normal operation, the device resumes audio playing.

#### 8.5.5.6 PVDD Drop Detection

TAS5828M not only provides PVDD Undervoltage Shutdown protection, but also optional PVDD drop detection. Based on internal PVDD real-time sensing voltage, TAS5828M is able to be configured to expected behavior, which could toggle pin10 PD\_DET from high to low to indicate PVDD drops below specific level (default 8 V), and whether TAS5828M automatically goes into Hiz mode to shutdown audio output. All these settings is accessible through Register 0x04h and 0x05h.

The purpose is to feedback PVDD voltage drop information through GPIO to user product control system, which is able to implement flexible protection strategy. For example, SOC could starts audio volume fade out process once PD\_DET pin goes to low. This process could provide effective pop-click free control shutdown.

#### 8.5.5.7 Clock Fault

When a clock error is detected on incoming data clock, the TAS5828M device switches to an internal oscillator and continues to the driving DAC, which attenuating the data from the last known value. Once this process is completed, the DAC output is hard muted to ground and audio output stops. This non-latched clock fault status is reported I<sup>2</sup>C fault status, and device automatically returns to play mode once correct clock is back.

## 8.6 Register Maps

### 8.6.1 CONTROL PORT Registers

表 8-8 lists the memory-mapped registers for the CONTROL PORT. All register offset addresses not listed in 表 8-8 should be considered as reserved locations and the register contents should not be modified.

表 8-8. CONTROL PORT Registers

Offset	Acronym	Register Name	Section
1h	RESET_CTRL	Register 1	<a href="#">セクション 8.6.1.2</a>
2h	DEVICE_CTRL1	Register 2	<a href="#">セクション 8.6.1.3</a>
3h	DEVICE_CTRL2	Register 3	<a href="#">セクション 8.6.1.4</a>
4h	PVDD_DROP_DETECTION_CTRL1	Register 4	<a href="#">セクション 8.6.1.5</a>
5h	PVDD_DROP_DETECTION_CTRL2	Register 5	<a href="#">セクション 8.6.1.6</a>
Fh	I2C_PAGE_AUTO_INC	Register 15	<a href="#">セクション 8.6.1.7</a>
28h	SIG_CH_CTRL	Register 40	<a href="#">セクション 8.6.1.8</a>
29h	CLOCK_DET_CTRL	Register 41	<a href="#">セクション 8.6.1.9</a>
30h	SDOUT_SEL	Register 48	<a href="#">セクション 8.6.1.10</a>
31h	I2S_CTRL	Register 49	<a href="#">セクション 8.6.1.11</a>
33h	SAP_CTRL1	Register 51	<a href="#">セクション 8.6.1.12</a>
34h	SAP_CTRL2	Register 52	<a href="#">セクション 8.6.1.13</a>
35h	SAP_CTRL3	Register 53	<a href="#">セクション 8.6.1.14</a>
37h	FS_MON	Register 55	<a href="#">セクション 8.6.1.15</a>
38h	BCK(SCLK)_MON	Register 56	<a href="#">セクション 8.6.1.16</a>
39h	CLKDET_STATUS	Register 57	<a href="#">セクション 8.6.1.17</a>
40h	DSP_PGM_MODE	Register 64	<a href="#">セクション 8.6.1.18</a>
46h	DSP_CTRL	Register 70	<a href="#">セクション 8.6.1.19</a>
4Ch	DIG_VOL	Register 76	<a href="#">セクション 8.6.1.20</a>
4Eh	DIG_VOL_CTRL1	Register 78	<a href="#">セクション 8.6.1.21</a>
4Fh	DIG_VOL_CTRL2	Register 79	<a href="#">セクション 8.6.1.22</a>
50h	AUTO_MUTE_CTRL	Register 80	<a href="#">セクション 8.6.1.23</a>
51h	AUTO_MUTE_TIME	Register 81	<a href="#">セクション 8.6.1.24</a>
53h	ANA_CTRL	Register 83	<a href="#">セクション 8.6.1.25</a>
54h	AGAIN	Register 84	<a href="#">セクション 8.6.1.26</a>
5Eh	PVDD_ADC	Register 94	<a href="#">セクション 8.6.1.27</a>
60h	GPIO_CTRL	Register 96	<a href="#">セクション 8.6.1.28</a>
61h	GPIO1_SEL	Register 97	<a href="#">セクション 8.6.1.29</a>
62h	GPIO2_SEL	Register 98	<a href="#">セクション 8.6.1.30</a>
63h	GPIO0_SEL	Register 99	<a href="#">セクション 8.6.1.31</a>
64h	GPIO_INPUT_SEL	Register 100	<a href="#">セクション 8.6.1.32</a>
65h	GPIO_OUT	Register 101	<a href="#">セクション 8.6.1.33</a>
66h	GPIO_OUT_INV	Register 102	<a href="#">セクション 8.6.1.34</a>
67h	DIE_ID	Register 103	<a href="#">セクション 8.6.1.35</a>
68h	POWER_STATE	Register 104	<a href="#">セクション 8.6.1.36</a>
69h	AUTOMUTE_STATE	Register 105	<a href="#">セクション 8.6.1.37</a>
6Ah	PHASE_CTRL	Register 106	<a href="#">セクション 8.6.1.38</a>
6Bh	SS_CTRL0	Register 107	<a href="#">セクション 8.6.1.39</a>



**表 8-8. CONTROL PORT Registers (continued)**

Offset	Acronym	Register Name	Section
6Ch	SS_CTRL1	Register 108	<a href="#">セクション 8.6.1.40</a>
6Dh	SS_CTRL2	Register 109	<a href="#">セクション 8.6.1.41</a>
6Eh	SS_CTRL3	Register 110	<a href="#">セクション 8.6.1.42</a>
6Fh	SS_CTRL4	Register 111	<a href="#">セクション 8.6.1.43</a>
70h	CHAN_FAULT	Register 112	<a href="#">セクション 8.6.1.44</a>
71h	GLOBAL_FAULT1	Register 113	<a href="#">セクション 8.6.1.45</a>
72h	GLOBAL_FAULT2	Register 114	<a href="#">セクション 8.6.1.46</a>
73h	WARNING	Register 115	<a href="#">セクション 8.6.1.47</a>
74h	PIN_CONTROL1	Register 116	<a href="#">セクション 8.6.1.48</a>
75h	PIN_CONTROL2	Register 117	<a href="#">セクション 8.6.1.49</a>
76h	MISC_CONTROL	Register 118	<a href="#">セクション 8.6.1.50</a>
77h	CBC_CONTROL	Register 119	<a href="#">セクション 8.6.1.51</a>
78h	FAULT_CLEAR	Register 120	<a href="#">セクション 8.6.1.52</a>

Complex bit access types are encoded to fit into small table cells. [表 8-9](#) shows the codes that are used for access types in this section.

**表 8-9. CONTROL PORT Access Type Codes**

Access Type	Code	Description
Read Type		
R	R	Read
Write Type		
W	W	Write
Reset or Default Value		
-n		Value after reset or the default value

]]],

### 8.6.1.1 RESET\_CTRL Register (Offset = 1h) [reset = 0x00]

RESET\_CTRL is shown in [图 8-14](#) and described in [表 8-10](#).

Return to [表 8-8](#).

**图 8-14. RESET\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED			RST_MOD	RESERVED			RST_REG
R/W			W	R			W

**表 8-10. RESET\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	This bit is reserved
4	RST_DIG_CORE	W	0	WRITE CLEAR BIT Reset DIG_CORE WRITE CLEAR BIT Reset Full Digital Core. This bit resets the Full Digital Signal Path (Include DSP coefficient RAM and I2C Control Port Registers), Since the DSP is also reset, the coefficient RAM content is also cleared by the DSP. 0: Normal 1: Reset Full Digital Signal Path
3-1	RESERVED	R	000	This bit is reserved
0	RST_REG	W	0	WRITE CLEAR BIT Reset Registers This bit resets the mode registers back to their initial values. Only reset Control Port Registers, The RAM content is not cleared. 0: Normal 1: Reset I <sup>2</sup> C Control Port Registers

### 8.6.1.2 DEVICE\_CTRL\_1 Register (Offset = 2h) [reset = 0x00]

DEVICE\_CTRL\_1 is shown in [图 8-15](#) and described in [表 8-11](#).

Return to [表 8-8](#).

**图 8-15. DEVICE\_CTRL\_1 Register**

7	6	5	4	3	2	1	0
RESERVED	FSW_SEL			RESERVED	DAMP_PBTB	DAMP_MOD	
R/W	R/W			R/W	R/W	R/W	

**表 8-11. DEVICE\_CTRL\_1 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6-4	FSW_SEL	R/W	000	SELECT FSW 000:384K 010:480K 011:576K 100:768K 001:Reserved 101:Reserved 110:Reserved 111:Reserved
3	RESERVED	R/W	0	This bit is reserved

表 8-11. DEVICE\_CTRL\_1 Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
2	DAMP_PBTL	R/W	0	0: SET DAMP TO BTL MODE 1: SET DAMP TO PBTL MODE
1-0	DAMP_MOD	R/W	00	00: BD MODE 01: 1SPW MODE 10: HYBRID MODE

### 8.6.1.3 DEVICE\_CTRL2 Register (Offset = 3h) [reset = 0x10]

DEVICE\_CTRL2 is shown in 図 8-16 and described in 表 8-12.

Return to 表 8-8.

図 8-16. DEVICE\_CTRL2 Register

7	6	5	4	3	2	1	0
RESERVED			DIS_DSP	MUTE_LEFT	RESERVED	CTRL_STATE	
R/W			R/W	R/W	R/W	R/W	

表 8-12. DEVICE\_CTRL2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	This bit is reserved
4	DIS_DSP	R/W	1	DSP reset When the bit is made 0, DSP starts powering up and send out data. This needs to be made 0 only after all the input clocks are settled so that DMA channels do not go out of sync. 0: Normal operation 1: Reset the DSP
3	MUTE	R/W	0	Mute both Left and Right Channel This bit issues soft mute request for both left and right channel. The volume is smoothly ramped down/up to avoid pop/click noise. 0: Normal volume 1: Mute
2	RESERVED	R/W	0	This bit is reserved
1-0	CTRL_STATE	R/W	00	device state control register 00: Deep Sleep 01: Sleep 10: Hiz, 11: PLAY

### 8.6.1.4 PVDD\_DROP\_DETECTION\_CTRL1 Register (Offset = 4h) [reset = 0x00]

PVDD\_DROP\_DETECTION\_CTRL1 is shown in 図 8-17 and described in 表 8-13.

Return to 表 8-8.

図 8-17. PVDD\_DROP\_DETECTION\_CTRL1 Register

7	6	5	4	3	2	1	0
RESERVED				PVDD_DROP_DET_SEQUEN CE	PVDD_DROP_DET_AVE_SAMP LES	PVDD_DROP_DET_BYPASS	
R/W				R/W	R/W	R/W	

表 8-13. PVDD\_DROP\_DETECTION\_CTRL1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	000	This bit is reserved

**表 8-13. PVDD\_DROP\_DETECTION\_CTRL1 Register Field Descriptions (continued)**

Bit	Field	Type	Reset	Description
3	PVDD_DROP_DET_State_Control	R/W	0	This bit controls whether device automatically set into Hiz or still play once PVDD drop detection happens. 0: The device keeps in play mode even PVDD drops configured threshold 1: The device goes into Hiz once PVDD drops configured threshold
2-1	PVDD_DROP_DET_AVE_SAMPLES	R/W	00	PVDD sense average samples for drop detection This bit is used to set PVDD voltage sense average samples for drop detection. 00: 1 sample - cycle by cycle, no average 01: 16 samples 10: 32 samples 11: 64 samples
0	PVDD_DROP_DET_Enable	R/W	0	PVDD drop detection Enable This bit controls enable or bypass PVDD drop detection. 0: Bypass PVDD drop detection 1: Enable PVDD drop detection

**8.6.1.5 PVDD\_DROP\_DETECTION\_CTRL2 Register (Offset = 5h) [reset = 0x44]**

PVDD\_DROP\_DETECTION\_CTRL2 is shown in [图 8-18](#) and described in [表 8-14](#).

Return to [表 8-8](#).

**图 8-18. PVDD\_DROP\_DETECTION\_CTRL2 Register**

7	6	5	4	3	2	1	0
PVDD Drop Detection Voltage Threshold							
R/W							

**表 8-14. PVDD\_DROP\_DETECTION\_CTRL2 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-0	PVDD Drop Detection Voltage Threshold	R/W	00000000	This bit is used to set PVDD Drop Detection Threshold. The ratio to 0xFFh equals to full scale voltage 30V. For example, 8V threshold: 8V/30V = 0x44h/0xFFh. PVDD Drop Threshold is configured as: 00: 0V 01: 0.117V ... 44: 8V ... FF: 30V

**8.6.1.6 I2C\_PAGE\_AUTO\_INC Register (Offset = Fh) [reset = 0x00]**

I2C\_PAGE\_AUTO\_INC is shown in [图 8-19](#) and described in [表 8-15](#).

Return to [表 8-8](#).

**图 8-19. I2C\_PAGE\_AUTO\_INC Register**

7	6	5	4	3	2	1	0
RESERVED				PAGE_AUTOINC_REG	RESERVED		
R/W				R/W	R/W		

**表 8-15. I2C\_PAGE\_AUTO\_INC Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	0000	This bit is reserved

表 8-15. I2C\_PAGE\_AUTO\_INC Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
3	PAGE_AUTOINC_REG	R/W	0	Page auto increment disable Disable page auto increment mode. for non -zero books. When end of page is reached it goes back to 8th address location of next page when this bit is 0. When this bit is 1 it goes to 0 th location of current page itself like in older part. 0: Enable Page auto increment 1: Disable Page auto increment
2-0	RESERVED	R/W	000	This bit is reserved

### 8.6.1.7 SIG\_CH\_CTRL Register (Offset = 28h) [reset = 0x00]

SIG\_CH\_CTRL is shown in 图 8-20 and described in 表 8-16.

Return to 表 8-8.

图 8-20. SIG\_CH\_CTRL Register

7	6	5	4	3	2	1	0
SCLK_RATIO_CONFIGURE				FSMODE	RESERVED		
R/W				R/W	R/W		

表 8-16. SIG\_CH\_CTRL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	SCLK_RATIO_CONFIGURE	R/W	0000	These bits indicate the configured SCLK ratio, the number of SCLK clocks in one audio frame. Device sets this ratio automatically. 4'b0011:32FS 4'b0101:64FS 4'b0111:128FS 4'b1001:256FS 4'b1011:512FS
3	FSMODE	R/W	0	FS Speed Mode These bits select the FS operation mode, which must be set according to the current audio sampling rate. Need set it manually If the input Fs is 44.1kHz/88.2kHz/176.4kHz. 4'b0000 Auto detection 4'b0100 Reserved 4'b0110 32KHz 4'b1000 44.1KHz 4'b1001 48KHz 4'b1010 88.2KHz 4'b1011 96KHz 4'b1100 176.4KHz 4'b1101 192KHz Others Reserved
2-0	RESERVED	R/W	000	This bit is reserved

### 8.6.1.8 CLOCK\_DET\_CTRL Register (Offset = 29h) [reset = 0x00]

CLOCK\_DET\_CTRL is shown in [图 8-21](#) and described in [表 8-17](#).

Return to [表 8-8](#).

**图 8-21. CLOCK\_DET\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED	DIS_DET_PLL	DIS_DET_SCLK_RANGE	DIS_DET_FS	DIS_DET_SCLK	DIS_DET_MISS	RESERVED	RESERVED
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

**表 8-17. CLOCK\_DET\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6	DIS_DET_PLL	R/W	0	Ignore PLL overrate Detection This bit controls whether to ignore the PLL overrate detection. The PLL must be slow than 150MHz or an error is reported. When ignored, a PLL overrate error does not cause a clock error. 0: Regard PLL overrate detection 1: Ignore PLL overrate detection
5	DIS_DET_SCLK_RANGE	R/W	0	Ignore BCK Range Detection This bit controls whether to ignore the SCLK range detection. The SCLK must be stable between 256 KHz and 50 MHz or an error is reported. When ignored, a SCLK range error does not cause a clock error. 0: Regard BCK Range detection 1: Ignore BCK Range detection
4	DIS_DET_FS	R/W	0	Ignore FS Error Detection This bit controls whether to ignore the FS Error detection. When ignored, FS error does not cause a clock error. But CLKDET_STATUS reports fs error. 0: Regard FS detection 1: Ignore FS detection
3	DIS_DET_SCLK	R/W	0	Ignore SCLK Detection This bit controls whether to ignore the SCLK detection against LRCK. The SCLK must be stable between 32FS and 512FS inclusive or an error is reported. When ignored, a SCLK error does not cause a clock error. 0: Regard SCLK detection 1: Ignore SCLK detection
2	DIS_DET_MISS	R/W	0	Ignore SCLK Missing Detection This bit controls whether to ignore the SCLK missing detection. When ignored, an SCLK missing does not cause a clock error. 0: Regard SCLK missing detection 1: Ignore SCLKmissing detection
1	RESERVED	R/W	0	This bit is reserved
0	RESERVED	R/W	0	This bit is reserved

### 8.6.1.9 SDOUT\_SEL Register (Offset = 30h) [reset = 0x00]

SDOUT\_SEL is shown in [图 8-23](#) and described in [表 8-18](#).

Return to [表 8-8](#).

**图 8-22. SDOUT\_SEL Register**

7	6	5	4	3	2	1	0
RESERVED				RESERVED		SDOUT_SEL	
R/W				R/W		R/W	

**表 8-18. SDOUT\_SEL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-1	RESERVED	R/W	0000000	These bits are reserved
0	SDOUT_SEL	R/W	0	SDOUT Select. This bit selects what is being output as SDOUT pin. 0: SDOUT is the DSP output (post-processing) 1: SDOUT is the DSP input (pre-processing)

### 8.6.1.10 I2S\_CTRL Register (Offset = 31h) [reset = 0x00]

I2S\_CTRL is shown in [图 8-23](#) and described in [表 8-19](#).

Return to [表 8-8](#).

**图 8-23. I2S\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED		SCLK_INV	RESERVED	RESERVED	RESERVED		RESERVED
R/W		R/W	R/W	R	R		R/W

**表 8-19. I2S\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	RESERVED	R/W	00	This bit is reserved
5	SCLK_INV	R/W	0	SCLK Polarity This bit sets the inverted SCLK mode. In inverted SCLK mode, the DAC assumes that the LRCK and DIN edges are aligned to the rising edge of the SCLK. Normally they are assumed to be aligned to the falling edge of the SCLK 0: Normal SCLKmode 1: Inverted SCLK mode
4	RESERVED	R/W	0	This bit is reserved
3	RESERVED	R	0	This bit is reserved
2-1	RESERVED	R	00	These bits are reserved
0	RESERVED	R/W	0	This bit is reserved

### 8.6.1.11 SAP\_CTRL1 Register (Offset = 33h) [reset = 0x02]

SAP\_CTRL1 is shown in [图 8-24](#) and described in [表 8-20](#).

Return to [表 8-8](#).

**图 8-24. SAP\_CTRL1 Register**

7	6	5	4	3	2	1	0
---	---	---	---	---	---	---	---

 **8-24. SAP\_CTRL1 Register (continued)**

I2S_SHIFT_MSB B	RESERVED	DATA_FORMAT	I2S_LRCLK_PULSE	WORD_LENGTH
R/W	R/W	R/W	R/W	R/W

**表 8-20. SAP\_CTRL1 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	I2S_SHIFT_MSB	R/W	0	I2S Shift MSB
6	RESERVED	R/W	0	This bit is reserved
5-4	DATA_FORMAT	R/W	00	I2S Data Format These bits control both input and output audio interface formats for DAC operation. 00: I2S 01: TDM/DSP 10: RTJ 11: LTJ
3-2	I2S_LRCLK_PULSE	R/W	00	01: LRCLK pulse < 8 SCLK
1-0	WORD_LENGTH	R/W	10	I2S Word Length These bits control both input and output audio interface sample word lengths for DAC operation. 00: 16 bits 01: 20 bits 10: 24 bits 11: 32 bits

**8.6.1.12 SAP\_CTRL2 Register (Offset = 34h) [reset = 0x00]**

SAP\_CTRL2 is shown in [図 8-25](#) and described in [表 8-21](#).

Return to [表 8-8](#).

 **8-25. SAP\_CTRL2 Register**

7	6	5	4	3	2	1	0
I2S_SHIFT							
R/W							

**表 8-21. SAP\_CTRL2 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-0	I2S_SHIFT	R/W	00000000	I2S Shift LSB These bits control the offset of audio data in the audio frame for both input and output. The offset is defined as the number of SCLK from the starting (MSB) of audio frame to the starting of the desired audio sample. MSB [8] locates in <a href="#">セクション 8.6.1.12</a> 00000000: offset = 0 SCLK (no offset) 00000001: offset = 1 SCLK 00000010: offset = 2 SCLKs and 11111111: offset = 512 SCLKs



### 8.6.1.13 SAP\_CTRL3 Register (Offset = 35h) [reset = 0x11]

SAP\_CTRL3 is shown in [Figure 8-26](#) and described in [Table 8-22](#).

Return to [Table 8-8](#).

**Figure 8-26. SAP\_CTRL3 Register**

7	6	5	4	3	2	1	0
RESERVED		LEFT_DAC_DPATH		RESERVED		RIGHT_DAC_DPATH	
R/W		R/W		R/W		R/W	

**Table 8-22. SAP\_CTRL3 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	RESERVED	R/W	00	These bits are reserved
5-4	LEFT_DAC_DPATH	R/W	01	Left DAC Data Path. These bits control the left channel audio data path connection. 00: Zero data (mute) 01: Left channel data 10: Right channel data 11: Reserved (do not set)
3-2	RESERVED	R/W	00	These bits are reserved
1-0	RIGHT_DAC_DPATH	R/W	01	Right DAC Data Path. These bits control the right channel audio data path connection. 00: Zero data (mute) 01: Right channel data 10: Left channel data 11: Reserved (do not set)

### 8.6.1.14 FS\_MON Register (Offset = 37h) [reset = 0x00]

FS\_MON is shown in [Figure 8-27](#) and described in [Table 8-23](#).

Return to [Table 8-8](#).

**Figure 8-27. FS\_MON Register**

7	6	5	4	3	2	1	0
RESERVED		SCLK_RATIO_HIGH		FS			
R/W		R		R			

**Table 8-23. FS\_MON Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	RESERVED	R/W	00	This bit is reserved
5-4	SCLK_RATIO_HIGH	R	00	2 msbs of detected SCLK ratio
3-0	FS	R	0000	These bits indicate the currently detected audio sampling rate. 4 'b0000 FS Error 4 'b0100 16KHz 4 'b0110 32KHz 4 'b1000 Reserved 4 'b1001 48KHz 4 'b1011 96KHz 4 'b1101 192KHz Others Reserved

### 8.6.1.15 BCK (SCLK)\_MON Register (Offset = 38h) [reset = 0x00]

BCK\_MON is shown in [图 8-28](#) and described in [表 8-24](#).

Return to [表 8-8](#).

**图 8-28. BCK (SCLK)\_MON Register**

7	6	5	4	3	2	1	0
BCLK (SCLK)_RATIO_LOW							
R							

**表 8-24. BCK\_MON Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-0	BCLK (SCLK)_RATIO_LOW	R	00000000	These bits indicate the currently detected BCK (SCLK) ratio, the number of BCK (SCLK) clocks in one audio frame. BCK (SCLK) = 32 FS~512 FS

### 8.6.1.16 CLKDET\_STATUS Register (Offset = 39h) [reset = 0x00]

CLKDET\_STATUS is shown in [图 8-29](#) and described in [表 8-25](#).

Return to [表 8-8](#).

**图 8-29. CLKDET\_STATUS Register**

7	6	5	4	3	2	1	0
RESERVED			DET_STATUS				
R/W			R				

**表 8-25. CLKDET\_STATUS Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	RESERVED	R/W	00	This bit is reserved
5-0	DET_STATUS	R	000000	bit0: In auto detection mode(reg_fsmode=0),this bit indicated whether the audio sampling rate is valid or not. In non auto detection mode(reg_fsmode!=0), Fs error indicates that configured fs is different with detected fs. Even FS Error Detection Ignore is set, this flag is also asserted. bit1: This bit indicates whether the SCLK is valid or not. The SCLK ratio must be stable and in the range of 32-512FS to be valid. bit2: This bit indicates whether the SCLK is missing or not. bit3:This bit indicates whether the PLL is locked or not. The PLL is reported as unlocked when it is disabled. bits4:This bit indicates whether the PLL is overrate bits5:This bit indicates whether the SCLK is overrate or underrate

### 8.6.1.17 DSP\_PGM\_MODE Register (Offset = 40h) [reset = 0x01]

DSP\_PGM\_MODE is shown in [图 8-30](#) and described in [表 8-26](#).

Return to [表 8-8](#).

**图 8-30. DSP\_PGM\_MODE Register**

7	6	5	4	3	2	1	0
RESERVED			CH1_HIZ	CH2_HIZ	MODE_SEL		
R/W					R/W		

**表 8-26. DSP\_PGM\_MODE Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	This bit is reserved
4	CH1_HIZ	R/W	0	Hi-Z Mode Channel-1 Stops output switching and sets channel-1 to Hi-Z mode. 0: Normal Operation 1: Hi-Z state
3	CH2_HIZ	R/W	0	Hi-Z Mode Channel-2 Stops output switching and sets channel-2 to Hi-Z mode. 0: Normal Operation 1: Hi-Z state
2-0	MODE_SEL	R/W	00001	DSP Program Selection These bits select the DSP program to use for audio processing. 000 => ram mode 001 => rom mode 1

### 8.6.1.18 DSP\_CTRL Register (Offset = 46h) [reset = 0x01]

DSP\_CTRL is shown in [图 8-31](#) and described in [表 8-27](#).

Return to [表 8-8](#).

**图 8-31. DSP\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED			USER_DEFINED_PROCESSING_RATE	RESERVED	BOOT_FROM_I RAM	USE_DEFAULT COEFFS	
R/W			R/W	R	R/W	R/W	R/W

**表 8-27. DSP\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	This bit is reserved
4-3	USER_DEFINED_PROCESSING_RATE	R/W	00	00:input 01:48k 10:96k 11:192k
2	RESERVED	R	0	This bit is reserved
1	RESERVED	R	0	This bit is reserved
0	RESERVED	R/W	1	This bit is reserved

### 8.6.1.19 DIG\_VOL Register (Offset = 4Ch) [reset = 30h]

DIG\_VOL is shown in [图 8-32](#) and described in [表 8-28](#).

Return to [表 8-8](#).

 8-32. DIG\_VOL Register

7	6	5	4	3	2	1	0
PGA_LEFT							
R/W							

表 8-28. DIG\_VOL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	PGA	R/W	00110000	Digital Volume These bits control both left and right channel digital volume. The digital volume is 24 dB to -103 dB in -0.5 dB step. 00000000: +24.0 dB 00000001: +23.5 dB ..... and 00101111: +0.5 dB 00110000: 0.0 dB 00110001: -0.5 dB ..... 11111110: -103 dB 11111111: Mute

### 8.6.1.20 DIG\_VOL\_CTRL1 Register (Offset = 4Eh) [reset = 0x33]

DIG\_VOL\_CTRL1 is shown in  8-33 and described in [表 8-29](#).

Return to [表 8-8](#).

 8-33. DIG\_VOL\_CTRL1 Register

7	6	5	4	3	2	1	0
PGA_RAMP_DOWN_SPEED		PGA_RAMP_DOWN_STEP		PGA_RAMP_UP_SPEED		PGA_RAMP_UP_STEP	
R/W		R/W		R/W		R/W	

表 8-29. DIG\_VOL\_CTRL1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-6	PGA_RAMP_DOWN_SPEED	R/W	00	Digital Volume Normal Ramp Down Frequency These bits control the frequency of the digital volume updates when the volume is ramping down. 00: Update every 1 FS period 01: Update every 2 FS periods 10: Update every 4 FS periods 11: Directly set the volume to zero (Instant mute)
5-4	PGA_RAMP_DOWN_STEP	R/W	11	Digital Volume Normal Ramp Down Step These bits control the step of the digital volume updates when the volume is ramping down. 00: Decrement by 4 dB for each update 01: Decrement by 2 dB for each update 10: Decrement by 1 dB for each update 11: Decrement by 0.5 dB for each update
3-2	PGA_RAMP_UP_SPEED	R/W	00	Digital Volume Normal Ramp Up Frequency These bits control the frequency of the digital volume updates when the volume is ramping up. 00: Update every 1 FS period 01: Update every 2 FS periods 10: Update every 4 FS periods 11: Directly restore the volume (Instant unmute)

表 8-29. DIG\_VOL\_CTRL1 Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
1-0	PGA_RAMP_UP_STEP	R/W	11	Digital Volume Normal Ramp Up Step These bits control the step of the digital volume updates when the volume is ramping up. 00: Increment by 4 dB for each update 01: Increment by 2 dB for each update 10: Increment by 1 dB for each update 11: Increment by 0.5 dB for each update

#### 8.6.1.21 DIG\_VOL\_CTRL2 Register (Offset = 4Fh) [reset = 0x30]

DIG\_VOL\_CTRL2 is shown in 图 8-34 and described in 表 8-30.

Return to 表 8-8.

图 8-34. DIG\_VOL\_CTRL2 Register

7	6	5	4	3	2	1	0
FAST_RAMP_DOWN_SPEED		FAST_RAMP_DOWN_STEP		RESERVED			
R/W		R/W		R/W			

表 8-30. DIG\_VOL\_CTRL2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-6	FAST_RAMP_DOWN_SPEED	R/W	00	Digital Volume Emergency Ramp Down Frequency These bits control the frequency of the digital volume updates when the volume is ramping down due to clock error or power outage, which usually needs faster ramp down compared to normal soft mute. 00: Update every 1 FS period 01: Update every 2 FS periods 10: Update every 4 FS periods 11: Directly set the volume to zero (Instant mute)
5-4	FAST_RAMP_DOWN_STEP	R/W	11	Digital Volume Emergency Ramp Down Step These bits control the step of the digital volume updates when the volume is ramping down due to clock error or power outage, which usually needs faster ramp down compared to normal soft mute. 00: Decrement by 4 dB for each update 01: Decrement by 2 dB for each update 10: Decrement by 1 dB for each update 11: Decrement by 0.5 dB for each update
3-0	RESERVED	R/W	0000	This bit is reserved

#### 8.6.1.22 AUTO\_MUTE\_CTRL Register (Offset = 50h) [reset = 0x00]

AUTO\_MUTE\_CTRL is shown in 图 8-35 and described in 表 8-31.

Return to 表 8-8.

图 8-35. AUTO\_MUTE\_CTRL Register

7	6	5	4	3	2	1	0
RESERVED					REG_AUTO_MUTE_CTRL		
R/W					R/W		

表 8-31. AUTO\_MUTE\_CTRL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-3	RESERVED	R/W	00000	This bit is reserved

**表 8-31. AUTO\_MUTE\_CTRL Register Field Descriptions (continued)**

Bit	Field	Type	Reset	Description
2-0	REG_AUTO_MUTE_CTRL	R/W	000	bit0: 0: Disable left channel auto mute 1: Enable left channel auto mute bit1: 0: Disable right channel auto mute 1: Enable right channel auto mute bit2: 0: Auto mute left channel and right channel independently. 1: Auto mute left and right channels only when both channels are about to be auto muted.

**8.6.1.23 AUTO\_MUTE\_TIME Register (Offset = 51h) [reset = 0x00]**

AUTO\_MUTE\_TIME is shown in [图 8-36](#) and described in [表 8-32](#).

Return to [表 8-8](#).

**图 8-36. AUTO\_MUTE\_TIME Register**

7	6	5	4	3	2	1	0
RESERVED	AUTOMUTE_TIME_LEFT			RESERVED	AUTOMUTE_TIME_RIGHT		
R/W	R/W			R/W	R/W		

**表 8-32. AUTO\_MUTE\_TIME Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6-4	AUTOMUTE_TIME_LEFT	R/W	000	Auto Mute Time for Left Channel These bits specify the length of consecutive zero samples at left channel before the channel can be auto muted. The times shown are for 96 kHz sampling rate and scales with other rates. 000: 11.5 ms 001: 53 ms 010: 106.5 ms 011: 266.5 ms 100: 0.535 sec 101: 1.065 sec 110: 2.665 sec 111: 5.33 sec
3	RESERVED	R/W	0	This bit is reserved
2-0	AUTOMUTE_TIME_RIGHT	R/W	000	Auto Mute Time for Right Channel These bits specify the length of consecutive zero samples at right channel before the channel can be auto muted. The times shown are for 96 kHz sampling rate and scales with other rates. 000: 11.5 ms 001: 53 ms 010: 106.5 ms 011: 266.5 ms 100: 0.535 sec 101: 1.065 sec 110: 2.665 sec 111: 5.33 sec

**8.6.1.24 ANA\_CTRL Register (Offset = 53h) [reset = 0h]**

ANA\_CTRL is shown in [图 8-37](#) and described in [表 8-33](#)

Return to [表 8-8](#)

☒ 8-37. ANA\_CTRL Register

7	6	5	4	3	2	1	0
AMUTE_DLY							
R/W							

表 8-33. ANA\_CTRL Register Field Descriptions

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6-5	Class D bandwidth control	R/W	00	00: 100kHz 01: 80kHz 10: 120kHz 11: 175kHz With Fsw=384kHz, 100kHz bandwidth is selected for high audio performance. With Fsw=768kHz, 175kHz bandwidth should be selected for high audio performance.
4-1	RESERVED	R/W	0000	These bits are reserved
0	L and R PWM output phase control	R/W	0	0: out of phase 1: in phase

#### 8.6.1.25 AGAIN Register (Offset = 54h) [reset = 0x00]

AGAIN is shown in ☒ 8-38 and described in 表 8-34.

Return to 表 8-8.

☒ 8-38. AGAIN Register

7	6	5	4	3	2	1	0
RESERVED				ANA_GAIN			
R/W				R/W			

表 8-34. AGAIN Register Field Descriptions

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	This bit is reserved
4-0	ANA_GAIN	R/W	00000	Analog Gain Control This bit controls the analog gain. 00000: 0 dB (29.5V peak voltage) 00001: -0.5db 11111: -15.5 dB

#### 8.6.1.26 PVDD\_ADC Register (Offset = 5Eh) [reset = 0h]

PVDD\_ADC is shown in ☒ 8-39 and described in 表 8-35.

Return to 表 8-8.

☒ 8-39. PVDD\_ADC Register

7	6	5	4	3	2	1	0
ADC_DATA_OUT							
R							

**表 8-35. PVDD\_ADC Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-0	PVDD_ADC[7:0]	R	00000000	PVDD Voltage = PVDD_ADC[7:0] / 8.428 (V) 223: 26.45V 222: 26.34V 221:26.22V ... 39: 4.63V 38: 4.51V 37: 4.39V

**8.6.1.27 GPIO\_CTRL Register (Offset = 60h) [reset = 0x00]**

GPIO\_CTRL is shown in [图 8-40](#) and described in [表 8-36](#).

Return to [表 8-8](#).

**图 8-40. GPIO\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED					GPIO0_OE	GPIO2_OE	GPIO1_OE
R/W					R/W	R/W	R/W

**表 8-36. GPIO\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-3	RESERVED	R/W	0000	This bit is reserved
2	GPIO0_OE	R/W	0	GPIO2 Output Enable. This bit sets the direction of the GPIO0 pin 0: GPIO0 is input 1: GPIO0 is output
1	GPIO2_OE	R/W	0	GPIO2 Output Enable This bit sets the direction of the GPIO2 pin 0: GPIO2 is input 1: GPIO2 is output
0	GPIO1_OE	R/W	0	GPIO1 Output Enable This bit sets the direction of the GPIO1 pin 0: GPIO1 is input 1: GPIO1 is output

**8.6.1.28 GPIO1\_SEL Register (Offset = 61h) [reset = 0x00]**

GPIO1\_SEL is shown in [图 8-41](#) and described in [表 8-37](#).

Return to [表 8-8](#).

**图 8-41. GPIO1\_SEL Register**

7	6	5	4	3	2	1	0
RESERVED				GPIO1_SEL			
R/W				R/W			

**表 8-37. GPIO1\_SEL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	0000	This bit is reserved



表 8-37. GPIO1\_SEL Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
3-0	GPIO1_SEL	R/W	0000	0000: off (low) 1000: GPIO1 as WARNZ output 1001: GPIO1 as Serial audio interface data output (SDOUT) 1011: GPIO1 as FAULTZ output 1100: GPIO1 as PVDD Drop Detection Flag 1101: GPIO1 as Class-H

#### 8.6.1.29 GPIO2\_SEL Register (Offset = 62h) [reset = 0x00]

GPIO2\_SEL is shown in [图 8-42](#) and described in [表 8-38](#).

Return to [表 8-8](#).

图 8-42. GPIO2\_SEL Register

7	6	5	4	3	2	1	0
RESERVED				GPIO2_SEL			
R/W				R/W			

表 8-38. GPIO2\_SEL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	0000	This bit is reserved
3-0	GPIO2_SEL	R/W	0000	0000: off (low) 1000: GPIO2 as WARNZ output 1001: GPIO2 as Serial audio interface data output (SDOUT) 1011: GPIO2 as FAULTZ output 1100: GPIO2 as PVDD Drop Detection Flag 1101: GPIO2 as Class-H

#### 8.6.1.30 GPIO0\_SEL Register (Offset = 63h) [reset = 0x00]

GPIO0\_SEL is shown in [图 8-43](#) and described in [表 8-39](#).

Return to [表 8-8](#).

图 8-43. GPIO0\_SEL Register

7	6	5	4	3	2	1	0
RESERVED				GPIO0_SEL			
R/W				R/W			

表 8-39. GPIO0\_SEL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	0000	This bit is reserved
3-0	GPIO0_SEL	R/W	0000	0000: off (low) 1000: GPIO0 as WARNZ output 1001: GPIO0 as Serial audio interface data output (SDOUT) 1011: GPIO0 as FAULTZ output 1100: GPIO0 as PVDD Drop Detection Flag 1101: GPIO0 as Class-H

#### 8.6.1.31 GPIO\_INPUT\_SEL Register (Offset = 64h) [reset = 0x00]

GPIO\_INPUT\_SEL is shown in [图 8-44](#) and described in [表 8-40](#).

Return to [表 8-8](#).

**图 8-44. GPIO\_INPUT\_SEL Register**

7	6	5	4	3	2	1	0
GPIO_SPI_MISO_SEL		GPIO_PHASE_SYNC_SEL		GPIO_RESETZ_SEL		GPIO_MUTEZ_SEL	
R/W		R/W		R/W		R/W	

**表 8-40. GPIO\_INPUT\_SEL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	GPIO_SPI_MISO_SEL	R/W	00	00: N/A 01: GPIO1 10: GPIO2 11: GPIO0
5-4	GPIO_PHASE_SYNC_SEL	R/W	00	00: N/A 01: GPIO1 10: GPIO2 11: GPIO0
3-2	GPIO_RESETZ_SEL	R/W	00	00: N/A 01: GPIO1 10: GPIO2 11: GPIO0 can not be reset by GPIO reset
1-0	GPIO_MUTEZ_SEL	R/W	00	00: N/A 01: GPIO1 10: GPIO2 11: GPIO0 MUTEZ pin active-low, output driver is set to HiZ state, Class D amplifier's output stop switching.

**8.6.1.32 GPIO\_OUT Register (Offset = 65h) [reset = 0x00]**

GPIO\_OUT is shown in [图 8-45](#) and described in [表 8-41](#).

Return to [表 8-8](#).

**图 8-45. GPIO\_OUT Register**

7	6	5	4	3	2	1	0
RESERVED					GPIO_OUT		
R/W					R/W		

**表 8-41. GPIO\_OUT Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-3	RESERVED	R/W	00000	This bit is reserved
2-0	GPIO_OUT	R/W	000	bit0: GPIO1 output bit1: GPIO2 output bit2: GPIO0 output

**8.6.1.33 GPIO\_OUT\_INV Register (Offset = 66h) [reset = 0x00]**

GPIO\_OUT\_INV is shown in [图 8-46](#) and described in [表 8-42](#).

Return to [表 8-8](#).

**图 8-46. GPIO\_OUT\_INV Register**

7	6	5	4	3	2	1	0
RESERVED					GPIO_OUT		

图 8-46. GPIO\_OUT\_INV Register (continued)

R/W	R/W
-----	-----

表 8-42. GPIO\_OUT\_INV Register Field Descriptions

Bit	Field	Type	Reset	Description
7-3	RESERVED	R/W	00000	This bit is reserved
2-0	GPIO_OUT	R/W	000	bit0: GPIO1 output invert bit1: GPIO2 output invert bit2: GPIO0 output invert

#### 8.6.1.34 DIE\_ID Register (Offset = 67h) [reset = 95h]

DIE\_ID is shown in 图 8-47 and described in 表 8-43.

Return to 表 8-8.

图 8-47. DIE\_ID Register

7	6	5	4	3	2	1	0
DIE_ID							
R							

表 8-43. DIE\_ID Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DIE_ID	R	10010101	DIE ID

#### 8.6.1.35 POWER\_STATE Register (Offset = 68h) [reset = 0x00]

POWER\_STATE is shown in 图 8-48 and described in 表 8-44.

Return to 表 8-8.

图 8-48. POWER\_STATE Register

7	6	5	4	3	2	1	0
STATE_RPT							
R							

表 8-44. POWER\_STATE Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	STATE_RPT	R	00000000	0: Deep sleep 1: Seep 2: HIZ 3: Play Others: reserved

#### 8.6.1.36 AUTOMUTE\_STATE Register (Offset = 69h) [reset = 0x00]

AUTOMUTE\_STATE is shown in 图 8-49 and described in 表 8-45.

Return to 表 8-8.

图 8-49. AUTOMUTE\_STATE Register

7	6	5	4	3	2	1	0
---	---	---	---	---	---	---	---

**图 8-49. AUTOMUTE\_STATE Register (continued)**

RESERVED		ZERO_RIGHT_MON	ZERO_LEFT_MON
R		R	R

**表 8-45. AUTOMUTE\_STATE Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-2	RESERVED	R	000000	This bit is reserved
1	ZERO_RIGHT_MON	R	0	This bit indicates the auto mute status for right channel. 0: Not auto muted 1: Auto muted
0	ZERO_LEFT_MON	R	0	This bit indicates the auto mute status for left channel. 0: Not auto muted 1: Auto muted

### 8.6.1.37 PHASE\_CTRL Register (Offset = 6Ah) [reset = 0]

PHASE\_CTRL is shown in [图 8-50](#) and described in [表 8-46](#).

Return to [表 8-8](#).

**图 8-50. PHASE\_CTRL Register**

7	6	5	4	3	2	1	0
RESERVED				RAMP_PHASE_SEL		PHASE_SYNC_SEL	PHASE_SYNC_EN
R/W				R/W		R/W	R/W

**表 8-46. PHASE\_CTRL Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-4	RESERVED	R/W	0000	This bit is reserved
3-2	RAMP_PHASE_SEL	R/W	00	select ramp clock phase when multi devices integrated in one system to reduce EMI and peak supply peak current, it is recommended set all devices the same RAMP frequency and same spread spectrum. it must be set before driving device into PLAY mode if this feature is needed. 2'b00: phase 0 2'b01: phase 1 2'b10: phase 2 2'b11: phase 3 all of above have a 45 degree of phase shift
1	PHASE_SYNC_SEL	R/W	0	ramp phase sync sel, 0: is gpio sync; 1: internal sync
0	PHASE_SYNC_EN	R/W	0	ramp phase sync enable

### 8.6.1.38 RAMP\_SS\_CTRL0 Register (Offset = 6Bh) [reset = 0x00]

RAMP\_SS\_CTRL0 is shown in [图 8-51](#) and described in [表 8-47](#).

Return to [表 8-8](#).

**图 8-51. SS\_CTRL0 Register**

7	6	5	4	3	2	1	0
RESERVED	RESERVED	SS_PRE_DIV_SEL	SS_MANUAL_MODE	RESERVED		SS_RDM_EN	SS_TRI_EN

图 8-51. SS\_CTRL0 Register (continued)

R/W	R/W	R/W	R/W	R/W	R/W	R/W
-----	-----	-----	-----	-----	-----	-----

表 8-47. RAMP\_SS\_CTRL0 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6	RESERVED	R/W	0	This bit is reserved
5	SS_PRE_DIV_SEL	R/W	0	Select pll clock divide 2 as source clock in manual mode
4	SS_MANUAL_MODE	R/W	0	Set ramp ss controller to manual mode
3-2	RESERVED	R/W	00	This bit is reserved
1	SS_RDM_EN	R/W	0	Random SS enable
0	SS_TRI_EN	R/W	0	Triangle SS enable

### 8.6.1.39 SS\_CTRL1 Register (Offset = 6Ch) [reset = 0x00]

SS\_CTRL1 is shown in 图 8-52 and described in 表 8-48.

Return to 表 8-8.

图 8-52. SS\_CTRL1 Register

7	6	5	4	3	2	1	0
RESERVED	SS_RDM_CTRL			SS_TRI_CTRL			
R/W	R/W			R/W			

表 8-48. SS\_CTRL1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6-4	SS_RDM_CTRL	R/W	000	Add Dither
3-0	SS_TRI_CTRL	R/W	0000	Triangle SS frequency and range control

### 8.6.1.40 SS\_CTRL2 Register (Offset = 6Dh) [reset = 0xA0]

SS\_CTRL2 is shown in 图 8-53 and described in 表 8-49.

Return to 表 8-8.

图 8-53. SS\_CTRL2 Register

7	6	5	4	3	2	1	0
TM_FREQ_CTRL							
R/W							

表 8-49. SS\_CTRL2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	TM_FREQ_CTRL	R/W	10100000	Control ramp frequency in manual mode, F=61440000/N

### 8.6.1.41 SS\_CTRL3 Register (Offset = 6Eh) [reset = 0x11]

SS\_CTRL3 is shown in 图 8-54 and described in 表 8-50.

Return to [表 8-8](#).

**図 8-54. SS\_CTRL3 Register**

7	6	5	4	3	2	1	0
TM_DSTEP_CTRL				TM_USTEP_CTRL			
R/W				R/W			

**表 8-50. SS\_CTRL3 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-4	SS_TM_DSTEP_CTRL	R/W	0001	Control triangle mode spread spectrum fall step in ramp ss manual mode
3-0	SS_TM_USTEP_CTRL	R/W	0001	Control triangle mode spread spectrum rise step in ramp ss manual mode

#### 8.6.1.42 SS\_CTRL4 Register (Offset = 6Fh) [reset = 0x24]

SS\_CTRL4 is shown in [図 8-55](#) and described in [表 8-51](#).

Return to [表 8-8](#).

**図 8-55. SS\_CTRL4 Register**

7	6	5	4	3	2	1	0
RESERVED	TM_AMP_CTRL		SS_TM_PERIOD_BOUNDARY				
R/W	R/W		R/W				

**表 8-51. SS\_CTRL4 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	RESERVED	R/W	0	This bit is reserved
6-5	TM_AMP_CTRL	R/W	01	Control ramp amp ctrl in ramp ss manual model
4-0	SS_TM_PERIOD_BOUNDARY	R/W	00100	Control triangle mode spread spectrum boundary in ramp ss manual mode

#### 8.6.1.43 CHAN\_FAULT Register (Offset = 70h) [reset = 0x00]

CHAN\_FAULT is shown in [図 8-56](#) and described in [表 8-52](#).

Return to [表 8-8](#).

**図 8-56. CHAN\_FAULT Register**

7	6	5	4	3	2	1	0
RESERVED				CH1_DC_1	CH2_DC_1	CH1_OC_I	CH2_OC_I
R				R	R	R	R

**表 8-52. CHAN\_FAULT Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-4	RESERVED	R	0000	This bit is reserved
3	CH1_DC_1	R	0	Left channel DC fault. Once there is a DC fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.

表 8-52. CHAN\_FAULT Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
2	CH2_DC_1	R	0	Right channel DC fault. Once there is a DC fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.
1	CH1_OC_I	R	0	Left channel over current fault. Once there is a OC fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.
0	CH2_OC_I	R	0	Right channel over current fault. Once there is a OC fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.

#### 8.6.1.44 GLOBAL\_FAULT1 Register (Offset = 71h) [reset = 0h]

GLOBAL\_FAULT1 is shown in [図 8-57](#) and described in [表 8-53](#).

Return to [表 8-8](#).

図 8-57. GLOBAL\_FAULT1 Register

7	6	5	4	3	2	1	0
OTP_CRC_ER ROR	BQ_WR_ERRO R	LOAD_EEPRO M_ERROR	RESERVED	RESERVED	CLK_FAULT_I	PVDD_OV_I	PVDD_UV_I
R	R	R	R	R	R	R	R

表 8-53. GLOBAL\_FAULT1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	OTP_CRC_ERROR	R	0	Indicate OTP CRC check error.
6	BQ_WR_ERROR	R	0	The recent BQ is written failed
5	LOAD_EEPROM_ERROR	R	0	0: EEPROM boot load was done successfully 1: EEPROM boot load was done unsuccessfully
4	RESERVED	R	0	This bit is reserved
3	RESERVED	R	0	This bit is reserved
2	CLK_FAULT_I	R	0	Clock fault. Once there is a Clock fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). Clock fault works with an auto-recovery mode, once the clock error removes, device automatically returns to the previous state. Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.
1	PVDD_OV_I	R	0	PVDD OV fault. Once there is a OV fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). OV fault works with an auto-recovery mode, once the OV error removes, device automatically returns to the previous state. Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.

**表 8-53. GLOBAL\_FAULT1 Register Field Descriptions (continued)**

Bit	Field	Type	Reset	Description
0	PVDD_UV_I	R	0	PVDD UV fault. Once there is a UV fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). OV fault works with an auto-recovery mode, once the OV error removes, device automatically returns to the previous state. Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.

**8.6.1.45 GLOBAL\_FAULT2 Register (Offset = 72h) [reset = 0h]**

GLOBAL\_FAULT2 is shown in [図 8-58](#) and described in [表 8-54](#).

Return to [表 8-8](#).

**図 8-58. GLOBAL\_FAULT2 Register**

7	6	5	4	3	2	1	0
RESERVED					CBC_FAULT_C H2_I	CBC_FAULT_C H1_I	OTSD_I
R					R	R	R

**表 8-54. GLOBAL\_FAULT2 Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-3	RESERVED	R	0000	This bit is reserved
2	CBC_FAULT_CH2_I	R	0	Right channel cycle by cycle over current fault
1	CBC_FAULT_CH1_I	R	0	Left channel cycle by cycle over current fault
0	OTSD_I	R	0	Over temperature shut down fault. Once there is a OT fault, this bit is set to be 1. Class D output is set to Hi-Z. Report by FAULT pin (GPIO). OV fault works with an auto-recovery mode, once the OV error removes, device automatically returns to the previous state. Clear this fault by setting bit 7 of <a href="#">セクション 8.6.1.52</a> to 1 or this bit keeps 1.

**8.6.1.46 WARNING Register (Offset = 73h) [reset = 0x00]**

WARNING is shown in [図 8-59](#) and described in [表 8-55](#).

Return to [表 8-8](#).

**図 8-59. WARNING Register**

7	6	5	4	3	2	1	0
RESERVED		CBCW_CH1_I	CBCW_CH2_I	OTW_LEVEL4_ I	OTW_LEVEL3_ I	OTW_LEVEL2_ I	OTW_LEVEL1_ I
R		R	R	R	R	R	R

**表 8-55. WARNING Register Field Descriptions**

Bit	Field	Type	Reset	Description
7-6	RESERVED	R	0	This bit is reserved
5	CBCW_CH1_I	R	0	Left channel cycle by cycle over current warning
4	CBCW_CH2_I	R	0	Right channel cycle by cycle over current warning



表 8-55. WARNING Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
3	OTW_LEVEL4_I	R	0	Over temperature warning leve4, 146C
2	OTW_LEVEL3_I	R	0	Over temperature warning leve3, 134C
1	OTW_LEVEL2_I	R	0	Over temperature warning leve2, 122C
0	OTW_LEVEL1_I	R	0	Over temperature warning leve1, 112C

#### 8.6.1.47 PIN\_CONTROL1 Register (Offset = 74h) [reset = 0x00]

PIN\_CONTROL1 is shown in 図 8-60 and described in 表 8-56.

Return to 表 8-8.

図 8-60. PIN\_CONTROL1 Register

7	6	5	4	3	2	1	0
MASK_OTSD	MASK_DVDD_UV	MASK_DVDD_OV	MASK_CLK_FAULT	RESERVED	MASK_PVDD_UV	MASK_DC	MASK_OC
R/W	R/W	R/W	R/W	R	R/W	R/W	R/W

表 8-56. PIN\_CONTROL1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	MASK_OTSD	R/W	0	Mask OTSD fault report
6	MASK_DVDD_UV	R/W	0	Mask DVDD UV fault report
5	MASK_DVDD_OV	R/W	0	Mask DVDD OV fault report
4	MASK_CLK_FAULT	R/W	0	Mask clock fault report
3	RESERVED	R	0	This bit is reserved
2	MASK_PVDD_UV	R/W	0	Mask PVDD UV fault report mask PVDD OV fault report
1	MASK_DC	R/W	0	Mask DC fault report
0	MASK_OC	R/W	0	Mask OC fault report

#### 8.6.1.48 PIN\_CONTROL2 Register (Offset = 75h) [reset = 0xF8]

PIN\_CONTROL2 is shown in 図 8-61 and described in 表 8-57.

Return to 表 8-8.

図 8-61. PIN\_CONTROL2 Register

7	6	5	4	3	2	1	0
CBC_FAULT_LATCH_EN	CBC_WARN_LATCH_EN	CLKFLT_LATCH_EN	OTSD_LATCH_EN	OTW_LATCH_EN	MASK_OTW	MASK_CBCW	MASK_CBC_FAULT
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

表 8-57. PIN\_CONTROL2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	CBC_FAULT_LATCH_EN	R/W	1	Enable CBC fault latch by setting this bit to 1
6	CBC_WARN_LATCH_EN	R/W	1	Enable CBC warning latch by setting this bit to 1
5	CLKFLT_LATCH_EN	R/W	1	Enable clock fault latch by setting this bit to 1
4	OTSD_LATCH_EN	R/W	1	Enable OTSD fault latch by setting this bit to 1

表 8-57. PIN\_CONTROL2 Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
3	OTW_LATCH_EN	R/W	1	Enable OT warning latch by setting this bit to 1
2	MASK_OTW	R/W	0	Mask OT warning report by setting this bit to 1
1	MASK_CBCW	R/W	0	Mask CBC warning report by setting this bit to 1
0	MASK_CBC_FAULT	R/W	0	Mask CBC fault report by setting this bit to 1

#### 8.6.1.49 MISC\_CONTROL Register (Offset = 76h) [reset = 0x00]

MISC\_CONTROL is shown in 图 8-62 and described in 表 8-58.

Return to 表 8-8.

图 8-62. MISC\_CONTROL Register

7	6	5	4	3	2	1	0
DET_STATUS_LATCH	RESERVED		OTSD_AUTO_REC_EN	RESERVED			
R/W	R/W		R/W	R/W			

表 8-58. MISC\_CONTROL Register Field Descriptions

Bit	Field	Type	Reset	Description
7	DET_STATUS_LATCH	R/W	0	1:Latch clock detection status 0:Don't latch clock detection status
6-5	RESERVED	R/W	00	These bits are reserved
4	OTSD_AUTO_REC_EN	R/W	0	OTSD auto recovery enable
3-0	RESERVED	R/W	0000	This bit is reserved

#### 8.6.1.50 CBC\_CONTROL Register (Offset = 77h) [reset = 0x00]

CBC\_CONTROL is shown in 图 8-63 and described in 表 8-59.

Return to 表 8-8.

图 8-63. CBC\_CONTROL Register

7	6	5	4	3	2	1	0
RESERVED			CBC_LEVEL_SEL		CBC_EN	CBC_WARN_EN	CBC_FAULT_EN
R/W			R/W		R/W	R/W	R/W

表 8-59. CBC\_CONTROL Register Field Descriptions

Bit	Field	Type	Reset	Description
7-5	RESERVED	R/W	000	These bits are reserved
4-3		CBC_LEVEL_SEL	00	This bit sets CBC level, which is percentage to Over-Current Threshold: 00: 80% 10: 60% 01: 40%
2	CBC_EN	R/W	0	Enable CBC function
1	CBC_WARN_EN	R/W	0	Enable CBC warning

**表 8-59. CBC\_CONTROL Register Field Descriptions (continued)**

Bit	Field	Type	Reset	Description
0	CBC_FAULT_EN	R/W	0	Enable CBC fault

### 8.6.1.51 FAULT\_CLEAR Register (Offset = 78h) [reset = 0x00]

FAULT\_CLEAR is shown in [图 8-64](#) and described in [表 8-60](#).

Return to [表 8-8](#).

**图 8-64. FAULT\_CLEAR Register**

7	6	5	4	3	2	1	0
ANALOG_FAULT_CLEAR		RESERVED					
W		R/W					

**表 8-60. FAULT\_CLEAR Register Field Descriptions**

Bit	Field	Type	Reset	Description
7	ANALOG_FAULT_CLEAR	W	0	WRITE CLEAR BIT once write this bit to 1, device clears analog fault
6-0	RESERVED	R/W	0000000	This bit is reserved

## 9 Application and Implementation

### Note

以下のアプリケーション情報は、TI の製品仕様に含まれるものではなく、TI ではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくこととなります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

### 9.1 Application Information

This section details the information required to configure the device for several popular configurations and provides guidance on integrating the TAS5828M device into the larger system.

#### 9.1.1 Inductor Selections

It is required that the peak current is smaller than the OCP (Over current protection) value which is 7.5 A, there are 3 cases which cause high peak current flow through inductor.

1. During power up (idle state, no audio input), the duty cycle increases from 0 to  $\theta$ . There is a start-up current which flow through inductor to set up the common mode voltage ( $PVDD \times \theta$ ).

### Note

$\theta = 0.5$  (BD Modulation),  $0.14$  (1 SPW Modulation),  $0.14$  (Hybrid Modulation)

2. During music playing, some audio burst signal (high frequency) with very hard PVDD clipping causes PWM duty cycle increase dramatically. This is the worst case and it rarely happens.

$$I_{peak\_clipping} \approx PVDD \times (1 - \theta) / (F_{sw} \times L) \quad (1)$$

3. Peak current due to Max output power. Ignore the ripple current flow through capacitor here.

$$I_{peak\_output\_power} \approx \sqrt{2 \times Max\_Output\_Power / R_{speaker\_Load}} \quad (2)$$

It is suggested that inductor saturation current  $I_{sat}$ , is larger than the amplifier peak current during power-up and play audio.

$$I_{SAT} \geq \max(I_{peak\_power\_up}, I_{peak\_clipping}, I_{peak\_output\_power}) \quad (3)$$

**表 9-1. Inductor Requirements**

PVDD (V)	Switching Frequency (kHz)	Minimum Inductance (L) ( $\mu$ H)
$\leq 12$	384	4.7
$> 12$	384	10

For higher switching frequencies ( $F_{sw}$ ), select the inductors with minimum inductance to be  $384 \text{ kHz} / F_{sw} \times L$ . Same PVDD and switching frequency, larger inductance means smaller idle current for lower power dissipation.

### 9.1.2 Bootstrap Capacitors

The output stage of the TAS5828M uses a high-side NMOS driver, rather than a PMOS driver. To generate the gate driver voltage for the high-side NMOS, a bootstrap capacitor for each output terminal acts as a floating power supply for the switching cycle. Use 0.47- $\mu$ F capacitors to connect the appropriate output pin (OUT\_X) to the bootstrap pin (BST\_X). For example, connect a 0.47- $\mu$ F capacitor between OUT\_A and BST\_A for bootstrapping the A channel. Similarly, connect another 0.47- $\mu$ F capacitor between the OUT\_B and BST\_B pins for the B channel inverting output.

### 9.1.3 Power Supply Decoupling

To ensure high efficiency, low THD, and high PSRR, proper power supply decoupling is necessary. Noise transients on the power supply lines are short duration voltage spikes. These spikes can contain frequency components that extend into the hundreds of megahertz. The power supply input must be decoupled with some good quality, low ESL, Low ESR capacitors larger than 22  $\mu$ F. These capacitors bypasses low frequency noise to the ground plane. For high frequency decoupling, place 1- $\mu$ F or 0.1- $\mu$ F capacitors as close as possible to the PVDD pins of the device.

### 9.1.4 Output EMI Filtering

The device is often used with a low-pass filter, which is used to filter out the carrier frequency of the PWM modulated output. This filter is frequently referred to as the L-C Filter, due to the presence of an inductive element L and a capacitive element C to make up the 2-pole filter.

The L-C filter removes the carrier frequency, reducing electromagnetic emissions and smoothing the current waveform which is drawn from the power supply. The presence and size of the L-C filter is determined by several system level constraints. In some low-power use cases that have no other circuits which are sensitive to EMI, a simple ferrite bead or a ferrite bead plus a capacitor can replace the tradition large inductor and capacitor that are commonly used. In other high-power applications, large toroid inductors are required for maximum power and film capacitors can be used due to audio characteristics. Refer to the application report Class-D LC Filter Design (SLOA119) for a detailed description on the proper component selection and design of an L-C filter based upon the desired load and response.

For EMI performance and EMI Design consideration, reference to application report: [TAS5825M Design Considerations for EMC](#).

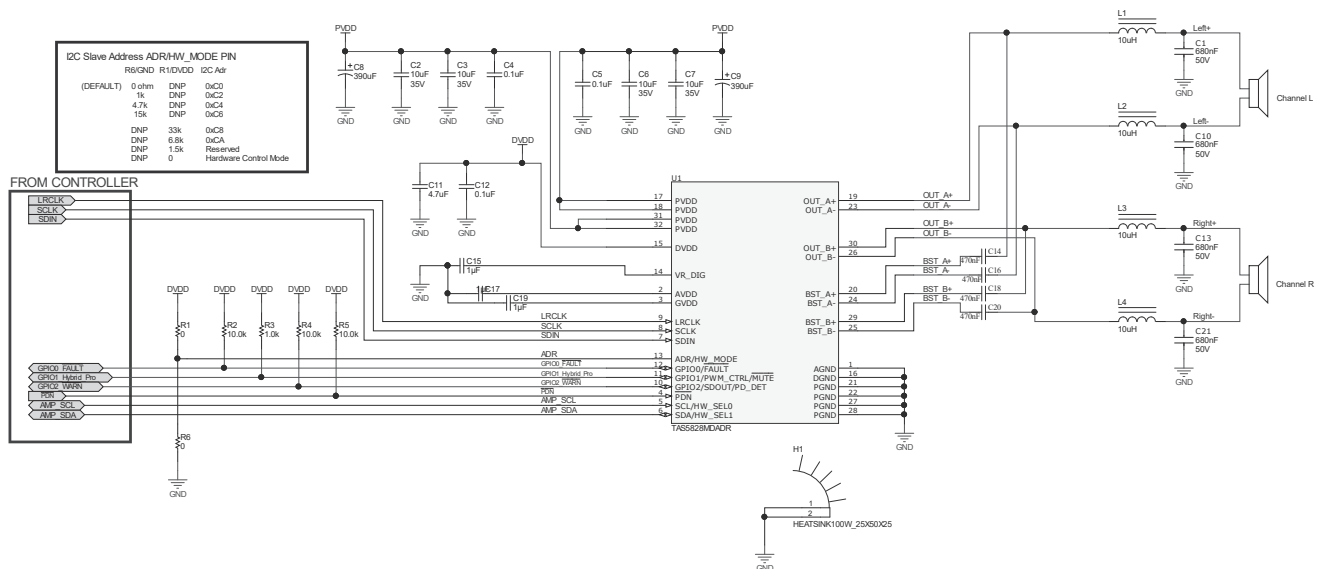
## 9.2 Typical Applications

### 9.2.1 2.0 (Stereo BTL) System

In the 2.0 system, two channels are presented to the amplifier via the digital input signal. These two channels are amplified and then sent to two separate speakers. In some cases, the amplified signal is further separated based upon frequency by a passive crossover network after the L-C filter. Even so, the application is considered 2.0.

Most commonly, the two channels are a pair of signals called a stereo pair, with one channel containing the audio for the left channel and the other channel containing the audio for the right channel. While certainly the two channels can contain any two audio channels, such as two surround channels of a multi-channel speaker system, the most popular occurrence in two channels systems is a stereo pair.

☒ 9-1 shows the 2.0 (Stereo BTL) system application.



☒ 9-1. 2.0 (Stereo BTL) System Application Schematic

## 9.2.2 Design Requirements

- Power supplies:
  - 3.3-V supply
  - 5-V to 24-V supply
- Communication: host processor serving as I<sup>2</sup>C compliant controller
- External memory (such as EEPROM and FLASH) used for coefficients.

The requirements for the supporting components for the TAS5828M device in a Stereo 2.0 (BTL) system is provide in 表 9-2.

**表 9-2. Supporting Component Requirements for Stereo 2.0 (BTL) Systems**

REFERENCE DESIGNATOR	VALUE	SIZE	DETAILED DESCRIPTION
C8, C9	390μF	SMD	CAP, AL, 390 uF, 35 V, ± 20%, SMD
C4, C5	0.1μF	0402	CAP, CERM, 10 uF, 35 V, ± 10%, X5R, 0805
C2, C3, C6, C7	10μF	0805	CAP, CERM, 22 μF, 35 V, ±20%, JB, 0805
C11	4.7μF	0603	CAP, CERM, 4.7 μF, 10 V, ±10%, X5R, 0603
C12	0.1μF	0603	CAP, CERM, 0.1 μF, 16 V, ±10%, X7R, 0603
C15, C17, C19	1μF	0603	CAP, CERM, 1 μF, 16 V, ±10%, X5R, 0603
C14, C16, C18, C20	0.47μF	0603	CAP, CERM, 0.47 μF, 16 V, ±10%, X7R, 0603
C1, C10, C13, C21	0.68μF	0805	CAP, CERM, 0.68 μF, 50 V, ±10%, X7R, 0805
L1, L2, L3, L4	10μH		Inductor, Shielded Drum Core, Ferrite, 10 uH, 7.1 A, 0.01294 ohm, SMD, 7447709100
R1, R6	0Ω	0402	RES, 0, 5%, 0.063 W, 0402
R2, R4, R5	10kΩ	0402	RES, 10.0 k, 1%, 0.063 W, 0402
R3	1kΩ	0402	RES, 1.0 k, 1%, 0.063 W, 0402

## 9.2.3 Detailed Design procedures

This Design procedures can be used for both Stereo 2.0, Advanced 2.1 and Mono Mode.

### 9.2.3.1 Step One: Hardware Integration

- Using the Typical Application Schematic as a guide, integrate the hardware into the system schematic.
- Following the recommended component placement, board layout, and routing given in the example layout above, integrate the device and its supporting components into the system PCB file.
  - The most critical sections of the circuit are the power supply inputs, the amplifier output signals, and the high-frequency signals, all of which go to the serial audio port. Constructing these signals to ensure they are given precedent as design trade-offs are made is recommended.
  - For questions and support go to the E2E forums ([e2e.ti.com](http://e2e.ti.com)). If deviating from the recommended layout is necessary, go to the E2E forum to request a layout review.

### 9.2.3.2 Step Two: Hardware Integration

Using the TAS5828MEVM evaluation module and the PPC3 app to configure the desired device settings.

### 9.2.3.3 Step Three: Software Integration

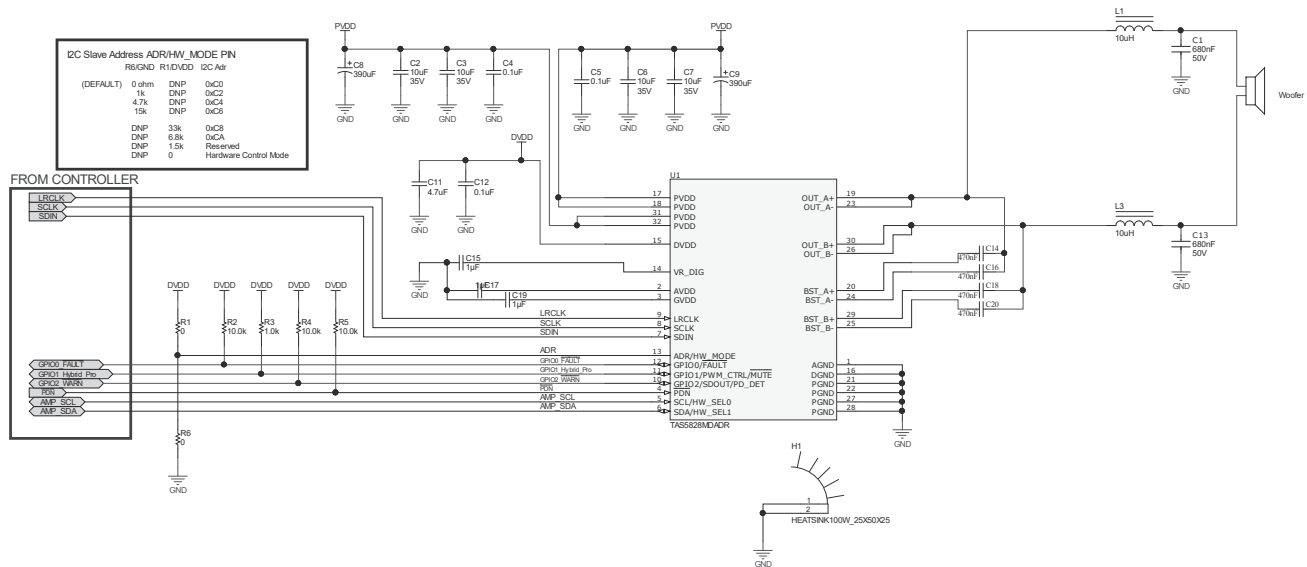
- Using the End System Integration feature of the PPC3 app to generate a baseline configuration file.
- Generate additional configuration files based upon operating modes of the end-equipment and integrate static configuration information into initialization files.
- Integrate dynamic controls (such as volume controls, mute commands, and mode-based EQ curves) into the main system program.

**TAS5828M**

JAJSM72A – JUNE 2021 – REVISED DECEMBER 2021

**9.2.4 MONO (PBTL) Systems**

In MONO mode, TAS5828M can be used as PBTL mode to drive sub-wwoofer with more output power.




**9-2. Sub-wwoofer (PBTL) Application Schematic**

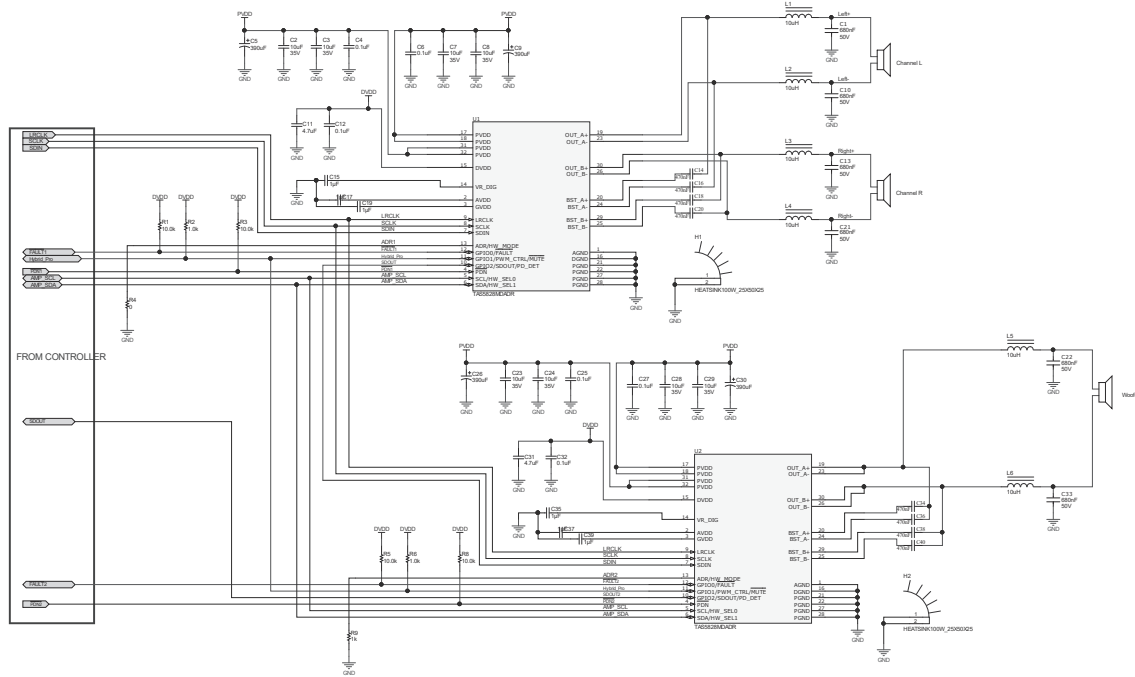
**表 9-3. Supporting Component Requirements for Sub-wwoofer (PBTL) Systems**


REFERENCE DESIGNATOR	VALUE	SIZE	DETAILED DESCRIPTION
C8, C9	390µF	SMD	CAP, AL, 390 uF, 35 V, ± 20%, SMD
C4, C5	0.1µF	0402	CAP, CERM, 10 uF, 35 V, ± 10%, X5R, 0805
C2, C3, C6, C7	10µF	0805	CAP, CERM, 22 µF, 35 V, ± 20%, JB, 0805
C11	4.7µF	0603	CAP, CERM, 4.7 µF, 10 V, ± 10%, X5R, 0603
C12	0.1µF	0603	CAP, CERM, 0.1 µF, 16 V, ± 10%, X7R, 0603
C15, C17, C19	1µF	0603	CAP, CERM, 1 µF, 16 V, ± 10%, X5R, 0603
C14, C16, C18, C20	0.47µF	0603	CAP, CERM, 0.47 µF, 16 V, ± 10%, X7R, 0603
C1, C13	0.68µF	0805	CAP, CERM, 0.68 µF, 50 V, ± 10%, X7R, 0805
L1, L3	10µH		Inductor, Shielded Drum Core, Ferrite, 10 uH, 7.1 A, 0.01294 ohm, SMD, 7447709100
R1, R6	0Ω	0402	RES, 0, 5%, 0.063 W, 0402
R2, R4, R5	10kΩ	0402	RES, 10.0 k, 1%, 0.063 W, 0402



### 9.2.5 Advanced 2.1 System (Two TAS5828M Devices)

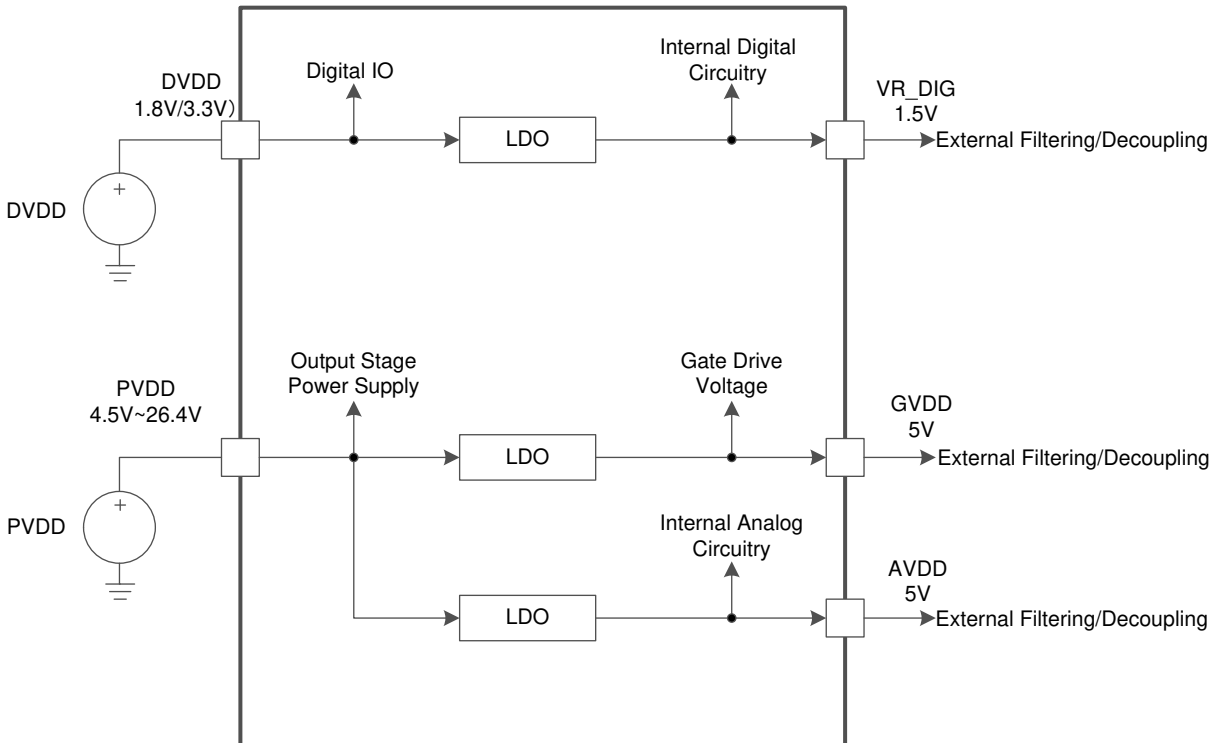
In higher performance systems, the subwoofer output can be enhanced using digital audio processing as was done in the high-frequency channels. To accomplish this, two TAS5828M devices are used - one for the high frequency left and right speakers and one for the mono subwoofer speaker. In this system, the audio signal can be sent from the TAS5828M device through the SDOUT pin. Alternatively, the subwoofer amplifier can accept the same digital input as the stereo, which might come from a central systems processor.  9-3 shows the 2.1 (Stereo BTL with Two TAS5828M devices) system application.



 9-3. 2.1 (2.1 CH with Two TAS5828M Devices) Application Schematic

## 10 Power Supply Recommendations

The TAS5828M device requires two power supplies for proper operation. A high-voltage supply called PVDD is required to power the output stage of the speaker amplifier and its associated circuitry. Additionally, one low-voltage power supply called DVDD is required to power the various low-power portions of the device. The allowable voltage range for both PVDD and DVDD supply are listed in the *Recommended Operating Conditions* table. The two power supplies do not have a required powerup sequence. The power supplies can be powered on in any order.



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FIG 10-1. Power Supply Function Block Diagram

### 10.1 DVDD Supply

The DVDD supply that is required from the system is used to power several portions of the device. As shown in FIG 10-1, it provides power to the DVDD pin. Proper connection, routing and decoupling techniques are highlighted in the *Application and Implementation* section and the *Layout Example* section and must be followed as closely as possible for proper operation and performance.

Some portions of the device also require a separate power supply that is a lower voltage than the DVDD supply. To simplify the power supply requirements for the system, the TAS5828M device includes an integrated low dropout (LDO) linear regulator to create this supply. This linear regulator is internally connected to the DVDD supply and its output is presented on the DVDD\_REG pin, providing a connection point for an external bypass capacitor. It is important to note that the linear regulator integrated in the device has only been designed to support the current requirements of the internal circuitry, and should not be used to power any additional external circuitry. Additional loading on this pin could cause the voltage to sag, negatively affecting the performance and operation of the device.

### 10.2 PVDD Supply

The output stage of the speaker amplifier drives the load using the PVDD supply. This is the power supply which provides the drive current to the load during playback. Proper connection, routing, and decoupling techniques are highlighted in the TAS5828MEVM and must be followed as closely as possible for proper operation and

performance. Due to the high-voltage switching of the output stage, it is particularly important to properly decouple the output power stages in the manner described in the TAS5828M device [Application and Implementation](#). Lack of proper decoupling, like that shown in the [Application and Implementation](#), results in voltage spikes which can damage the device.

A separate power supply is required to drive the gates of the MOSFETs used in the output stage of the speaker amplifier. This power supply is derived from the PVDD supply via an integrated linear regulator. A GVDD pin is provided for the attachment of decoupling capacitor for the gate drive voltage regulator. It is important to note that the linear regulator integrated in the device has only been designed to support the current requirements of the internal circuitry, and should not be used to power any additional external circuitry. Additional loading on this pin could cause the voltage to sag, negatively affecting the performance and operation of the device.

Another separate power supply is derived from the PVDD supply via an integrated linear regulator is AVDD. AVDD pin is provided for the attachment of decoupling capacitor for the TAS5828M internal circuitry. It is important to note that the linear regulator integrated in the device has only been designed to support the current requirements of the internal circuitry, and should not be used to power any additional external circuitry. Additional loading on this pin could cause the voltage to sag, negatively affecting the performance and operation of the device.

## 11 Layout

### 11.1 Layout Guidelines

#### 11.1.1 General Guidelines for Audio Amplifiers

Audio amplifiers which incorporate switching output stages must have special attention paid to their layout and the layout of the supporting components used around them. The system level performance metrics, including thermal performance, electromagnetic compliance (EMC), device reliability, and audio performance are all affected by the device and supporting component layout.

Ideally, the guidance provided in the applications section with regard to device and component selection can be followed by precise adherence to the layout guidance shown in the [Layout Example](#) section. These examples represent exemplary baseline balance of the engineering trade-offs involved with laying out the device. These designs can be modified slightly as needed to meet the needs of a given application. In some applications, for instance, solution size can be compromised to improve thermal performance through the use of additional contiguous copper near the device. Conversely, EMI performance can be prioritized over thermal performance by routing on internal traces and incorporating a via picket-fence and additional filtering components. In all cases, it is recommended to start from the guidance shown in the [Layout Example](#) section and work with TI field application engineers or through the E2E community to modify it based upon the application specific goals.

#### 11.1.2 Importance of PVDD Bypass Capacitor Placement on PVDD Network

Placing the bypassing and decoupling capacitors close to supply has long been understood in the industry. This applies to DVDD, AVDD, GVDD and PVDD. However, the capacitors on the PVDD net for the TAS5828M device deserve special attention.

The small bypass capacitors on the PVDD lines of the DUT must be placed as close to the PVDD pins as possible. Not only does placing these devices far away from the pins increase the electromagnetic interference in the system, but doing so can also negatively affect the reliability of the device. Placement of these components too far from the TAS5828M device can cause ringing on the output pins that can cause the voltage on the output pin to exceed the maximum allowable ratings shown in the *Absolute Maximum Ratings* table, damaging the device. For that reason, the capacitors on the PVDD net must be no further away from their associated PVDD pins than what is shown in the example layouts in the [Layout Example](#) section.

#### 11.1.3 Optimizing Thermal Performance

Follow the layout example shown in the [Figure 11-1](#) to achieve the best balance of solution size, thermal, audio, and electromagnetic performance. In some cases, deviation from this guidance can be required due to design constraints which cannot be avoided. In these instances, the system designer should ensure that the heat can get out of the device and into the ambient air surrounding the device. Fortunately, the heat created in the device naturally travels away from the device and into the lower temperature structures around the device.

##### 11.1.3.1 Device, Copper, and Component Layout

Primarily, the goal of the PCB design is to minimize the thermal impedance in the path to those cooler structures. These tips should be followed to achieve that goal:

- Avoid placing other heat producing components or structures near the amplifier (including above or below in the end equipment).
- If possible, use a higher layer count PCB to provide more heat sinking capability for the TAS5828M device and to prevent traces and copper signal and power planes from breaking up the contiguous copper on the top and bottom layer.
- Place the TAS5828M device away from the edge of the PCB when possible to ensure that the heat can travel away from the device on all four sides.
- Avoid cutting off the flow of heat from the TAS5828M device to the surrounding areas with traces or via strings. Instead, route traces perpendicular to the device and line up vias in columns which are perpendicular to the device.
- Unless the area between two pads of a passive component is large enough to allow copper to flow in between the two pads, orient it so that the narrow end of the passive component is facing the TAS5828M device.

- Because the ground pins are the best conductors of heat in the package, maintain a contiguous ground plane from the ground pins to the PCB area surrounding the device for as many of the ground pins as possible.

### 11.1.3.2 Stencil Pattern

The recommended drawings for the TAS5828M device PCB foot print and associated stencil pattern are shown at the end of this document in the package addendum. Additionally, baseline recommendations for the via arrangement under and around the device are given as a starting point for the PCB design. This guidance is provided to suit the majority of manufacturing capabilities in the industry and prioritizes manufacturability over all other performance criteria. In elevated ambient temperature or under high-power dissipation use-cases, this guidance may be too conservative and advanced PCB design techniques may be used to improve thermal performance of the system.

---

#### Note

The customer must verify that deviation from the guidance shown in the package addendum, including the deviation explained in this section, meets the customer's quality, reliability, and manufacturability goals.

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#### 11.1.3.2.1 PCB footprint and Via Arrangement

The PCB footprint (also known as a symbol or land pattern) communicates to the PCB fabrication vendor the shape and position of the copper patterns to which the TAS5828M device is soldered. This footprint can be followed directly from the guidance in the package addendum at the end of this data sheet. It is important to make sure that the thermal pad, which connects electrically and thermally to the PowerPAD™ of the TAS5828M device, be made no smaller than what is specified in the package addendum. This ensures that the TAS5828M device has the largest interface possible to move heat from the device to the board.

The via pattern shown in the package addendum provides an improved interface to carry the heat from the device through to the layers of the PCB, because small diameter plated vias (with minimally-sized annular rings) present a low thermal-impedance path from the device into the PCB. Once into the PCB, the heat travels away from the device and into the surrounding structures and air. By increasing the number of vias, as shown in the [Layout Example](#) section, this interface can benefit from improved thermal performance.

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#### Note

Vias can obstruct heat flow if they are not constructed properly.

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More notes on the construction and placement of vias are as follows:

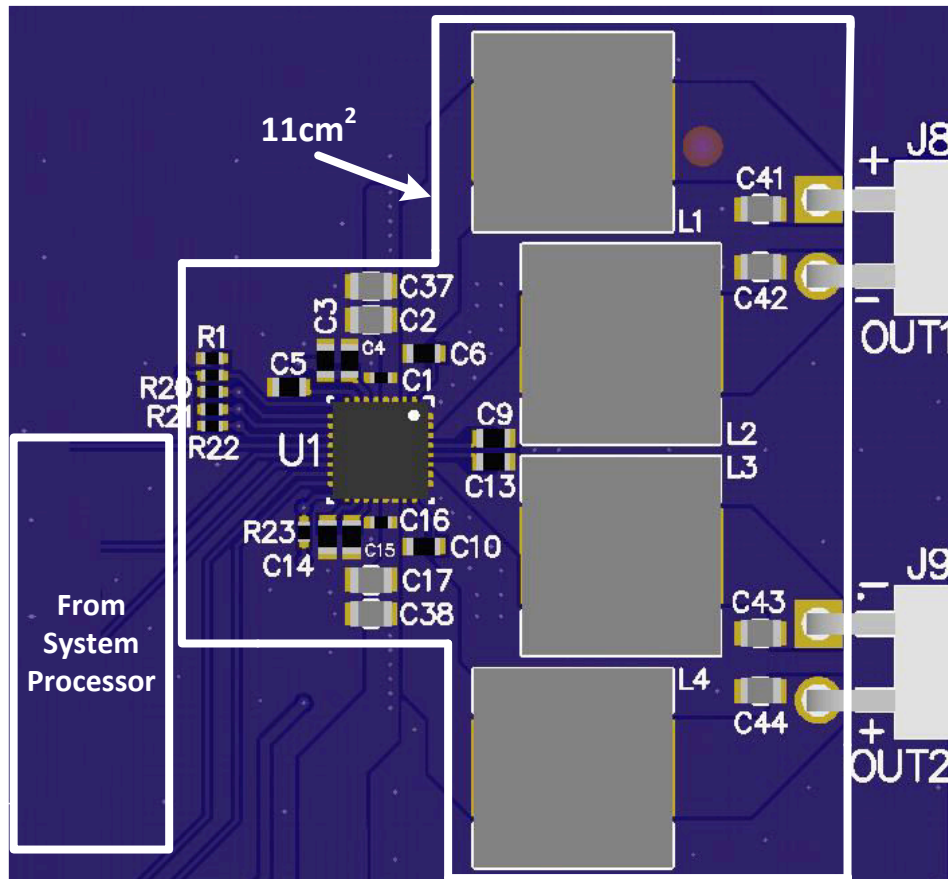
- Remove thermal reliefs on thermal vias, because they impede the flow of heat through the via.
- Vias filled with thermally conductive material are best, but a simple plated via can be used to avoid the additional cost of filled vias.
- The diameter of the drill must be 8 mm or less. Also, the distance between the via barrel and the surrounding planes should be minimized to help heat flow from the via into the surrounding copper material. In all cases, minimum spacing should be determined by the voltages present on the planes surrounding the via and minimized wherever possible.
- Vias should be arranged in columns, which extend in a line radially from the heat source to the surrounding area. This arrangement is shown in the [Layout Example](#) section.
- Ensure that vias do not cut off power current flow from the power supply through the planes on internal layers. If needed, remove some vias that are farthest from the TAS5828M device to open up the current path to and from the device.

#### 11.1.3.2.2 Solder Stencil

During the PCB assembly process, a piece of metal called a stencil on top of the PCB and deposits solder paste on the PCB wherever there is an opening (called an aperture) in the stencil. The stencil determines the quantity and the location of solder paste that is applied to the PCB in the electronic manufacturing process. In most cases, the aperture for each of the component pads is almost the same size as the pad itself. However, the thermal pad on the PCB is large and depositing a large, single deposition of solder paste would lead to

manufacturing issues. Instead, the solder is applied to the board in multiple apertures, to allow the solder paste to outgas during the assembly process and reduce the risk of solder bridging under the device. This structure is called an aperture array, and is shown in the [Layout Example](#) section. It is important that the total area of the aperture array (the area of all of the small apertures combined) covers between 70% and 80% of the area of the thermal pad itself.

### 11.2 Layout Example



☒ 11-1. 2.0 (Stereo BTL) 3-D View

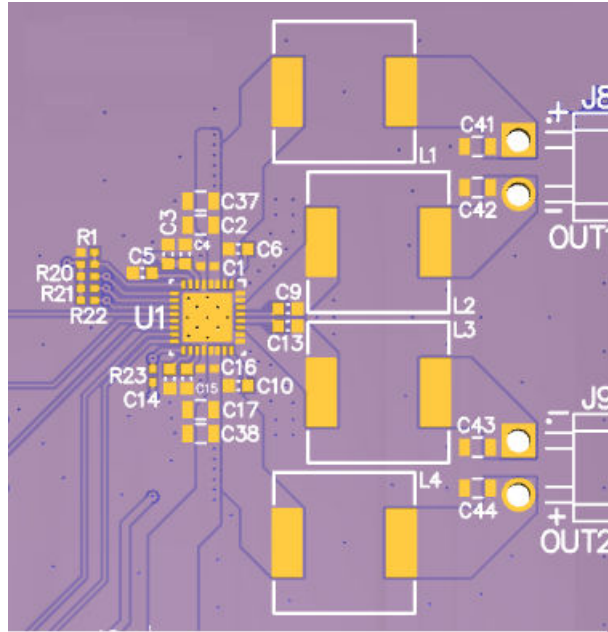


图 11-2. 2.0 (Stereo BTL) Top Copper View

## 12 Device and Documentation Support

### 12.1 Device Support

#### 12.1.1 Device Nomenclature

The glossary section is a general glossary with commonly used acronyms and words which are defined in accordance with a broad TI initiative to comply with industry standards such as JEDEC, IPC, IEEE, and others. The glossary provided in this section defines words, phrases, and acronyms that are unique to this product and documentation, collateral, or support tools and software used with this product. For any additional questions regarding definitions and terminology, please see the [e2e Audio Amplifier Forum](#).

**Bridge tied load (BTL)** is an output configuration in which one terminal of the speaker is connected to one half-bridge and the other terminal is connected to another half-bridge.

**DUT** refers to a *device under test* to differentiate one device from another.

**Closed-loop architecture** describes a topology in which the amplifier monitors the output terminals, comparing the output signal to the input signal and attempts to correct for non-linearities in the output.

**Dynamic controls** are those which are changed during normal use by either the system or the end-user.

**GPIO** is a general purpose input/output pin. It is a highly configurable, bi-directional digital pin which can perform many functions as required by the system.

**Host processor (also known as System Processor, Scalar, Host, or System Controller)** refers to device which serves as a central system controller, providing control information to devices connected to it as well as gathering audio source data from devices upstream from it and distributing it to other devices. This device often configures the controls of the audio processing devices (like the TAS5828M) in the audio path in order to optimize the audio output of a loudspeaker based on frequency response, time alignment, target sound pressure level, safe operating area of the system, and user preference.

**Maximum continuous output power** refers to the maximum output power that the amplifier can continuously deliver without shutting down when operated in a 25°C ambient temperature. Testing is performed for the period of time required that their temperatures reach thermal equilibrium and are no longer increasing

**Parallel bridge tied load (PBTL)** is an output configuration in which one terminal of the speaker is connected to two half-bridges which have been placed in parallel and the other terminal is connected to another pair of half bridges placed in parallel

$r_{DS(on)}$  is a measure of the on-resistance of the MOSFETs used in the output stage of the amplifier.

**Static controls/Static configurations** are controls which do not change while the system is in normal use.

**Vias** are copper-plated through-hole in a PCB.

#### 12.1.2 Development Support

For RDGUI software, please consult your local field support engineer.

### 12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 12.3 サポート・リソース

TI E2E™ サポート・フォーラムは、検証済みの迅速な回答と設計支援をエンジニアがエキスパートから直接得るための頼れる情報源です。既存の回答を検索し、または新たに質問することで、必要とする設計支援を迅速に得ることができます。

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## 12.4 Trademarks

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## 12.5 静電気放電に関する注意事項



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ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

## 12.6 用語集

**TI 用語集** この用語集には、用語や略語の一覧および定義が記載されています。

## 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TAS5828MDADR	ACTIVE	HTSSOP	DAD	32	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	-40 to 85	TAS 5828M	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBsolete:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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郵送先住所：Texas Instruments, Post Office Box 655303, Dallas, Texas 75265  
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